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Characterization of the Sulfur-Saturated Melt Versions of the HLW HAIG Glasses

M. C. Hsieh

February 2023

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REVIEWS AND APPROVALS

AUTHORS:

M. C. Hsieh, Applied Materials Research

TECHNICAL REVIEW:

A. N. Stanfield, Applied Materials Research, Reviewed per E7 2.60

APPROVAL:

J. Manna, Division Director, Environmental and Legacy Management

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EXECUTIVE SUMMARY

This report provides the results from the chemical analyses of a series of sulfur-saturated melt versions of the High-Level Waste High-Aluminum Glass study glasses, a series of simulated nuclear waste glasses designed and fabricated at Pacific Northwest National Laboratory. These data will be used in the development, validation, and implementation of enhanced property/composition models for waste glass vitrification at Hanford.

Chemical analyses were performed on a representative sample of each of the sulfur-saturated melt versions of the glasses to allow for comparisons with targeted compositions as well as the measured compositions of the quenched glasses. The relative differences between the targeted and measured concentrations of B_2O_3 , Cr_2O_3 , K_2O , Li_2O , Na_2O , and P_2O_5 for several of the glasses were greater than $\pm 10\%$. The relative differences between the targeted and measured concentrations of Al_2O_3 and ZrO_2 for one of the glasses were greater than $\pm 10\%$. As expected, the measured concentrations of SO_3 in most of the glasses were higher than targeted due to the use of the sulfur saturation method in fabricating these glasses.

The wash solutions contained mainly sodium, sulfur, and sulfate ions.

TABLE OF CONTENTS

LIST OF TABLES	viii
LIST OF ABBREVIATIONS.....	ix
1.0 Introduction.....	1
2.0 Experimental Procedure.....	1
2.1 Quality Assurance	1
2.2 Glasses Selected for Study.....	1
2.3 Glass Composition Analysis.....	3
2.4 Wash Solution Analysis	4
3.0 Results and Discussion	5
3.1 Review and Evaluation of the SSM Glass Composition Measurements.....	5
3.1.1 Treatment of Detection Limits	5
3.1.2 Composition Measurements by Glass Identifier.....	5
3.1.3 Results for the LRM Standard Glass	6
3.1.4 Measured versus Targeted Compositions.....	6
3.2 Comparison of Measured Compositions of Baseline and SSM Glasses	7
3.3 Review and Evaluation of the Wash Solution Measurements	7
3.3.1 Treatment of Detection Limits	7
3.3.2 Composition Measurements by Wash Solution Identifier.....	7
3.3.3 Results for the Standard Solutions.....	7
3.3.4 Measured Compositions of the Wash Solutions.....	7
4.0 Summary	8
5.0 References.....	9
Appendix A . Tables and Exhibits Supporting the HLW HAIG Glass Composition Measurements.....	A-1
Appendix B . Tables and Exhibits Supporting the HLW HAIG Wash Solution Composition Measurements	B-1

LIST OF TABLES

Table 2-1. Identifiers for the HLW HAIG SSM Study Glasses	2
Table 2-2. Identifiers for the HLW HAIG SSM Wash Solutions.....	3
Table 2-3. Preparation and Measurement Methods Used in Reporting the Analyte Concentrations of the Study Glasses	4
Table 2-4. Measurement Methods Used in Reporting the Analyte Concentrations of the Wash Solutions .	5

LIST OF ABBREVIATIONS

ARG-1	Analytical Reference Glass-1
BDL	below detection limit
DOE	U. S. Department of Energy
HLW HAIG	High-Level Waste High-Aluminum Glass
hp std	High Purity Standards ICP multi-element custom solution SM-744-063
IC	ion chromatography
ICP-OES	inductively coupled plasma – optical emission spectroscopy
ID	identifier
KH	potassium hydroxide fusion
LM	lithium metaborate fusion
LRM	low-activity test reference material
ORP	Office of River Protection
PF	sodium peroxide fusion
PNNL	Pacific Northwest National Laboratory
Q	quenched
seq	sequence
SRNL	Savannah River National Laboratory
SRS	Savannah River Site
SSM	sulfur-saturated melt
std	High Purity Standards ICP multi-element custom solution SM-744-013
TTQAP	Task Technical and Quality Assurance Plan
wt. %	weight percent
WTP	Waste Treatment and Immobilization Plant

1.0 Introduction

The U.S. Department of Energy (DOE) is responsible for building the Hanford Tank Waste Treatment and Immobilization Plant (WTP) at the Hanford site in Washington to remediate 56 million gallons of radioactive waste historically stored in 177 underground tanks. The Office of River Protection (ORP) has requested that the Savannah River National Laboratory (SRNL) contribute in areas of recognized capabilities and expertise for glass waste form development to support successful startup of the WTP.

Successful efforts have allowed for demonstration of greatly enhanced treatment efficiencies of those projected from the minimum requirements set forth in the WTP Contract^a. Additional flexibility and expansion of the qualified glass forming region are the current focus.¹ SRNL support of this work is defined in the Task Technical and Quality Assurance Plan (TTQAP).²

This report provides results from the chemical analyses of the sulfur-saturated melt (SSM) versions of the High-Level Waste High-Aluminum Glass (HLW HAIG) study glasses, a series of simulated nuclear waste glasses designed and fabricated at Pacific Northwest National Laboratory (PNNL). The glasses were selected as part of a broader study of the influence of glass composition on chemical durability, sulfur retention, and other properties.³ The resulting data will be used in the development, validation, and implementation of enhanced property/composition models for nuclear waste glasses.¹

2.0 Experimental Procedure

2.1 Quality Assurance

Requirements for performing reviews of technical reports and the extent of review are established in Savannah River Site (SRS) Manual E7, Procedure 2.60.⁴ SRNL documents the extent and type of review using the SRNL Technical Report Design Checklist contained in WSRC-IM-2002-00011.⁵ Laboratory data for this study were recorded in the SRNL Electronic Laboratory Notebook system, experiment L6390-00441-06. The glasses provided by PNNL were designed and fabricated following a Task Plan.¹

2.2 Glasses Selected for Study

The baseline (quenched) glass compositions in this study were designed and fabricated by PNNL. Characterization of the baseline glasses were reported earlier.⁶ Samples of each of the SSM versions of the study glasses, along with samples of the wash solutions resulting from the preparation of each of the SSM glasses, were received at SRNL for chemical composition analysis. The PNNL identifiers (IDs) for the glass samples and associated SRNL sample identifiers are listed in Table 2-1. The identifiers for the wash solutions are likewise listed in Table 2-2.

^a Contract DE-AC27-01RV14136, as amended, U.S. Department of Energy, Richland, WA (2000).

Table 2-1. Identifiers for the HLW HAIG SSM Study Glasses

PNNL Glass ID	Lab ID
HAIG-01-Q-SSM-S	S-14308
HAIG-02-Q-SSM-S	S-14309
HAIG-03-Q-SSM-S	S-14310
HAIG-04-Q-SSM-S	S-14311
HAIG-05-Q-SSM-S	S-14312
HAIG-06-Q-SSM-S	S-14313
HAIG-07-1-Q-SSM-S	S-14314
HAIG-08-Q-SSM-S	S-14315
HAIG-09-Q-SSM-S	S-14316
HAIG-11-Q-SSM-S	S-14317
HAIG-12-Q-SSM-S	S-14318
HAIG-13-Q-SSM-S	S-14319
HAIG-14-Q-SSM-S	S-14320
HAIG-15-Q-SSM-S	S-14321
HAIG-16-Q-SSM-S	S-14322
HAIG-17-Q-SSM-S	S-14323
HAIG-18-Q-SSM-S	S-14324
HAIG-19-Q-SSM-S	S-14325
HAIG-20-Q-SSM-S	S-14326
HAIG-21-Q-SSM-S	S-14327
HAIG-22-Q-SSM-S	S-14328
HAIG-23-Q-SSM-S	S-14329
HAIG-24-Q-SSM-S	S-14330
HAIG-25-Q-SSM-S	S-14331
EWG-HAIG-SSM-S	S-14332

Table 2-2. Identifiers for the HLW HAIG SSM Wash Solutions

PNNL Wash Solution ID	Lab ID
HAIG-01-Q-SSM-W	S-14283
HAIG-02-Q-SSM-W	S-14284
HAIG-03-Q-SSM-W	S-14285
HAIG-04-Q-SSM-W	S-14286
HAIG-05-Q-SSM-W	S-14287
HAIG-06-Q-SSM-W	S-14288
HAIG-07-1-Q-SSM-W	S-14289
HAIG-08-Q-SSM-W	S-14290
HAIG-09-Q-SSM-W	S-14291
HAIG-11-Q-SSM-W	S-14292
HAIG-12-Q-SSM-W	S-14293
HAIG-13-Q-SSM-W	S-14294
HAIG-14-Q-SSM-W	S-14295
HAIG-15-Q-SSM-W	S-14296
HAIG-16-Q-SSM-W	S-14297
HAIG-17-Q-SSM-W	S-14298
HAIG-18-Q-SSM-W	S-14299
HAIG-19-Q-SSM-W	S-14300
HAIG-20-Q-SSM-W	S-14301
HAIG-21-Q-SSM-W	S-14302
HAIG-22-Q-SSM-W	S-14303
HAIG-23-Q-SSM-W	S-14304
HAIG-24-Q-SSM-W	S-14305
HAIG-25-Q-SSM-W	S-14306
EWG-HAIG-SSM-W	S-14307

2.3 Glass Composition Analysis

Chemical analyses were performed under the auspices of an analytical plan⁷ on a representative sample of each of the glasses listed in Table 2-1 to allow for comparisons with the targeted compositions. Three dissolution techniques were used for preparing each of the glass samples, in duplicate, for analysis (potassium hydroxide fusion (KH), lithium metaborate fusion (LM), and sodium peroxide fusion (PF)).⁸⁻¹⁰ Note that for some analytes, the analytical plan specified more than one preparation method for analysis. The results were reviewed and, in general, the method that provided better recovery of the analyte was selected for reporting.

Each of the duplicate samples was analyzed twice for each element of interest by inductively coupled plasma – optical emission spectroscopy (ICP-OES)¹¹ or ion chromatography (IC),¹² for a total of four measurements per element per glass. Glass standards were also intermittently measured to assess the performance of the ICP-OES and IC instruments over the course of these analyses. Specifically, several samples of Analytical Reference Glass-1 (ARG-1) and low-activity test reference material (LRM) were included as part of the analytical plan.⁷ The ARG-1 composition reported as the “Corning, Inc., Glass Composition”¹³ and the LRM composition reported as the “Consensus Average”¹⁴ are used as the reference compositions of this glass. The preparation and measurement methods used for each of the reported glass components are listed in Table 2-3.

Table 2-3. Preparation and Measurement Methods Used in Reporting the Analyte Concentrations of the Study Glasses

Analyte	Measurement Method	Preparation Method
Al	ICP-OES	PF
B	ICP-OES	PF
Bi	ICP-OES	LM
Ca	ICP-OES	LM
Cd	ICP-OES	LM
Cr	ICP-OES	LM
F	IC	KH
Fe	ICP-OES	LM
K	ICP-OES	PF
Li	ICP-OES	PF
Mg	ICP-OES	LM
Mn	ICP-OES	LM
Na	ICP-OES	LM
Ni	ICP-OES	LM
P	ICP-OES	PF
S	ICP-OES	LM
Si	ICP-OES	PF
Sr	ICP-OES	LM
Ti	ICP-OES	LM
Zn	ICP-OES	LM
Zr	ICP-OES	PF

2.4 Wash Solution Analysis

Chemical analyses were performed under the auspices of an analytical plan⁷ on a representative sample of each of the wash solutions resulting from the preparation of the SSM versions of the glasses, as listed in Table 2-2. The samples were diluted at SRNL based on the expected concentrations of the species in solution in preparation for the analysis.

Each of the samples was analyzed in triplicate for each element of interest by ICP-OES¹¹ and IC¹². Solution standards and blanks were also intermittently measured to assess the performance of the ICP-OES and IC instruments over the course of these analyses. The measurement methods used for each of the reported wash solution components are listed in Table 2-4.

Table 2-4. Measurement Methods Used in Reporting the Analyte Concentrations of the Wash Solutions

Analyte	Measurement Method
Al	ICP-OES
B	ICP-OES
Bi	ICP-OES
Ca	ICP-OES
Cd	ICP-OES
Cr	ICP-OES
F ⁻	IC
Fe	ICP-OES
K	ICP-OES
Li	ICP-OES
Mg	ICP-OES
Mn	ICP-OES
Na	ICP-OES
Ni	ICP-OES
P	ICP-OES
PO ₄ ³⁻	IC
S	ICP-OES
SO ₄ ²⁻	IC
Si	ICP-OES
Sr	ICP-OES
Ti	ICP-OES
Zn	ICP-OES
Zr	ICP-OES

3.0 Results and Discussion

JMP® Version 16.0.0 (SAS Institute, Inc.)¹⁵ was used to support these analyses.

3.1 Review and Evaluation of the SSM Glass Composition Measurements

Table A-1, Table A-2, and Table A-3 in Appendix A provide the elemental concentration measurements in weight percent (wt.%) from glasses prepared using KH, LM, and PF methods, respectively. Elemental measurements for samples of the LRM glass are also included in these tables of Appendix A.

3.1.1 Treatment of Detection Limits

The elemental concentrations in Table A-1, Table A-2, and Table A-3 in Appendix A were converted to oxide concentrations by multiplying the values of each element by the gravimetric factor for the corresponding oxide. A concentration measurement that was reported to be below the detection limit (BDL) was set to the detection limit for the purposes of data review and calculating a sum of oxides for each glass. Concentration measurements that were BDL are denoted with a less than symbol (<).

3.1.2 Composition Measurements by Glass Identifier

Exhibit A-1 in Appendix A provides plots of the oxide concentration measurements by the PNNL Glass ID (including the LRM glasses) by Lab ID grouped by targeted concentration. Different symbols and colors are used to represent the different glasses. These plots show the individual measurements across the

duplicates of each preparation method and the two instrument calibrations for each glass. Plotting the data in this format provides an opportunity to review the values for each individual glass as a function of the duplicate preparations and duplicate measurements. A review of the plots presented in these exhibits reveals the repeatability of the four individual values for each oxide for each glass. There were no indications of errors in preparation or measurement that had to be addressed in treatment of the data.

3.1.3 Results for the LRM Standard Glass

Exhibit A-2 in Appendix A provides a comparison of the LRM results to their acceptability limits utilized by SRNL.¹¹ The review is in the form of plots of the measurements arranged by preparation method and element, framed by upper and lower acceptability limits for the concentration of each element of interest. The results show that all measurements of the LRM elements of interest were within the acceptability limits during the execution of these analyses.

3.1.4 Measured versus Targeted Compositions

All measurements for each oxide for each glass (Table A-1, Table A-2, and Table A-3 in Appendix A) were used in calculating oxide values, which were then averaged to determine a representative chemical composition for each glass. A sum of oxides was also computed for each glass based upon the averaged oxide values. Exhibit A-3 in Appendix A provides plots showing the result for each glass for each oxide to allow PNNL to draw comparisons between the measured and targeted values. All ARG-1 standard glass measurements were within 10% of reference values¹³.

Table A-4 in Appendix A provides a summary of the average compositions, targeted compositions and some associated differences and relative differences. The measured sums of oxides for all but one of the glasses fall within the interval of 97.2 wt.% to 102 wt.%, indicating acceptable recovery of the glass components.¹⁶ One glass, HAIG-18-Q-SSM-S, had a measured sum of oxides equal to 90.4 wt.%. Also, a standard glass, EWG-HAIG-SSM-S, had a measured sum of oxides equal to 89.0 wt.%. Because not all components were listed in the targeted composition, the targeted sum of oxides was 87.9 wt.%. Entries in Table A-4 show the relative differences between the measured and targeted values for the analytes with measured and targeted values above 1 wt.%. The relative differences were shaded if they are 10% or more and are summarized below.

- Al_2O_3 relative difference was 16% for EWG-HAIG-SSM-S.
- B_2O_3 relative differences were 10% or greater for HAIG-11-Q-SSM-S, HAIG-18-Q-SSM-S, and HAIG-21-SSM-S.
- Cr_2O_3 relative differences were 10% or greater for HAIG-02-Q-SSM-S, HAIG-04-Q-SSM-S, HAIG-06-Q-SSM-S, HAIG-09-Q-SSM-S, HAIG-11-Q-SSM-S, HAIG-12-Q-SSM-S, HAIG-14-Q-SSM-S, HAIG-15-Q-SSM-S, HAIG-16-Q-SSM-S, HAIG-20-Q-SSM-S, and HAIG-22-Q-SSM-S.
- K_2O relative differences were greater than 10% for HAIG-07-1-Q-SSM-S, HAIG-13-Q-SSM-S, HAIG-18-Q-SSM-S, HAIG-21-Q-SSM-S, and HAIG-22-Q-SSM-S.
- Li_2O relative differences were greater than 10% for HAIG-02-Q-SSM-S, HAIG-09-Q-SSM-S, HAIG-18-Q-SSM-S, HAIG-20-Q-SSM-S, HAIG-21-Q-SSM-S, and HAIG-24-Q-SSM-S.
- Na_2O relative differences were greater than 10% for HAIG-08-Q-SSM-S, HAIG-18-Q-SSM-S, HAIG-20-Q-SSM-S, HAIG-23-Q-SSM-S, and HAIG-24-Q-SSM-S.
- P_2O_5 relative differences were 10% or greater for HAIG-01-Q-SSM-S, HAIG-03-Q-SSM-S, HAIG-06-Q-SSM-S, HAIG-07-1-Q-SSM-S, HAIG-08-Q-SSM-S, HAIG-09-Q-SSM-S, HAIG-11-Q-SSM-S, HAIG-16-Q-SSM-S, HAIG-18-Q-SSM-S, HAIG-19-Q-SSM-S, HAIG-20-Q-SSM-S, HAIG-23-Q-SSM-S, HAIG-24-Q-SSM-S, and HAIG-25-Q-SSM-S.
- The ZrO_2 relative difference was 11% for EWG-HAIG-SSM-S.
- As expected, the measured SO_3 concentrations in the glasses were higher than targeted due to the use of the sulfur saturation method in fabricating these glasses.

3.2 Comparison of Measured Compositions of Baseline and SSM Glasses

Exhibit A-4 in Appendix A provides a comparison of the measured oxide concentrations among the baseline (quenched) and SSM versions of the study glasses. A review of Exhibit A-4 led to the following observations:

- The measured Cr_2O_3 concentrations were lower in the SSM versions of the study glasses.
- The measured SO_3 concentrations were higher for SSM versions of the study glasses, as expected, due to the use of the sulfur saturation method in fabricating these glasses.

The discussion of the analyses of the wash solutions, provided in Section 3.3, may provide further insight into the measured compositions of the SSM glasses.

3.3 Review and Evaluation of the Wash Solution Measurements

Table B-1 in Appendix B provides the elemental concentration measurements in mg/L for the wash solutions as measured by ICP-OES. Table B-2 in Appendix B provides the anion concentration measurements in mg/L for the wash solutions as measured by IC. Elemental measurements of the blanks and standard solutions are included in the tables of Appendix B.

3.3.1 Treatment of Detection Limits

The elemental and anion concentrations in Table B-1 and Table B-2 of Appendix B include measurements that were reported to be below the detection limit. These values were set to the detection limit for the purposes of data review and of calculating an average composition for each wash solution.

3.3.2 Composition Measurements by Wash Solution Identifier

Exhibit B-1 in Appendix B provides plots of the elemental and anion concentration measurements grouped by the wash solution identifier (including the blanks and standard solutions). Different symbols and colors are used to represent the different solutions. Plotting the data in this format provides an opportunity to review the values for each individual solution as a function of the triplicate measurements. A review of the plots presented in these exhibits reveals the repeatability of the three individual values for each analyte for each solution. These observations were not considered to indicate an error in preparation or measurement that had to be addressed in treatment of the data. Therefore, the entire set of measurement data was used in determining representative, measured compositions for the wash solutions.

3.3.3 Results for the Standard Solutions

Table B-3 in Appendix B provides comparisons of the standard solution results to their reference values. The results in this table indicate no issues with the performance of the analyses.

3.3.4 Measured Compositions of the Wash Solutions

From the discussion of Section 3.3.2, all the measurements for each analyte for each wash solution (Table B-1 and Table B-2 of Appendix B) were averaged to determine a representative chemical composition for each solution. Table B-4 in Appendix B provides a summary of the average measured compositions of the wash solutions. The following observations are offered from the review of Table B-4:

- The wash solutions contained mainly Na (382-1610 mg/L), S (356-710 mg/L), and SO_4^{2-} (1040-2130 mg/L), which could be attributed to the excess sodium sulfate added as part of the SSM preparation process.
- The measured concentrations of Al, B, Ca, Cr, F⁻, K, Li, P, Si, and PO_4^{3-} in the wash solutions were generally 100 mg/L or lower for the majority of the glasses.
- The measured concentration of B in HAIG-11-Q-SSM-S and HAIG-18-Q-SSM-S were 161 mg/L and 217 mg/L, respectively.
- The measured concentrations of Cr in seven glasses were higher than 100 mg/L:

- HAIG-11-Q-SSM-S, HAIG-12-Q-SSM-S, HAIG-14-Q-SSM-S, HAIG-15-Q-SSM-S, HAIG-16-Q-SSM-S, HAIG-18-Q-SSM-S, and HAIG-19-Q-SSM-S.
- The measured concentrations of K in four glasses were higher than 100 mg/L:
 - HAIG-01-Q-SSM-W, HAIG-04-Q-SSM-W, HAIG-07-1-Q-SSM-W, and HAIG-13-Q-SSM-W.
- The measured concentrations of Bi, Cd, Fe, Mg, Mn, Ni, Sr, Ti, Zn and Zr in the wash solutions were near or below the detection limits.

4.0 Summary

Chemical analyses were performed on a series of SSM versions of simulated nuclear waste glasses and resulting wash solutions with ICP-OES and IC. The glasses were designed and fabricated by PNNL as part of a broader study of the influence of glass composition on chemical durability, sulfur retention, and other properties.

The relative differences between the targeted and measured concentrations of B_2O_3 , Cr_2O_3 , K_2O , Li_2O , Na_2O , and P_2O_5 for several of the glasses were greater than $\pm 10\%$. The relative differences between the targeted and measured concentrations of Al_2O_3 and ZrO_2 for one of the glasses were greater than $\pm 10\%$. As expected, the measured concentrations of SO_3 in most of the glasses were higher than targeted due to the use of the sulfur saturation method in fabricating these glasses.

The wash solutions contained mainly sodium, sulfur, and sulfate ions.

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Appendix A. Tables and Exhibits Supporting the HLW HAIG Glass Composition Measurements

Table A-1. KH Measurements (wt.%) of the SSM Study Glasses

PNNL ID	Block	Sub – Block	Seq	Lab ID	F⁺
LRM	1	1	1	LRMKH111	0.898
ARG-1	1	1	2	ARGKH111	<0.0500
HAIG-12-Q-SSM-S	1	1	3	S-14318KH11	0.320
HAIG-23-Q-SSM-S	1	1	4	S-14329KH21	0.276
HAIG-17-Q-SSM-S	1	1	5	S-14323KH11	0.216
HAIG-24-Q-SSM-S	1	1	6	S-14330KH11	0.178
HAIG-13-Q-SSM-S	1	1	7	S-14319KH11	0.457
HAIG-25-Q-SSM-S	1	1	8	S-14331KH21	0.0620
HAIG-22-Q-SSM-S	1	1	9	S-14328KH11	0.512
HAIG-17-Q-SSM-S	1	1	10	S-14323KH21	0.214
LRM	1	1	11	LRMKH112	0.897
ARG-1	1	1	12	ARGKH112	<0.0500
HAIG-22-Q-SSM-S	1	1	13	S-14328KH21	0.509
HAIG-03-Q-SSM-S	1	1	14	S-14310KH21	0.128
HAIG-25-Q-SSM-S	1	1	15	S-14331KH11	0.0621
HAIG-12-Q-SSM-S	1	1	16	S-14318KH21	0.321
HAIG-24-Q-SSM-S	1	1	17	S-14330KH21	0.181
HAIG-03-Q-SSM-S	1	1	18	S-14310KH11	0.128
HAIG-23-Q-SSM-S	1	1	19	S-14329KH11	0.277
HAIG-13-Q-SSM-S	1	1	20	S-14319KH21	0.455
LRM	1	1	21	LRMKH113	0.905
ARG-1	1	1	22	ARGKH113	<0.0500
LRM	1	2	1	LRMKH121	0.906
ARG-1	1	2	2	ARGKH121	<0.0500
HAIG-17-Q-SSM-S	1	2	3	S-14323KH22	0.216
HAIG-22-Q-SSM-S	1	2	4	S-14328KH22	0.511
HAIG-23-Q-SSM-S	1	2	5	S-14329KH22	0.278
HAIG-25-Q-SSM-S	1	2	6	S-14331KH22	0.0628
HAIG-25-Q-SSM-S	1	2	7	S-14331KH12	0.0627
HAIG-24-Q-SSM-S	1	2	8	S-14330KH22	0.181
HAIG-24-Q-SSM-S	1	2	9	S-14330KH12	0.180
HAIG-12-Q-SSM-S	1	2	10	S-14318KH12	0.229
LRM	1	2	11	LRMKH122	0.906
ARG-1	1	2	12	ARGKH122	<0.0500
HAIG-17-Q-SSM-S	1	2	13	S-14323KH12	0.218
HAIG-03-Q-SSM-S	1	2	14	S-14310KH12	0.129
HAIG-03-Q-SSM-S	1	2	15	S-14310KH22	0.128
HAIG-13-Q-SSM-S	1	2	16	S-14319KH12	0.468
HAIG-23-Q-SSM-S	1	2	17	S-14329KH12	0.277
HAIG-12-Q-SSM-S	1	2	18	S-14318KH22	0.324
HAIG-13-Q-SSM-S	1	2	19	S-14319KH22	0.457
HAIG-22-Q-SSM-S	1	2	20	S-14328KH12	0.515
LRM	1	2	21	LRMKH123	0.903
ARG-1	1	2	22	ARGKH123	<0.0500
LRM	2	1	1	LRMKH211	0.899
ARG-1	2	1	2	ARGKH211	<0.0500
HAIG-15-Q-SSM-S	2	1	3	S-14321KH21	0.215

Table A-1. KH Measurements (wt.%) of the SSM Study Glasses (continued)

PNNL ID	Block	Sub – Block	Seq	Lab ID	F ⁻
HAIG-09-Q-SSM-S	2	1	4	S-14316KH21	0.0975
HAIG-14-Q-SSM-S	2	1	5	S-14320KH11	0.0621
HAIG-06-Q-SSM-S	2	1	6	S-14313KH11	0.115
HAIG-11-Q-SSM-S	2	1	7	S-14317KH21	0.195
HAIG-19-Q-SSM-S	2	1	8	S-14325KH11	0.101
HAIG-15-Q-SSM-S	2	1	9	S-14321KH11	0.216
HAIG-16-Q-SSM-S	2	1	10	S-14322KH11	0.154
HAIG-11-Q-SSM-S	2	1	11	S-14317KH11	0.194
LRM	2	1	12	LRMKH212	0.895
ARG-1	2	1	13	ARGKH212	<0.0500
HAIG-06-Q-SSM-S	2	1	14	S-14313KH21	0.113
HAIG-21-Q-SSM-S	2	1	15	S-14327KH21	0.329
HAIG-19-Q-SSM-S	2	1	16	S-14325KH21	0.100
HAIG-18-Q-SSM-S	2	1	17	S-14324KH21	0.224
HAIG-16-Q-SSM-S	2	1	18	S-14322KH21	0.154
HAIG-14-Q-SSM-S	2	1	19	S-14320KH21	0.0613
HAIG-09-Q-SSM-S	2	1	20	S-14316KH11	0.0958
HAIG-18-Q-SSM-S	2	1	21	S-14324KH11	0.221
HAIG-21-Q-SSM-S	2	1	22	S-14327KH11	0.328
LRM	2	1	23	LRMKH213	0.899
ARG-1	2	1	24	ARGKH213	<0.0500
LRM	2	2	1	LRMKH221	0.911
ARG-1	2	2	2	ARGKH221	<0.0500
HAIG-19-Q-SSM-S	2	2	3	S-14325KH22	0.102
HAIG-11-Q-SSM-S	2	2	4	S-14317KH22	0.198
HAIG-06-Q-SSM-S	2	2	5	S-14313KH22	0.115
HAIG-09-Q-SSM-S	2	2	6	S-14316KH22	0.0994
HAIG-14-Q-SSM-S	2	2	7	S-14320KH12	0.0632
HAIG-21-Q-SSM-S	2	2	8	S-14327KH12	0.286
HAIG-18-Q-SSM-S	2	2	9	S-14324KH12	0.224
HAIG-15-Q-SSM-S	2	2	10	S-14321KH22	0.218
HAIG-15-Q-SSM-S	2	2	11	S-14321KH12	0.220
LRM	2	2	12	LRMKH222	0.907
ARG-1	2	2	13	ARGKH222	<0.0500
HAIG-16-Q-SSM-S	2	2	14	S-14322KH12	0.157
HAIG-14-Q-SSM-S	2	2	15	S-14320KH22	0.0626
HAIG-06-Q-SSM-S	2	2	16	S-14313KH12	0.117
HAIG-09-Q-SSM-S	2	2	17	S-14316KH12	0.0980
HAIG-19-Q-SSM-S	2	2	18	S-14325KH12	0.104
HAIG-16-Q-SSM-S	2	2	19	S-14322KH22	0.157
HAIG-18-Q-SSM-S	2	2	20	S-14324KH22	0.227
HAIG-11-Q-SSM-S	2	2	21	S-14317KH12	0.198
HAIG-21-Q-SSM-S	2	2	22	S-14327KH22	0.335
LRM	2	2	23	LRMKH223	0.909
ARG-1	2	2	24	ARGKH223	<0.0500
LRM	3	1	1	LRMKH311	0.898
ARG-1	3	1	2	ARGKH311	<0.0500

Table A-1. KH Measurements (wt.%) of the SSM Study Glasses (continued)

PNNL ID	Block	Sub – Block	Seq	Lab ID	F ⁻
HAIG-08-Q-SSM-S	3	1	3	S-14315KH21	0.0654
HAIG-08-Q-SSM-S	3	1	4	S-14315KH11	0.0631
HAIG-05-Q-SSM-S	3	1	5	S-14312KH11	0.268
HAIG-01-Q-SSM-S	3	1	6	S-14308KH11	0.549
HAIG-04-Q-SSM-S	3	1	7	S-14311KH11	0.468
HAIG-02-Q-SSM-S	3	1	8	S-14309KH21	0.0931
HAIG-20-Q-SSM-S	3	1	9	S-14326KH11	0.144
HAIG-02-Q-SSM-S	3	1	10	S-14309KH11	0.0879
LRM	3	1	11	LRMKH312	0.901
ARG-1	3	1	12	ARGKH312	<0.0500
HAIG-07-1-Q-SSM-S	3	1	13	S-14314KH21	0.439
HAIG-05-Q-SSM-S	3	1	14	S-14312KH21	0.274
HAIG-20-Q-SSM-S	3	1	15	S-14326KH21	0.145
EWG-HAIG-SSM-S	3	1	16	S-14332KH11	<0.0500
HAIG-01-Q-SSM-S	3	1	17	S-14308KH21	0.552
HAIG-07-1-Q-SSM-S	3	1	18	S-14314KH11	0.438
HAIG-04-Q-SSM-S	3	1	19	S-14311KH21	0.469
EWG-HAIG-SSM-S	3	1	20	S-14332KH21	<0.0500
LRM	3	1	21	LRMKH313	0.908
ARG-1	3	1	22	ARGKH313	<0.0500
LRM	3	2	1	LRMKH321	0.900
ARG-1	3	2	2	ARGKH321	<0.0500
HAIG-08-Q-SSM-S	3	2	3	S-14315KH12	0.0639
HAIG-08-Q-SSM-S	3	2	4	S-14315KH22	0.0659
HAIG-02-Q-SSM-S	3	2	5	S-14309KH22	0.0945
HAIG-07-1-Q-SSM-S	3	2	6	S-14314KH22	0.442
EWG-HAIG-SSM-S	3	2	7	S-14332KH12	<0.0500
HAIG-05-Q-SSM-S	3	2	8	S-14312KH22	0.278
HAIG-01-Q-SSM-S	3	2	9	S-14308KH22	0.557
HAIG-04-Q-SSM-S	3	2	10	S-14311KH22	0.474
LRM	3	2	11	LRMKH322	0.905
ARG-1	3	2	12	ARGKH322	<0.0500
HAIG-04-Q-SSM-S	3	2	13	S-14311KH12	0.477
EWG-HAIG-SSM-S	3	2	14	S-14332KH22	<0.0500
HAIG-07-1-Q-SSM-S	3	2	15	S-14314KH12	0.443
HAIG-01-Q-SSM-S	3	2	16	S-14308KH12	0.558
HAIG-20-Q-SSM-S	3	2	17	S-14326KH12	0.147
HAIG-05-Q-SSM-S	3	2	18	S-14312KH12	0.274
HAIG-20-Q-SSM-S	3	2	19	S-14326KH22	0.148
HAIG-02-Q-SSM-S	3	2	20	S-14309KH12	0.0898
LRM	3	2	21	LRMKH322	0.910
ARG-1	3	2	22	ARGKH322	<0.0500

Table A-2. LM Measurements (wt.%) of the SSM Study Glasses

PNNL ID	Block	Sub – Block	Seq	Lab ID	Bi	Ca	Cd	Cr	Fe	Mg	Mn	Na	Ni	S	Sr	Ti	Zn
LRM	1	1	1	LRMLM111	<0.100	0.352	0.138	0.125	1.01	0.0645	0.0638	15.1	0.135	0.0987	<0.0500	0.0587	<0.0500
ARG-1	1	1	2	ARGLM111	<0.100	1.04	<0.0250	0.0643	9.69	0.510	1.47	8.38	0.792	0.0658	<0.0500	0.673	<0.0500
HAIG-14-Q-SSM-S	1	1	3	S-14320LM21	<0.100	0.133	<0.0250	0.633	6.84	0.0595	0.0220	13.6	0.106	0.388	<0.0500	<0.0500	<0.0500
HAIG-07-1-Q-SSM-S	1	1	4	S-14314LM11	0.515	0.842	0.0938	0.0299	6.29	0.362	0.0676	14.7	0.691	0.256	0.0871	0.158	0.165
EWG-HAIG-SSM-S	1	1	5	S-14332LM11	<0.100	1.61	<0.0250	<0.0250	<0.100	<0.0500	<0.0100	7.24	<0.100	<0.0500	0.394	2.00	1.21
HAIG-21-Q-SSM-S	1	1	6	S-14327LM11	0.394	0.647	0.0736	0.183	5.59	0.278	0.0540	11.8	0.555	0.384	0.0665	0.119	0.128
HAIG-12-Q-SSM-S	1	1	7	S-14318LM21	0.397	0.648	0.0717	0.715	0.154	0.280	0.0563	14.3	0.551	0.295	0.0656	0.137	0.124
HAIG-21-Q-SSM-S	1	1	8	S-14327LM21	0.399	0.649	0.0743	0.184	5.63	0.281	0.0541	12.0	0.562	0.362	0.0667	0.117	0.129
HAIG-24-Q-SSM-S	1	1	9	S-14330LM11	0.868	2.43	0.0800	0.451	3.79	0.310	0.752	9.75	0.301	0.425	0.0829	<0.0500	<0.0500
HAIG-17-Q-SSM-S	1	1	10	S-14323LM21	0.259	0.433	0.0485	0.0602	0.533	0.190	0.0314	13.8	0.368	0.360	<0.0500	0.0996	0.0832
LRM	1	1	11	LRMLM112	<0.100	0.356	0.140	0.127	1.04	0.0652	0.0644	15.9	0.137	0.117	<0.0500	0.0596	<0.0500
ARG-1	1	1	12	ARGLM112	<0.100	1.06	<0.0250	0.0650	10.0	0.515	1.50	8.65	0.802	<0.0500	<0.0500	0.683	<0.0500
HAIG-12-Q-SSM-S	1	1	13	S-14318LM11	0.398	0.653	0.0723	0.720	0.150	0.282	0.0482	14.8	0.558	0.308	0.0665	0.139	0.126
HAIG-17-Q-SSM-S	1	1	14	S-14323LM11	0.261	0.436	0.0487	0.0615	0.535	0.192	0.0308	13.9	0.370	0.357	<0.0500	0.102	0.0835
HAIG-08-Q-SSM-S	1	1	15	S-14315LM11	<0.100	0.145	<0.0250	0.371	7.47	0.0638	0.0240	14.3	0.118	0.348	<0.0500	0.0518	<0.0500
EWG-HAIG-SSM-S	1	1	16	S-14332LM21	<0.100	1.64	<0.0250	<0.0250	<0.100	<0.0500	<0.0100	7.49	<0.100	0.0586	0.400	2.04	1.22
HAIG-24-Q-SSM-S	1	1	17	S-14330LM21	0.857	2.46	0.0793	0.445	3.86	0.307	0.749	10.1	0.300	0.432	0.0820	<0.0500	<0.0500
HAIG-07-1-Q-SSM-S	1	1	18	S-14314LM21	0.517	0.851	0.0945	0.0302	6.51	0.364	0.0691	15.5	0.704	0.233	0.0883	0.159	0.165
HAIG-14-Q-SSM-S	1	1	19	S-14320LM11	<0.100	0.134	<0.0250	0.630	7.05	0.0600	0.0218	14.4	0.106	0.391	<0.0500	<0.0500	<0.0500
HAIG-08-Q-SSM-S	1	1	20	S-14315LM21	<0.100	0.142	<0.0250	0.363	7.45	0.0625	0.0232	14.3	0.115	0.333	<0.0500	0.0503	<0.0500
LRM	1	1	21	LRMLM113	<0.100	0.356	0.140	0.127	1.06	0.0654	0.0644	16.0	0.137	0.102	<0.0500	0.0596	<0.0500
ARG-1	1	1	22	ARGLM113	<0.100	1.05	<0.0250	0.0637	10.2	0.506	1.48	8.93	0.783	0.0519	<0.0500	0.670	<0.0500
LRM	1	2	1	LRMLM121	<0.100	0.347	0.137	0.125	1.03	0.0637	0.0633	15.8	0.134	0.0906	<0.0500	0.0583	<0.0500
ARG-1	1	2	2	ARGLM121	<0.100	1.01	<0.0250	0.0633	10.0	0.498	1.38	9.03	0.774	<0.0500	<0.0500	0.665	<0.0500
EWG-HAIG-SSM-S	1	2	3	S-14332LM12	<0.100	1.66	<0.0250	<0.0250	<0.100	<0.0500	<0.0100	7.55	<0.100	<0.0500	0.378	2.09	1.22
HAIG-24-Q-SSM-S	1	2	4	S-14330LM12	0.851	2.45	0.0779	0.443	3.81	0.302	0.738	9.92	0.294	0.430	0.0794	<0.0500	<0.0500
HAIG-08-Q-SSM-S	1	2	5	S-14315LM12	<0.100	0.141	<0.0250	0.366	7.37	0.0623	0.0236	14.4	0.115	0.326	<0.0500	0.0508	<0.0500
HAIG-12-Q-SSM-S	1	2	6	S-14318LM22	0.388	0.633	0.0702	0.705	0.153	0.274	0.0555	14.9	0.542	0.288	0.0631	0.135	0.119
HAIG-14-Q-SSM-S	1	2	7	S-14320LM22	<0.100	0.131	<0.0250	0.624	7.00	0.0581	0.0219	14.4	0.103	0.389	<0.0500	<0.0500	<0.0500
HAIG-21-Q-SSM-S	1	2	8	S-14327LM12	0.385	0.635	0.0720	0.181	5.73	0.274	0.0531	12.5	0.546	0.377	0.0643	0.118	0.123
EWG-HAIG-SSM-S	1	2	9	S-14332LM22	<0.100	1.66	<0.0250	<0.0250	<0.100	<0.0500	<0.0100	7.54	<0.100	<0.0500	0.385	2.08	1.23
HAIG-07-1-Q-SSM-S	1	2	10	S-14314LM12	0.526	0.840	0.0937	0.0300	6.47	0.361	0.0681	15.7	0.694	0.237	0.0860	0.159	0.161
LRM	1	2	11	LRMLM122	<0.100	0.349	0.137	0.125	1.04	0.0639	0.0634	16.1	0.135	0.117	<0.0500	0.0587	<0.0500
ARG-1	1	2	12	ARGLM122	<0.100	1.03	<0.0250	0.0640	10.0	0.502	1.40	8.84	0.782	<0.0500	<0.0500	0.673	<0.0500
HAIG-17-Q-SSM-S	1	2	13	S-14323LM12	0.267	0.430	0.0483	0.0615	0.532	0.190	0.0307	13.8	0.367	0.352	<0.0500	0.102	0.0821
HAIG-21-Q-SSM-S	1	2	14	S-14327LM22	0.410	0.649	0.0740	0.185	5.74	0.280	0.0545	12.4	0.563	0.374	0.0661	0.118	0.126
HAIG-17-Q-SSM-S	1	2	15	S-14323LM22	0.264	0.429	0.0482	0.0605	0.534	0.190	0.0314	14.0	0.367	0.350	<0.0500	0.0999	0.0820
HAIG-14-Q-SSM-S	1	2	16	S-14320LM12	<0.100	0.133	<0.0250	0.635	7.07	0.0598	0.0217	14.5	0.106	0.399	<0.0500	<0.0500	<0.0500
HAIG-07-1-Q-SSM-S	1	2	17	S-14314LM22	0.521	0.840	0.0932	0.0305	6.51	0.360	0.0688	15.6	0.697	0.254	0.0864	0.158	0.161
HAIG-12-Q-SSM-S	1	2	18	S-14318LM12	0.401	0.645	0.0717	0.719	0.150	0.280	0.048	15.1	0.553	0.327	0.0651	0.138	0.122
HAIG-08-Q-SSM-S	1	2	19	S-14315LM22	<0.100	0.141	<0.0250	0.367	7.45	0.0625	0.0232	14.4	0.115	0.346	<0.0500	0.0505	<0.0500
HAIG-24-Q-SSM-S	1	2	20	S-14330LM22	0.877	2.51	0.0793	0.450	3.90	0.308	0.752	10.2	0.300	0.452	0.0813	<0.0500	<0.0500
LRM	1	2	21	LRMLM123	<0.100	0.352	0.139	0.126	1.06	0.0644	0.0641	16.3	0.136	0.0946	<0.0500	0.0591	<0.0500
ARG-1	1	2	22	ARGLM123	<0.100	1.03	<0.0250	0.0643	10.2	0.505	1.47	9.55	0.787	0.0661	<0.0500	0.679	<0.0500
LRM	2	1	1	LRMLM211	<0.100	0.345	0.136	0.124	1.00	0.0631	0.0627	15.2	0.133	0.0899	<0.0500	0.0576	<0.0500
ARG-1	2	1	2	ARGLM211	<0.100	1.04	<0.0250	0.0646	9.83	0.502	1.49	8.64	0.790	<0.0500	<0.0500	0.671	<0.0500
HAIG-05-Q-SSM-S	2	1	3	S-14312LM11	0.350	0.590	0.0685	0.392	7.56	0.254	0.0532	12.8	0.495	0.316	0.0604	0.123	0.115

Table A-2. LM Measurements (wt.%) of the SSM Study Glasses (continued)

PNNL ID	Block	Sub – Block	Seq	Lab ID	Bi	Ca	Cd	Cr	Fe	Mg	Mn	Na	Ni	S	Sr	Ti	Zn
HAIG-06-Q-SSM-S	2	1	4	S-14313LM21	0.153	0.263	0.0281	0.691	1.03	0.114	0.0189	15.4	0.218	0.316	<0.0500	0.0741	0.0509
HAIG-02-Q-SSM-S	2	1	5	S-14309LM21	0.121	0.211	<0.0250	0.784	3.19	0.0912	0.0202	14.9	0.175	0.382	<0.0500	0.0555	<0.0500
HAIG-06-Q-SSM-S	2	1	6	S-14313LM11	0.160	0.266	0.0286	0.703	1.02	0.116	0.0190	15.3	0.221	0.322	<0.0500	0.0754	0.0512
HAIG-01-Q-SSM-S	2	1	7	S-14308LM21	0.645	1.05	0.118	<0.0250	0.968	0.439	0.0713	15.1	0.898	0.313	0.109	0.181	0.205
HAIG-20-Q-SSM-S	2	1	8	S-14326LM11	0.188	0.307	0.0348	0.774	0.515	0.135	0.0216	11.7	0.265	0.456	<0.0500	0.0579	0.0599
HAIG-02-Q-SSM-S	2	1	9	S-14309LM11	0.120	0.215	<0.0250	0.791	3.24	0.0923	0.0201	15.0	0.177	0.397	<0.0500	0.0570	<0.0500
HAIG-22-Q-SSM-S	2	1	10	S-14328LM11	0.603	0.962	0.111	0.918	0.832	0.415	0.0657	11.0	0.837	0.417	0.0964	0.177	0.186
HAIG-01-Q-SSM-S	2	1	11	S-14308LM11	0.650	1.04	0.120	<0.0250	0.979	0.443	0.0723	15.0	0.910	0.341	0.110	0.182	0.209
LRM	2	1	12	LRMLM212	<0.100	0.365	0.145	0.130	1.02	0.0664	0.0659	15.6	0.141	0.105	<0.0500	0.0608	<0.0500
ARG-1	2	1	13	ARGLM212	<0.100	1.07	<0.0250	0.0662	9.85	0.518	1.52	8.80	0.813	0.0620	<0.0500	0.688	<0.0500
HAIG-25-Q-SSM-S	2	1	14	S-14331LM11	<0.100	0.148	<0.0250	0.378	7.22	0.0643	0.0245	13.7	0.119	0.358	<0.0500	0.0521	<0.0500
HAIG-11-Q-SSM-S	2	1	15	S-14317LM21	0.283	0.479	0.0491	0.265	1.25	0.206	0.0337	13.8	0.403	0.255	<0.0500	0.107	0.0912
HAIG-25-Q-SSM-S	2	1	16	S-14331LM21	<0.100	0.146	<0.0250	0.375	7.19	0.0640	0.0246	13.7	0.119	0.357	<0.0500	0.0516	<0.0500
HAIG-05-Q-SSM-S	2	1	17	S-14312LM21	0.358	0.602	0.0701	0.400	7.48	0.259	0.0539	12.6	0.509	0.334	0.0616	0.125	0.117
HAIG-11-Q-SSM-S	2	1	18	S-14317LM11	0.274	0.474	0.0487	0.262	1.26	0.204	0.0335	13.9	0.398	0.224	<0.0500	0.106	0.0904
HAIG-22-Q-SSM-S	2	1	19	S-14328LM21	0.580	0.943	0.109	0.897	0.812	0.407	0.0644	10.8	0.820	0.380	0.0936	0.174	0.182
HAIG-16-Q-SSM-S	2	1	20	S-14322LM21	0.185	0.329	0.0340	0.746	2.94	0.144	0.0271	14.3	0.272	0.292	<0.0500	0.0837	0.0624
HAIG-16-Q-SSM-S	2	1	21	S-14322LM11	0.182	0.330	0.0337	0.740	2.95	0.143	0.0269	14.2	0.270	0.283	<0.0500	0.0826	0.0629
HAIG-20-Q-SSM-S	2	1	22	S-14326LM21	0.175	0.302	0.0342	0.761	0.504	0.133	0.0206	11.8	0.260	0.465	<0.0500	0.0572	0.0585
LRM	2	1	23	LRMLM213	<0.100	0.358	0.141	0.127	1.02	0.0648	0.0642	15.7	0.137	0.113	<0.0500	0.0589	<0.0500
ARG-1	2	1	24	ARGLM213	<0.100	1.05	<0.0250	0.0658	9.87	0.513	1.47	8.72	0.805	0.0704	<0.0500	0.681	<0.0500
LRM	2	2	1	LRMLM221	<0.100	0.349	0.139	0.127	0.991	0.0632	0.0625	15.1	0.135	0.0638	<0.0500	0.0584	<0.0500
ARG-1	2	2	2	ARGLM221	<0.100	1.02	<0.0250	0.0638	9.62	0.492	1.43	8.91	0.775	<0.0500	<0.0500	0.663	<0.0500
HAIG-20-Q-SSM-S	2	2	3	S-14326LM22	0.175	0.291	0.0332	0.754	0.504	0.128	0.0198	11.4	0.252	0.465	<0.0500	0.0553	0.0556
HAIG-05-Q-SSM-S	2	2	4	S-14312LM12	0.339	0.574	0.0670	0.388	7.46	0.246	0.0516	12.5	0.483	0.319	0.0570	0.120	0.111
HAIG-25-Q-SSM-S	2	2	5	S-14331LM22	<0.100	0.139	<0.0250	0.365	7.24	0.0607	0.0230	13.9	0.114	0.329	<0.0500	<0.0500	<0.0500
HAIG-20-Q-SSM-S	2	2	6	S-14326LM12	0.169	0.292	0.0331	0.749	0.504	0.128	0.0200	11.6	0.253	0.470	<0.0500	0.0531	0.0554
HAIG-05-Q-SSM-S	2	2	7	S-14312LM22	0.337	0.575	0.0673	0.389	7.49	0.247	0.0508	12.9	0.485	0.312	0.0571	0.120	0.110
HAIG-06-Q-SSM-S	2	2	8	S-14313LM12	0.147	0.256	0.0274	0.688	1.01	0.111	0.0178	15.3	0.213	0.327	<0.0500	0.0720	<0.0500
HAIG-22-Q-SSM-S	2	2	9	S-14328LM12	0.543	0.893	0.104	0.868	0.791	0.385	0.0600	10.5	0.777	0.395	0.0866	0.163	0.169
HAIG-02-Q-SSM-S	2	2	10	S-14309LM22	0.103	0.198	<0.0250	0.746	3.17	0.0850	0.0184	14.8	0.163	0.371	<0.0500	<0.0500	<0.0500
HAIG-11-Q-SSM-S	2	2	11	S-14317LM22	0.256	0.452	0.0462	0.254	1.25	0.193	0.0310	14.1	0.378	0.223	<0.0500	0.100	0.0845
LRM	2	2	12	LRMLM222	<0.100	0.318	0.126	0.118	1.01	0.0590	0.0577	15.5	0.123	0.0629	<0.0500	0.0549	<0.0500
ARG-1	2	2	13	ARGLM222	<0.100	0.973	<0.0250	0.0635	9.70	0.490	1.41	8.62	0.757	0.0500	<0.0500	0.673	<0.0500
HAIG-16-Q-SSM-S	2	2	14	S-14322LM22	0.205	0.313	0.0322	0.735	2.94	0.139	0.0261	14.3	0.260	0.281	<0.0500	0.0829	0.0600
HAIG-01-Q-SSM-S	2	2	15	S-14308LM12	0.647	1.02	0.111	<0.0250	0.939	0.418	0.0675	14.9	0.850	0.329	0.104	0.174	0.192
HAIG-25-Q-SSM-S	2	2	16	S-14331LM12	<0.100	0.139	<0.0250	0.367	7.21	0.0613	0.0230	13.8	0.113	0.323	<0.0500	0.0511	<0.0500
HAIG-11-Q-SSM-S	2	2	17	S-14317LM12	0.298	0.453	0.0467	0.260	1.26	0.198	0.0320	14.0	0.384	0.202	<0.0500	0.105	0.0868
HAIG-06-Q-SSM-S	2	2	18	S-14313LM22	0.171	0.254	0.0272	0.689	1.01	0.111	0.0180	15.1	0.212	0.314	<0.0500	0.0742	<0.0500
HAIG-22-Q-SSM-S	2	2	19	S-14328LM22	0.608	0.903	0.105	0.890	0.802	0.393	0.0618	10.4	0.788	0.395	0.0917	0.174	0.175
HAIG-01-Q-SSM-S	2	2	20	S-14308LM22	0.653	1.03	0.113	<0.0250	0.943	0.421	0.0677	14.9	0.854	0.346	0.105	0.174	0.195
HAIG-02-Q-SSM-S	2	2	21	S-14309LM12	0.137	0.204	<0.0250	0.778	3.18	0.0892	0.0189	14.8	0.169	0.396	<0.0500	0.0536	<0.0500
HAIG-16-Q-SSM-S	2	2	22	S-14322LM12	0.207	0.317	0.0323	0.736	2.94	0.139	0.0258	14.1	0.261	0.285	<0.0500	0.0831	0.0605
LRM	2	2	23	LRMLM223	<0.100	0.348	0.137	0.128	1.01	0.0636	0.0628	15.6	0.134	0.0817	<0.0500	0.0600	<0.0500
ARG-1	2	2	24	ARGLM223	<0.100	1.02	<0.0250	0.0644	9.74	0.496	1.44	8.63	0.771	<0.0500	<0.0500	0.685	<0.0500
LRM	3	1	1	LRMLM311	<0.100	0.349	0.140	0.127	0.998	0.0644	0.0619	15.1	0.139	0.0939	<0.0500	0.0618	<0.0500
ARG-1	3	1	2	ARGLM311	<0.100	0.994	<0.0250	0.0623	9.67	0.484	1.42	8.55	0.764	0.0518	<0.0500	0.650	<0.0500

Table A-2. LM Measurements (wt.%) of the SSM Study Glasses (continued)

PNNL ID	Block	Sub – Block	Seq	Lab ID	Bi	Ca	Cd	Cr	Fe	Mg	Mn	Na	Ni	S	Sr	Ti	Zn
HAIG-09-Q-SSM-S	3	1	3	S-14316LM11	0.119	0.216	<0.0250	0.475	3.25	0.0932	0.0202	11.0	0.176	0.505	<0.0500	0.0629	<0.0500
HAIG-13-Q-SSM-S	3	1	4	S-14319LM21	0.465	0.779	0.0833	0.0553	5.82	0.328	0.0617	12.7	0.658	0.389	0.0809	0.156	0.152
HAIG-19-Q-SSM-S	3	1	5	S-14325LM11	0.113	0.193	<0.0250	0.197	4.17	0.0849	0.0205	14.6	0.157	0.339	<0.0500	0.0638	<0.0500
HAIG-23-Q-SSM-S	3	1	6	S-14329LM21	0.336	0.533	0.0601	0.478	0.144	0.230	0.0356	9.64	0.461	0.493	0.0547	0.0983	0.104
HAIG-03-Q-SSM-S	3	1	7	S-14310LM11	0.183	0.292	0.0329	0.0916	3.79	0.129	0.0269	13.2	0.252	0.324	<0.0500	0.0629	0.0579
HAIG-04-Q-SSM-S	3	1	8	S-14311LM11	0.540	0.859	0.0984	0.532	4.73	0.368	0.0658	14.3	0.750	0.277	0.0886	0.168	0.168
HAIG-18-Q-SSM-S	3	1	9	S-14324LM11	0.300	0.488	0.0528	0.177	0.337	0.208	0.0324	12.4	0.414	0.359	0.0501	0.0955	0.0946
HAIG-04-Q-SSM-S	3	1	10	S-14311LM21	0.540	0.859	0.0989	0.532	4.71	0.368	0.0661	14.4	0.753	0.258	0.0882	0.168	0.168
LRM	3	1	11	LRMLM312	<0.100	0.356	0.143	0.128	1.01	0.0654	0.0626	15.5	0.141	0.0694	<0.0500	0.0629	<0.0500
ARG-1	3	1	12	ARGLM312	<0.100	1.03	<0.0250	0.0633	9.66	0.491	1.45	8.70	0.777	<0.0500	<0.0500	0.664	<0.0500
HAIG-13-Q-SSM-S	3	1	13	S-14319LM11	0.480	0.800	0.0862	0.0565	5.83	0.338	0.0636	12.7	0.678	0.398	0.0829	0.161	0.156
HAIG-19-Q-SSM-S	3	1	14	S-14325LM21	0.111	0.197	<0.0250	0.200	4.17	0.0858	0.0207	14.7	0.160	0.355	<0.0500	0.0643	<0.0500
HAIG-23-Q-SSM-S	3	1	15	S-14329LM11	0.339	0.550	0.0619	0.489	0.150	0.236	0.0366	9.71	0.475	0.504	0.0562	0.0990	0.106
HAIG-15-Q-SSM-S	3	1	16	S-14321LM21	0.257	0.419	0.0453	0.953	0.880	0.181	0.0288	11.6	0.355	0.373	<0.0500	0.0964	0.0828
HAIG-18-Q-SSM-S	3	1	17	S-14324LM21	0.300	0.488	0.0528	0.176	0.336	0.209	0.0325	12.6	0.414	0.359	0.0502	0.0950	0.0947
HAIG-03-Q-SSM-S	3	1	18	S-14310LM21	0.182	0.292	0.0331	0.0922	3.800	0.129	0.0270	13.2	0.252	0.330	<0.0500	0.0631	0.0581
HAIG-15-Q-SSM-S	3	1	19	S-14321LM11	0.256	0.417	0.0452	0.951	0.886	0.181	0.0287	11.5	0.355	0.372	<0.0500	0.0963	0.0806
HAIG-09-Q-SSM-S	3	1	20	S-14316LM21	0.126	0.220	<0.0250	0.483	3.21	0.0946	0.0203	11.0	0.180	0.468	<0.0500	0.0642	<0.0500
LRM	3	1	21	LRMLM313	<0.100	0.356	0.143	0.129	1.01	0.0655	0.0626	15.6	0.141	0.0982	<0.0500	0.0632	<0.0500
ARG-1	3	1	22	ARGLM313	<0.100	1.02	<0.0250	0.0634	9.65	0.490	1.45	8.57	0.778	0.0665	<0.0500	0.664	<0.0500
LRM	3	2	1	LRMLM321	<0.100	0.358	0.144	0.130	1.01	0.0652	0.0631	14.7	0.140	0.0918	<0.0500	0.0631	<0.0500
ARG-1	3	2	2	ARGLM321	<0.100	1.02	<0.0250	0.0634	9.79	0.486	1.45	8.37	0.770	<0.0500	<0.0500	0.660	<0.0500
HAIG-23-Q-SSM-S	3	2	3	S-14329LM12	0.341	0.552	0.0621	0.494	0.151	0.235	0.0367	9.37	0.472	0.521	0.0562	0.0986	0.105
HAIG-15-Q-SSM-S	3	2	4	S-14321LM22	0.248	0.422	0.0454	0.960	0.881	0.180	0.0288	11.2	0.354	0.378	<0.0500	0.0960	0.0812
HAIG-23-Q-SSM-S	3	2	5	S-14329LM22	0.327	0.544	0.0608	0.486	0.147	0.231	0.0360	9.24	0.463	0.540	0.0553	0.0982	0.104
HAIG-13-Q-SSM-S	3	2	6	S-14319LM22	0.465	0.798	0.0852	0.0566	5.97	0.333	0.0627	12.4	0.665	0.368	0.0821	0.159	0.152
HAIG-04-Q-SSM-S	3	2	7	S-14311LM22	0.532	0.865	0.0992	0.537	4.89	0.366	0.0660	14.1	0.748	0.263	0.0882	0.168	0.165
HAIG-15-Q-SSM-S	3	2	8	S-14321LM12	0.245	0.417	0.0450	0.949	0.879	0.178	0.0283	11.3	0.349	0.371	<0.0500	0.0950	0.0788
HAIG-09-Q-SSM-S	3	2	9	S-14316LM22	0.118	0.221	<0.0250	0.486	3.27	0.0939	0.0202	10.6	0.178	0.505	<0.0500	0.0637	<0.0500
HAIG-18-Q-SSM-S	3	2	10	S-14324LM22	0.293	0.493	0.0531	0.178	0.339	0.207	0.0326	12.1	0.412	0.371	0.0505	0.0944	0.0938
LRM	3	2	11	LRMLM322	<0.100	0.358	0.143	0.129	1.02	0.0649	0.0627	15.1	0.140	0.0982	<0.0500	0.0629	<0.0500
ARG-1	3	2	12	ARGLM322	<0.100	1.02	<0.0250	0.0635	9.85	0.488	1.44	8.45	0.772	0.0508	<0.0500	0.663	<0.0500
HAIG-03-Q-SSM-S	3	2	13	S-14310LM22	0.172	0.295	0.0331	0.0933	3.87	0.129	0.0271	12.8	0.250	0.320	<0.0500	0.0621	0.0574
HAIG-13-Q-SSM-S	3	2	14	S-14319LM12	0.471	0.808	0.0870	0.0570	6.01	0.337	0.0638	12.4	0.676	0.388	0.0833	0.161	0.155
HAIG-19-Q-SSM-S	3	2	15	S-14325LM12	0.103	0.197	<0.0250	0.200	4.27	0.0850	0.0205	14.3	0.158	0.355	<0.0500	0.0635	<0.0500
HAIG-09-Q-SSM-S	3	2	16	S-14316LM12	0.115	0.220	<0.0250	0.483	3.37	0.0940	0.0209	10.8	0.177	0.496	<0.0500	0.0639	<0.0500
HAIG-19-Q-SSM-S	3	2	17	S-14325LM22	0.106	0.199	<0.0250	0.201	4.28	0.0854	0.0206	14.3	0.159	0.351	<0.0500	0.0639	<0.0500
HAIG-18-Q-SSM-S	3	2	18	S-14324LM12	0.298	0.496	0.0533	0.180	0.341	0.208	0.0327	12.1	0.414	0.373	0.0507	0.0955	0.0947
HAIG-04-Q-SSM-S	3	2	19	S-14311LM12	0.538	0.872	0.0994	0.540	4.86	0.369	0.0665	14.0	0.750	0.264	0.0895	0.170	0.168
HAIG-03-Q-SSM-S	3	2	20	S-14310LM12	0.181	0.298	0.0333	0.0933	3.88	0.130	0.0272	12.7	0.253	0.329	<0.0500	0.0624	0.0579
LRM	3	2	21	LRMLM323	<0.100	0.358	0.144	0.130	1.02	0.0652	0.0629	15.1	0.140	0.0928	<0.0500	0.0632	<0.0500
ARG-1	3	2	22	ARGLM323	<0.100	1.02	<0.0250	0.0637	9.83	0.491	1.45	8.41	0.774	0.0531	<0.0500	0.667	<0.0500

Table A-3. PF Measurements (wt.%) of the SSM Study Glasses

PNNL ID	Block	Sub – Block	Seq	Lab ID	Al	B	K	Li	P	Si	Zr
LRM	1	1	1	LRMPF111	5.35	2.43	1.43	<0.100	0.193	26.5	0.725
ARG-1	1	1	2	ARGLM111	2.59	2.64	2.54	1.50	<0.100	23.1	<0.100
HAIG-14-Q-SSM-S	1	1	3	S-14320PF11	12.2	5.18	0.416	2.40	0.275	11.1	0.437
HAIG-12-Q-SSM-S	1	1	4	S-14318PF21	11.4	5.02	1.15	0.313	0.443	14.3	4.39
HAIG-23-Q-SSM-S	1	1	5	S-14329PF21	10.9	5.33	1.09	2.54	1.31	16.3	1.54
HAIG-11-Q-SSM-S	1	1	6	S-14317PF11	13.7	2.46	0.795	2.10	1.47	13.3	4.16
HAIG-01-Q-SSM-S	1	1	7	S-14308PF21	11.0	2.96	1.77	0.204	1.58	15.8	3.25
HAIG-15-Q-SSM-S	1	1	8	S-14321PF11	12.1	2.68	0.833	2.70	0.101	19.9	0.816
HAIG-17-Q-SSM-S	1	1	9	S-14323PF11	11.1	4.03	0.860	1.15	0.392	17.9	3.12
HAIG-12-Q-SSM-S	1	1	10	S-14318PF11	11.4	5.02	1.19	0.313	0.428	14.4	4.45
LRM	1	1	11	LRMPF112	5.42	2.45	1.47	<0.100	0.184	26.8	0.817
ARG-1	1	1	12	ARGLM112	2.55	2.61	2.48	1.50	<0.100	23.0	<0.100
HAIG-17-Q-SSM-S	1	1	13	S-14323PF21	11.0	4.00	0.906	1.14	0.396	17.9	3.10
HAIG-01-Q-SSM-S	1	1	14	S-14308PF11	10.9	2.91	1.88	0.227	1.56	15.8	3.27
HAIG-14-Q-SSM-S	1	1	15	S-14320PF21	12.0	5.08	0.351	2.37	0.322	10.9	0.450
HAIG-02-Q-SSM-S	1	1	16	S-14309PF21	12.9	6.19	0.477	0.459	1.51	11.3	1.54
HAIG-02-Q-SSM-S	1	1	17	S-14309PF11	12.5	5.97	0.478	0.447	1.49	11.0	1.47
HAIG-15-Q-SSM-S	1	1	18	S-14321PF21	12.2	2.69	0.796	2.69	0.123	20.2	0.818
HAIG-11-Q-SSM-S	1	1	19	S-14317PF21	13.6	2.44	0.697	2.08	1.45	13.3	4.18
HAIG-23-Q-SSM-S	1	1	20	S-14329PF11	11.2	5.44	1.11	2.57	1.36	16.7	1.56
LRM	1	1	21	LRMPF113	5.46	2.45	1.45	<0.100	0.253	26.8	0.787
ARG-1	1	1	22	ARGLM113	2.58	2.62	2.56	1.50	0.106	23.2	<0.100
LRM	1	2	1	LRMPF121	5.32	2.38	1.25	<0.100	0.200	26.0	0.714
ARG-1	1	2	2	ARGLM121	2.52	2.55	2.39	1.43	0.119	22.4	<0.100
HAIG-17-Q-SSM-S	1	2	3	S-14323PF12	10.9	3.88	0.709	1.09	0.425	17.5	2.99
HAIG-12-Q-SSM-S	1	2	4	S-14318PF22	11.2	4.84	0.968	0.267	0.435	13.8	4.25
HAIG-14-Q-SSM-S	1	2	5	S-14320PF12	11.9	4.96	0.150	2.27	0.275	10.7	0.445
HAIG-15-Q-SSM-S	1	2	6	S-14321PF12	11.7	2.57	0.701	2.54	0.104	19.2	0.776
HAIG-11-Q-SSM-S	1	2	7	S-14317PF22	13.4	2.39	0.644	1.99	1.46	13.0	4.01
HAIG-14-Q-SSM-S	1	2	8	S-14320PF22	12.1	5.02	0.245	2.30	0.304	10.8	0.437
HAIG-15-Q-SSM-S	1	2	9	S-14321PF22	11.8	2.59	0.632	2.53	0.114	19.3	0.779
HAIG-11-Q-SSM-S	1	2	10	S-14317PF12	13.3	2.37	0.654	1.97	1.43	12.8	3.95
LRM	1	2	11	LRMPF122	5.32	2.36	1.21	<0.100	0.244	25.8	0.759
ARG-1	1	2	12	ARGLM122	2.52	2.53	2.33	1.43	0.104	22.4	<0.100
HAIG-23-Q-SSM-S	1	2	13	S-14329PF12	10.7	5.18	0.955	2.44	1.32	16.3	1.45
HAIG-02-Q-SSM-S	1	2	14	S-14309PF22	12.3	5.82	0.341	0.405	1.48	10.6	1.41
HAIG-02-Q-SSM-S	1	2	15	S-14309PF12	12.3	5.82	0.345	0.403	1.49	10.6	1.39
HAIG-23-Q-SSM-S	1	2	16	S-14329PF22	10.6	5.14	0.959	2.42	1.37	15.7	1.45
HAIG-17-Q-SSM-S	1	2	17	S-14323PF22	10.8	3.89	0.759	1.09	0.457	17.3	3.00
HAIG-01-Q-SSM-S	1	2	18	S-14308PF12	10.8	2.89	1.61	0.184	1.58	15.4	3.16
HAIG-01-Q-SSM-S	1	2	19	S-14308PF22	10.6	2.82	1.59	0.194	1.58	15.1	3.05
HAIG-12-Q-SSM-S	1	2	20	S-14318PF12	11.3	4.88	1.05	0.265	0.474	14.0	4.32
LRM	1	2	21	LRMPF123	5.27	2.36	1.30	<0.100	0.223	25.8	0.779
ARG-1	1	2	22	ARGLM123	2.49	2.53	2.25	1.42	0.119	22.3	<0.100
LRM	2	1	1	LRMPF211	5.23	2.33	1.28	<0.100	0.197	25.6	0.723
ARG-1	2	1	2	ARGLM211	2.52	2.53	2.34	1.47	0.112	22.4	<0.100
HAIG-08-Q-SSM-S	2	1	3	S-14315PF21	12.4	4.33	0.303	0.879	1.66	11.5	<0.100

Table A-3. PF Measurements (wt.%) of the SSM Study Glasses (continued)

PNNL ID	Block	Sub – Block	Seq	Lab ID	Al	B	K	Li	P	Si	Zr
HAIG-22-Q-SSM-S	2	1	4	S-14328PF11	10.5	2.73	1.41	1.85	1.04	17.5	1.52
HAIG-19-Q-SSM-S	2	1	5	S-14325PF21	14.2	2.36	0.323	2.44	0.611	12.4	1.99
HAIG-21-Q-SSM-S	2	1	6	S-14327PF11	11.7	3.22	0.995	1.96	1.71	12.1	0.865
HAIG-05-Q-SSM-S	2	1	7	S-14312PF11	10.3	6.23	1.02	0.183	0.358	10.3	2.21
HAIG-08-Q-SSM-S	2	1	8	S-14315PF11	12.7	4.43	0.325	0.882	1.73	11.9	<0.100
HAIG-22-Q-SSM-S	2	1	9	S-14328PF21	10.8	2.79	1.54	1.86	1.05	18.0	1.58
HAIG-05-Q-SSM-S	2	1	10	S-14312PF21	10.4	6.32	1.03	0.188	0.345	10.5	2.25
HAIG-13-Q-SSM-S	2	1	11	S-14319PF21	10.7	2.44	1.14	2.11	0.252	13.5	4.03
LRM	2	1	12	LRMPF212	5.27	2.33	1.27	<0.100	0.204	25.8	0.810
ARG-1	2	1	13	ARGLM212	2.53	2.51	2.36	1.46	<0.100	22.6	0.104
HAIG-13-Q-SSM-S	2	1	14	S-14319PF11	10.9	2.49	1.15	2.14	0.262	13.8	4.06
HAIG-07-1-Q-SSM-S	2	1	15	S-14314PF11	12.5	3.41	1.30	<0.100	0.800	12.1	1.44
HAIG-18-Q-SSM-S	2	1	16	S-14324PF11	14.2	2.74	0.697	2.40	1.53	10.7	2.38
HAIG-20-Q-SSM-S	2	1	17	S-14326PF11	10.8	5.95	0.522	1.50	1.75	13.9	2.23
HAIG-19-Q-SSM-S	2	1	18	S-14325PF11	14.4	2.36	0.315	2.44	0.615	12.5	2.00
HAIG-07-1-Q-SSM-S	2	1	19	S-14314PF21	12.9	3.48	1.34	<0.100	0.841	12.4	1.46
HAIG-20-Q-SSM-S	2	1	20	S-14326PF21	10.7	5.91	0.511	1.47	1.73	13.8	2.21
HAIG-21-Q-SSM-S	2	1	21	S-14327PF21	11.7	3.21	0.989	1.98	1.68	12.2	0.845
HAIG-18-Q-SSM-S	2	1	22	S-14324PF21	14.0	2.69	0.681	2.39	1.51	10.8	2.34
LRM	2	1	23	LRMPF213	5.34	2.33	1.29	<0.100	0.242	26.0	0.782
ARG-1	2	1	24	ARGLM213	2.51	2.51	2.30	1.46	0.106	22.5	0.101
LRM	2	2	1	LRMPF221	5.10	2.28	1.21	<0.100	0.181	25.2	0.682
ARG-1	2	2	2	ARGLM221	2.42	2.46	2.23	1.40	<0.100	21.9	<0.100
HAIG-05-Q-SSM-S	2	2	3	S-14312PF12	9.95	6.01	1.01	0.142	0.314	10.0	2.07
HAIG-20-Q-SSM-S	2	2	4	S-14326PF22	10.5	5.76	0.539	1.42	1.70	13.4	2.09
HAIG-07-1-Q-SSM-S	2	2	5	S-14314PF22	12.0	3.31	1.24	<0.100	0.805	11.7	1.31
HAIG-13-Q-SSM-S	2	2	6	S-14319PF12	10.3	2.36	1.07	2.04	0.261	13.0	3.77
HAIG-05-Q-SSM-S	2	2	7	S-14312PF22	10.1	6.13	0.933	0.137	0.300	10.2	2.14
HAIG-22-Q-SSM-S	2	2	8	S-14328PF12	10.5	2.72	1.41	1.78	1.01	17.4	1.50
HAIG-21-Q-SSM-S	2	2	9	S-14327PF22	11.4	3.19	0.992	1.91	1.73	11.8	0.798
HAIG-13-Q-SSM-S	2	2	10	S-14319PF22	10.4	2.38	1.06	2.06	0.281	13.2	3.81
HAIG-08-Q-SSM-S	2	2	11	S-14315PF22	12.2	4.24	0.268	0.84	1.69	11.3	<0.100
LRM	2	2	12	LRMPF222	5.13	2.30	1.27	<0.100	0.248	25.3	0.720
ARG-1	2	2	13	ARGLM222	2.45	2.48	2.27	1.42	<0.100	22.0	<0.100
HAIG-19-Q-SSM-S	2	2	14	S-14325PF22	13.8	2.30	0.290	2.32	0.577	12.0	1.87
HAIG-08-Q-SSM-S	2	2	15	S-14315PF12	12.1	4.24	0.251	0.831	1.70	11.3	<0.100
HAIG-07-1-Q-SSM-S	2	2	16	S-14314PF12	12.2	3.34	1.22	<0.100	0.840	11.7	1.31
HAIG-21-Q-SSM-S	2	2	17	S-14327PF12	11.5	3.19	0.971	1.91	1.73	11.8	0.799
HAIG-20-Q-SSM-S	2	2	18	S-14326PF12	10.4	5.68	0.471	1.40	1.73	13.3	2.04
HAIG-19-Q-SSM-S	2	2	19	S-14325PF12	13.9	2.29	0.260	2.39	0.614	12.0	1.86
HAIG-18-Q-SSM-S	2	2	20	S-14324PF12	13.6	2.65	0.606	2.27	1.48	10.2	2.18
HAIG-22-Q-SSM-S	2	2	21	S-14328PF22	10.6	2.74	1.49	1.80	1.05	17.5	1.50
HAIG-18-Q-SSM-S	2	2	22	S-14324PF22	13.5	2.63	0.590	2.27	1.51	10.5	2.17
LRM	2	2	23	LRMPF223	5.15	2.29	1.19	<0.100	0.246	25.3	0.722
ARG-1	2	2	24	ARGLM223	2.45	2.48	2.26	1.42	<0.100	22.1	<0.100
LRM	3	1	1	LRMPF311	4.98	2.29	1.37	0.102	0.206	25.1	0.702
ARG-1	3	1	2	ARGLM311	2.4	2.47	2.34	1.42	0.111	21.9	<0.100

Table A-3. PF Measurements (wt.%) of the SSM Study Glasses (continued)

PNNL ID	Block	Sub – Block	Seq	Lab ID	Al	B	K	Li	P	Si	Zr
HAIG-24-Q-SSM-S	3	1	3	S-14330PF11	10.7	4.46	0.643	1.21	0.392	14.5	0.678
EWG-HAIG-SSM-S	3	1	4	S-14332PF11	3.34	3.40	0.117	2.13	0.238	20.9	1.46
HAIG-03-Q-SSM-S	3	1	5	S-14310PF21	9.93	4.49	0.561	0.36	1.30	15.2	1.41
HAIG-04-Q-SSM-S	3	1	6	S-14311PF11	10.5	3.00	1.36	0.179	0.185	15.8	0.45
HAIG-16-Q-SSM-S	3	1	7	S-14322PF11	11.1	3.06	0.647	1.21	0.820	14.7	3.62
HAIG-09-Q-SSM-S	3	1	8	S-14316PF21	10.4	6.24	0.350	2.29	0.528	10.7	3.93
HAIG-24-Q-SSM-S	3	1	9	S-14330PF21	10.7	4.43	0.603	1.20	0.378	14.5	0.703
HAIG-06-Q-SSM-S	3	1	10	S-14313PF11	13.9	5.64	0.555	0.144	0.889	11.8	0.183
LRM	3	1	11	LRMPF312	5.09	2.29	1.30	<0.100	0.267	25.2	0.744
ARG-1	3	1	12	ARGLM312	2.49	2.51	2.32	1.43	0.126	22.3	0.102
HAIG-03-Q-SSM-S	3	1	13	S-14310PF11	10.1	4.63	0.552	0.362	1.28	15.5	1.45
HAIG-25-Q-SSM-S	3	1	14	S-14331PF21	12.4	4.46	0.400	0.905	1.73	11.9	<0.100
HAIG-16-Q-SSM-S	3	1	15	S-14322PF21	11.1	3.08	0.567	1.22	0.884	14.7	3.62
HAIG-04-Q-SSM-S	3	1	16	S-14311PF21	10.5	2.96	1.42	0.137	0.181	15.8	0.453
EWG-HAIG-SSM-S	3	1	17	S-14332PF21	3.51	3.54	0.164	2.22	0.222	21.9	1.53
HAIG-09-Q-SSM-S	3	1	18	S-14316PF11	10.6	6.31	0.354	2.33	0.554	10.9	3.98
HAIG-06-Q-SSM-S	3	1	19	S-14313PF21	14.2	5.79	0.547	0.164	0.887	12.1	0.188
HAIG-25-Q-SSM-S	3	1	20	S-14331PF11	12.3	4.40	0.360	0.889	1.73	11.8	<0.100
LRM	3	1	21	LRMPF313	5.05	2.30	1.36	0.153	0.271	25.3	0.728
ARG-1	3	1	22	ARGLM313	2.46	2.5	2.41	1.42	0.122	22.2	0.101
LRM	3	2	1	LRMPF321	5.22	2.34	1.40	<0.100	0.182	25.7	0.706
ARG-1	3	2	2	ARGLM321	2.46	2.50	2.37	1.36	<0.100	22.2	<0.100
EWG-HAIG-SSM-S	3	2	3	S-14332PF12	3.47	3.46	<0.100	2.13	0.188	21.3	1.47
HAIG-06-Q-SSM-S	3	2	4	S-14313PF12	14.0	5.62	0.537	<0.100	0.859	11.7	0.147
HAIG-25-Q-SSM-S	3	2	5	S-14331PF12	12.2	4.26	0.364	0.763	1.68	11.4	<0.100
HAIG-03-Q-SSM-S	3	2	6	S-14310PF12	10.1	4.53	0.595	0.255	1.28	15.1	1.38
HAIG-24-Q-SSM-S	3	2	7	S-14330PF22	11.2	4.51	0.633	1.14	0.394	14.7	0.686
HAIG-06-Q-SSM-S	3	2	8	S-14313PF22	14	5.60	0.456	<0.100	0.856	11.7	0.156
HAIG-16-Q-SSM-S	3	2	9	S-14322PF22	11.3	3.05	0.609	0.997	0.837	14.7	3.63
HAIG-03-Q-SSM-S	3	2	10	S-14310PF22	10.2	4.55	0.494	0.238	1.24	15.2	1.41
LRM	3	2	11	LRMPF322	5.17	2.30	1.32	<0.100	0.229	25.4	0.732
ARG-1	3	2	12	ARGLM322	2.47	2.49	2.37	1.35	<0.100	22.1	<0.100
HAIG-09-Q-SSM-S	3	2	13	S-14316PF22	10.5	6.15	0.467	2.27	0.482	10.6	3.90
HAIG-24-Q-SSM-S	3	2	14	S-14330PF12	11.1	4.53	0.648	1.15	0.356	14.7	0.688
HAIG-09-Q-SSM-S	3	2	15	S-14316PF12	10.6	6.19	0.446	2.24	0.509	10.7	3.91
HAIG-25-Q-SSM-S	3	2	16	S-14331PF22	12.2	4.26	0.325	0.763	1.62	11.4	<0.100
EWG-HAIG-SSM-S	3	2	17	S-14332PF22	3.44	3.45	0.151	2.09	0.229	21.1	1.46
HAIG-04-Q-SSM-S	3	2	18	S-14311PF12	10.6	2.96	1.32	<0.100	0.13	15.6	0.420
HAIG-16-Q-SSM-S	3	2	19	S-14322PF12	11.4	3.03	0.601	0.998	0.788	14.6	3.61
HAIG-04-Q-SSM-S	3	2	20	S-14311PF22	10.8	2.99	1.41	<0.100	0.129	15.8	0.433
LRM	3	2	21	LRMPF323	5.25	2.32	1.29	<0.100	0.186	25.6	0.729
ARG-1	3	2	22	ARGLM323	2.53	2.51	2.46	1.36	<0.100	22.4	<0.100

Table A-4. Comparison of Measured and Targeted Compositions

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
ARG-1	Al ₂ O ₃	4.72	4.73	-0.013	0%
ARG-1	B ₂ O ₃	8.13	8.67	-0.543	-6%
ARG-1	Bi ₂ O ₃	<0.111	0	0.111	
ARG-1	CaO	1.44	1.43	0.008	1%
ARG-1	CdO	<0.0286	0	0.029	
ARG-1	Cr ₂ O ₃	0.0936	0.093	0.001	
ARG-1	F	<0.05	0	0.050	
ARG-1	Fe ₂ O ₃	14.1	14	0.071	1%
ARG-1	K ₂ O	2.85	2.71	0.140	5%
ARG-1	Li ₂ O	3.08	3.21	-0.130	-4%
ARG-1	MgO	0.827	0.86	-0.033	
ARG-1	MnO	1.87	1.88	-0.006	0%
ARG-1	Na ₂ O	11.7	11.5	0.239	2%
ARG-1	NiO	0.994	1.05	-0.056	-5%
ARG-1	P ₂ O ₅	<0.245	0.22	0.025	
ARG-1	SiO ₂	47.9	47.9	-0.003	0%
ARG-1	SO ₃	<0.137	0	0.137	
ARG-1	SrO	<0.0591	0.0037	0.055	
ARG-1	TiO ₂	1.12	1.15	-0.031	-3%
ARG-1	ZnO	<0.0622	0.02	0.042	
ARG-1	ZrO ₂	<0.136	0.13	0.006	
ARG-1	Sum of Oxides	99.7	99.6	0.097	0%
EWG-HAIG-SSM-S	Al ₂ O ₃	6.50	5.59	0.91	16%
EWG-HAIG-SSM-S	B ₂ O ₃	11.1	11.3	-0.151	-1%
EWG-HAIG-SSM-S	Bi ₂ O ₃	<0.111	0	0.111	
EWG-HAIG-SSM-S	CaO	2.30	2.23	0.068	3%
EWG-HAIG-SSM-S	CdO	<0.0286	0	0.029	
EWG-HAIG-SSM-S	Cr ₂ O ₃	<0.0365	0	0.037	
EWG-HAIG-SSM-S	F	<0.05	0	0.050	
EWG-HAIG-SSM-S	Fe ₂ O ₃	<0.143	0	0.143	
EWG-HAIG-SSM-S	K ₂ O	<0.16	0	0.160	
EWG-HAIG-SSM-S	Li ₂ O	4.61	5.08	-0.467	-9%
EWG-HAIG-SSM-S	MgO	<0.0829	0	0.083	
EWG-HAIG-SSM-S	MnO	<0.0129	0	0.013	
EWG-HAIG-SSM-S	Na ₂ O	10.0	9.67	0.379	4%
EWG-HAIG-SSM-S	NiO	<0.127	0	0.127	
EWG-HAIG-SSM-S	P ₂ O ₅	0.502	0.65	-0.148	
EWG-HAIG-SSM-S	SiO ₂	45.6	46.5	-0.933	-2%
EWG-HAIG-SSM-S	SO ₃	<0.13	0	0.130	
EWG-HAIG-SSM-S	SrO	0.460	0.45	0.010	
EWG-HAIG-SSM-S	TiO ₂	3.42	3.21	0.214	7%
EWG-HAIG-SSM-S	ZnO	1.52	1.46	0.059	4%
EWG-HAIG-SSM-S	ZrO ₂	2.00	1.8	0.199	11%
EWG-HAIG-SSM-S	Sum of Oxides	89.0	87.9	1.023	1%
HAIG-01-Q-SSM-S	Al ₂ O ₃	20.5	20.2	0.254	1%
HAIG-01-Q-SSM-S	B ₂ O ₃	9.32	9.5	-0.178	-2%
HAIG-01-Q-SSM-S	Bi ₂ O ₃	0.723	0.714	0.009	

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-01-Q-SSM-S	CaO	1.45	1.43	0.018	1%
HAIG-01-Q-SSM-S	CdO	0.132	0.143	-0.011	
HAIG-01-Q-SSM-S	Cr ₂ O ₃	<0.0365	0.019	0.018	
HAIG-01-Q-SSM-S	F	0.554	0.82	-0.266	
HAIG-01-Q-SSM-S	Fe ₂ O ₃	1.37	1.36	0.009	1%
HAIG-01-Q-SSM-S	K ₂ O	2.06	2.1	-0.037	-2%
HAIG-01-Q-SSM-S	Li ₂ O	0.435	0.495	-0.060	
HAIG-01-Q-SSM-S	MgO	0.713	0.714	-0.001	
HAIG-01-Q-SSM-S	MnO	0.0900	0.087	0.003	
HAIG-01-Q-SSM-S	Na ₂ O	20.2	20	0.186	1%
HAIG-01-Q-SSM-S	NiO	1.12	1.14	-0.023	-2%
HAIG-01-Q-SSM-S	P ₂ O ₅	3.61	4.21	-0.601	-14%
HAIG-01-Q-SSM-S	SiO ₂	33.2	31.5	1.713	5%
HAIG-01-Q-SSM-S	SO ₃	0.830	0.486	0.344	
HAIG-01-Q-SSM-S	SrO	0.127	0.147	-0.020	
HAIG-01-Q-SSM-S	TiO ₂	0.296	0.286	0.010	
HAIG-01-Q-SSM-S	ZnO	0.249	0.241	0.008	
HAIG-01-Q-SSM-S	ZrO ₂	4.30	4.41	-0.111	-3%
HAIG-01-Q-SSM-S	Sum of Oxides	101	100	1.264	1%
HAIG-02-Q-SSM-S	Al ₂ O ₃	23.6	23.9	-0.281	-1%
HAIG-02-Q-SSM-S	B ₂ O ₃	19.2	19.7	-0.542	-3%
HAIG-02-Q-SSM-S	Bi ₂ O ₃	0.134	0.143	-0.009	
HAIG-02-Q-SSM-S	CaO	0.290	0.286	0.004	
HAIG-02-Q-SSM-S	CdO	<0.0286	0.029	0	
HAIG-02-Q-SSM-S	Cr ₂ O ₃	1.13	1.6	-0.468	-29%
HAIG-02-Q-SSM-S	F	0.0913	0.164	-0.073	
HAIG-02-Q-SSM-S	Fe ₂ O ₃	4.57	4.78	-0.212	-4%
HAIG-02-Q-SSM-S	K ₂ O	0.494	0.42	0.074	
HAIG-02-Q-SSM-S	Li ₂ O	0.923	1.07	-0.147	-14%
HAIG-02-Q-SSM-S	MgO	0.148	0.143	0.005	
HAIG-02-Q-SSM-S	MnO	0.0250	0.017	0.008	
HAIG-02-Q-SSM-S	Na ₂ O	20.1	19.2	0.852	4%
HAIG-02-Q-SSM-S	NiO	0.218	0.229	-0.011	
HAIG-02-Q-SSM-S	P ₂ O ₅	3.42	3.71	-0.290	-8%
HAIG-02-Q-SSM-S	SiO ₂	23.3	22.3	0.965	4%
HAIG-02-Q-SSM-S	SO ₃	0.965	0.097	0.868	
HAIG-02-Q-SSM-S	SrO	<0.0591	0.029	0.030	
HAIG-02-Q-SSM-S	TiO ₂	<0.0901	0.057	0.033	
HAIG-02-Q-SSM-S	ZnO	<0.0622	0.048	0.014	
HAIG-02-Q-SSM-S	ZrO ₂	1.96	2.07	-0.108	-5%
HAIG-02-Q-SSM-S	Sum of Oxides	101	100	0.712	1%
HAIG-03-Q-SSM-S	Al ₂ O ₃	19.1	20.1	-1.049	-5%
HAIG-03-Q-SSM-S	B ₂ O ₃	14.7	15.7	-1.049	-7%
HAIG-03-Q-SSM-S	Bi ₂ O ₃	0.200	0.213	-0.013	
HAIG-03-Q-SSM-S	CaO	0.412	0.426	-0.014	
HAIG-03-Q-SSM-S	CdO	0.0378	0.043	-0.005	
HAIG-03-Q-SSM-S	Cr ₂ O ₃	0.135	0.172	-0.037	
HAIG-03-Q-SSM-S	F	0.128	0.244	-0.116	

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-03-Q-SSM-S	Fe ₂ O ₃	5.48	5.69	-0.207	-4%
HAIG-03-Q-SSM-S	K ₂ O	0.663	0.625	0.038	
HAIG-03-Q-SSM-S	Li ₂ O	0.654	0.93	-0.276	
HAIG-03-Q-SSM-S	MgO	0.214	0.213	0.001	
HAIG-03-Q-SSM-S	MnO	0.0349	0.026	0.009	
HAIG-03-Q-SSM-S	Na ₂ O	17.5	16.7	0.790	5%
HAIG-03-Q-SSM-S	NiO	0.320	0.341	-0.021	
HAIG-03-Q-SSM-S	P ₂ O ₅	2.92	3.37	-0.448	-13%
HAIG-03-Q-SSM-S	SiO ₂	32.6	32.8	-0.176	-1%
HAIG-03-Q-SSM-S	SO ₃	0.813	0.145	0.668	
HAIG-03-Q-SSM-S	SrO	<0.0591	0.044	0.015	
HAIG-03-Q-SSM-S	TiO ₂	0.104	0.085	0.019	
HAIG-03-Q-SSM-S	ZnO	0.072	0.072	0	
HAIG-03-Q-SSM-S	ZrO ₂	1.91	2.02	-0.112	-6%
HAIG-03-Q-SSM-S	Sum of Oxides	98.0	100	-1.982	-2%
HAIG-04-Q-SSM-S	Al ₂ O ₃	20.0	20.7	-0.671	-3%
HAIG-04-Q-SSM-S	B ₂ O ₃	9.59	10.2	-0.613	-6%
HAIG-04-Q-SSM-S	Bi ₂ O ₃	0.599	0.621	-0.022	
HAIG-04-Q-SSM-S	CaO	1.21	1.24	-0.031	-3%
HAIG-04-Q-SSM-S	CdO	0.113	0.124	-0.011	
HAIG-04-Q-SSM-S	Cr ₂ O ₃	0.782	1.13	-0.348	-31%
HAIG-04-Q-SSM-S	F	0.472	0.713	-0.241	
HAIG-04-Q-SSM-S	Fe ₂ O ₃	6.86	6.89	-0.031	0%
HAIG-04-Q-SSM-S	K ₂ O	1.66	1.82	-0.161	-9%
HAIG-04-Q-SSM-S	Li ₂ O	<0.278	0.382	-0.104	
HAIG-04-Q-SSM-S	MgO	0.610	0.621	-0.011	
HAIG-04-Q-SSM-S	MnO	0.0853	0.076	0.009	
HAIG-04-Q-SSM-S	Na ₂ O	19.1	19.5	-0.358	-2%
HAIG-04-Q-SSM-S	NiO	0.955	0.993	-0.038	
HAIG-04-Q-SSM-S	P ₂ O ₅	0.358	0.371	-0.013	
HAIG-04-Q-SSM-S	SiO ₂	33.7	33	0.694	2%
HAIG-04-Q-SSM-S	SO ₃	0.663	0.422	0.241	
HAIG-04-Q-SSM-S	SrO	0.105	0.128	-0.023	
HAIG-04-Q-SSM-S	TiO ₂	0.281	0.248	0.033	
HAIG-04-Q-SSM-S	ZnO	0.208	0.21	-0.002	
HAIG-04-Q-SSM-S	ZrO ₂	0.593	0.604	-0.011	
HAIG-04-Q-SSM-S	Sum of Oxides	98.3	100	-1.712	-2%
HAIG-05-Q-SSM-S	Al ₂ O ₃	19.2	20	-0.751	-4%
HAIG-05-Q-SSM-S	B ₂ O ₃	19.9	21.2	-1.325	-6%
HAIG-05-Q-SSM-S	Bi ₂ O ₃	0.386	0.428	-0.042	
HAIG-05-Q-SSM-S	CaO	0.819	0.856	-0.037	
HAIG-05-Q-SSM-S	CdO	0.0779	0.086	-0.008	
HAIG-05-Q-SSM-S	Cr ₂ O ₃	0.573	0.662	-0.089	
HAIG-05-Q-SSM-S	F	0.274	0.491	-0.218	
HAIG-05-Q-SSM-S	Fe ₂ O ₃	10.7	11.1	-0.381	-3%
HAIG-05-Q-SSM-S	K ₂ O	1.20	1.26	-0.058	-5%
HAIG-05-Q-SSM-S	Li ₂ O	0.350	0.452	-0.102	
HAIG-05-Q-SSM-S	MgO	0.417	0.428	-0.011	

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-05-Q-SSM-S	MnO	0.0676	0.052	0.016	
HAIG-05-Q-SSM-S	Na ₂ O	17.1	15.7	1.420	9%
HAIG-05-Q-SSM-S	NiO	0.627	0.685	-0.058	
HAIG-05-Q-SSM-S	P ₂ O ₅	0.754	0.78	-0.026	
HAIG-05-Q-SSM-S	SiO ₂	21.9	22	-0.072	0%
HAIG-05-Q-SSM-S	SO ₃	0.800	0.291	0.509	
HAIG-05-Q-SSM-S	SrO	0.0698	0.088	-0.018	
HAIG-05-Q-SSM-S	TiO ₂	0.203	0.171	0.032	
HAIG-05-Q-SSM-S	ZnO	0.141	0.145	-0.004	
HAIG-05-Q-SSM-S	ZrO ₂	2.93	3.06	-0.132	-4%
HAIG-05-Q-SSM-S	Sum of Oxides	98.6	99.9	-1.354	-1%
HAIG-06-Q-SSM-S	Al ₂ O ₃	26.5	27.9	-1.400	-5%
HAIG-06-Q-SSM-S	B ₂ O ₃	18.2	19.6	-1.367	-7%
HAIG-06-Q-SSM-S	Bi ₂ O ₃	0.176	0.182	-0.006	
HAIG-06-Q-SSM-S	CaO	0.363	0.365	-0.002	
HAIG-06-Q-SSM-S	CdO	0.0318	0.036	-0.004	
HAIG-06-Q-SSM-S	Cr ₂ O ₃	1.01	1.19	-0.177	-15%
HAIG-06-Q-SSM-S	F	0.115	0.209	-0.094	
HAIG-06-Q-SSM-S	Fe ₂ O ₃	1.45	1.47	-0.015	-1%
HAIG-06-Q-SSM-S	K ₂ O	0.631	0.536	0.095	
HAIG-06-Q-SSM-S	Li ₂ O	<0.273	0.322	-0.049	
HAIG-06-Q-SSM-S	MgO	0.187	0.182	0.005	
HAIG-06-Q-SSM-S	MnO	0.0238	0.022	0.002	
HAIG-06-Q-SSM-S	Na ₂ O	20.6	19.7	0.891	5%
HAIG-06-Q-SSM-S	NiO	0.275	0.292	-0.017	
HAIG-06-Q-SSM-S	P ₂ O ₅	2.00	2.32	-0.320	-14%
HAIG-06-Q-SSM-S	SiO ₂	25.3	25.2	0.097	0%
HAIG-06-Q-SSM-S	SO ₃	0.798	0.124	0.674	
HAIG-06-Q-SSM-S	SrO	<0.0591	0.038	0.021	
HAIG-06-Q-SSM-S	TiO ₂	0.123	0.073	0.050	
HAIG-06-Q-SSM-S	ZnO	<0.0629	0.062	0.001	
HAIG-06-Q-SSM-S	ZrO ₂	0.228	0.247	-0.019	
HAIG-06-Q-SSM-S	Sum of Oxides	98.4	100	-1.634	-2%
HAIG-07-1-Q-SSM-S	Al ₂ O ₃	23.4	23.7	-0.270	-1%
HAIG-07-1-Q-SSM-S	B ₂ O ₃	10.9	11.3	-0.401	-4%
HAIG-07-1-Q-SSM-S	Bi ₂ O ₃	0.579	0.597	-0.018	
HAIG-07-1-Q-SSM-S	CaO	1.18	1.19	-0.010	-1%
HAIG-07-1-Q-SSM-S	CdO	0.107	0.119	-0.012	
HAIG-07-1-Q-SSM-S	Cr ₂ O ₃	0.0441	0.074	-0.030	
HAIG-07-1-Q-SSM-S	F	0.441	0.685	-0.245	
HAIG-07-1-Q-SSM-S	Fe ₂ O ₃	9.21	9.08	0.134	1%
HAIG-07-1-Q-SSM-S	K ₂ O	1.54	1.75	-0.214	-12%
HAIG-07-1-Q-SSM-S	Li ₂ O	<0.215	0.175	0.040	
HAIG-07-1-Q-SSM-S	MgO	0.600	0.597	0.003	
HAIG-07-1-Q-SSM-S	MnO	0.0883	0.073	0.015	
HAIG-07-1-Q-SSM-S	Na ₂ O	20.7	19.8	0.925	5%
HAIG-07-1-Q-SSM-S	NiO	0.886	0.954	-0.068	
HAIG-07-1-Q-SSM-S	P ₂ O ₅	1.88	2.1	-0.218	-10%

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-07-1-Q-SSM-S	SiO ₂	25.6	24.8	0.818	3%
HAIG-07-1-Q-SSM-S	SO ₃	0.612	0.406	0.206	
HAIG-07-1-Q-SSM-S	SrO	0.103	0.123	-0.020	
HAIG-07-1-Q-SSM-S	TiO ₂	0.264	0.239	0.025	
HAIG-07-1-Q-SSM-S	ZnO	0.203	0.202	0.001	
HAIG-07-1-Q-SSM-S	ZrO ₂	1.86	1.9	-0.036	-2%
HAIG-07-1-Q-SSM-S	Sum of Oxides	100	99.9	0.628	1%
HAIG-08-Q-SSM-S	Al ₂ O ₃	23.3	24.3	-0.965	-4%
HAIG-08-Q-SSM-S	B ₂ O ₃	13.9	14.8	-0.922	-6%
HAIG-08-Q-SSM-S	Bi ₂ O ₃	<0.111	0.096	0.015	
HAIG-08-Q-SSM-S	CaO	0.199	0.192	0.007	
HAIG-08-Q-SSM-S	CdO	<0.0286	0.019	0.010	
HAIG-08-Q-SSM-S	Cr ₂ O ₃	0.536	0.649	-0.113	
HAIG-08-Q-SSM-S	F	0.0646	0.11	-0.045	
HAIG-08-Q-SSM-S	Fe ₂ O ₃	10.6	10.7	-0.070	-1%
HAIG-08-Q-SSM-S	K ₂ O	0.345	0.283	0.062	
HAIG-08-Q-SSM-S	Li ₂ O	1.85	1.8	0.047	3%
HAIG-08-Q-SSM-S	MgO	0.104	0.096	0.008	
HAIG-08-Q-SSM-S	MnO	0.0303	0.012	0.018	
HAIG-08-Q-SSM-S	Na ₂ O	19.3	17.5	1.844	11%
HAIG-08-Q-SSM-S	NiO	0.147	0.154	-0.007	
HAIG-08-Q-SSM-S	P ₂ O ₅	3.88	4.36	-0.476	-11%
HAIG-08-Q-SSM-S	SiO ₂	24.6	24.8	-0.198	-1%
HAIG-08-Q-SSM-S	SO ₃	0.845	0.065	0.780	
HAIG-08-Q-SSM-S	SrO	<0.0591	0.02	0.039	
HAIG-08-Q-SSM-S	TiO ₂	0.0848	0.038	0.047	
HAIG-08-Q-SSM-S	ZnO	<0.0622	0.033	0.029	
HAIG-08-Q-SSM-S	ZrO ₂	<0.135	0.041	0.094	
HAIG-08-Q-SSM-S	Sum of Oxides	100	100	0.204	0%
HAIG-09-Q-SSM-S	Al ₂ O ₃	19.9	21.1	-1.213	-6%
HAIG-09-Q-SSM-S	B ₂ O ₃	20.0	21.8	-1.764	-8%
HAIG-09-Q-SSM-S	Bi ₂ O ₃	0.133	0.156	-0.023	
HAIG-09-Q-SSM-S	CaO	0.307	0.312	-0.005	
HAIG-09-Q-SSM-S	CdO	<0.0286	0.031	-0.002	
HAIG-09-Q-SSM-S	Cr ₂ O ₃	0.704	1.06	-0.356	-34%
HAIG-09-Q-SSM-S	F	0.0977	0.179	-0.081	
HAIG-09-Q-SSM-S	Fe ₂ O ₃	4.68	4.81	-0.128	-3%
HAIG-09-Q-SSM-S	K ₂ O	0.487	0.459	0.028	
HAIG-09-Q-SSM-S	Li ₂ O	4.91	5.62	-0.706	-13%
HAIG-09-Q-SSM-S	MgO	0.156	0.156	0	
HAIG-09-Q-SSM-S	MnO	0.0263	0.019	0.007	
HAIG-09-Q-SSM-S	Na ₂ O	14.6	13.6	1.026	8%
HAIG-09-Q-SSM-S	NiO	0.226	0.25	-0.024	
HAIG-09-Q-SSM-S	P ₂ O ₅	1.19	1.36	-0.172	-13%
HAIG-09-Q-SSM-S	SiO ₂	22.9	23.2	-0.256	-1%
HAIG-09-Q-SSM-S	SO ₃	1.23	0.106	1.126	1062%
HAIG-09-Q-SSM-S	SrO	<0.0591	0.032	0.027	
HAIG-09-Q-SSM-S	TiO ₂	0.106	0.062	0.044	

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-09-Q-SSM-S	ZnO	<0.0622	0.053	0.009	
HAIG-09-Q-SSM-S	ZrO ₂	5.31	5.6	-0.291	-5%
HAIG-09-Q-SSM-S	Sum of Oxides	97.2	100	-2.755	-3%
HAIG-11-Q-SSM-S	Al ₂ O ₃	25.5	24.5	1.008	4%
HAIG-11-Q-SSM-S	B ₂ O ₃	7.78	8.84	-1.064	-12%
HAIG-11-Q-SSM-S	Bi ₂ O ₃	0.310	0.316	-0.006	
HAIG-11-Q-SSM-S	CaO	0.650	0.631	0.019	
HAIG-11-Q-SSM-S	CdO	0.0545	0.063	-0.009	
HAIG-11-Q-SSM-S	Cr ₂ O ₃	0.380	1.81	-1.430	-79%
HAIG-11-Q-SSM-S	F	0.196	0.362	-0.166	
HAIG-11-Q-SSM-S	Fe ₂ O ₃	1.79	1.73	0.064	4%
HAIG-11-Q-SSM-S	K ₂ O	0.840	0.927	-0.087	
HAIG-11-Q-SSM-S	Li ₂ O	4.38	4.59	-0.209	-5%
HAIG-11-Q-SSM-S	MgO	0.332	0.316	0.016	
HAIG-11-Q-SSM-S	MnO	0.0420	0.039	0.003	
HAIG-11-Q-SSM-S	Na ₂ O	18.8	19.9	-1.095	-6%
HAIG-11-Q-SSM-S	NiO	0.497	0.505	-0.008	
HAIG-11-Q-SSM-S	P ₂ O ₅	3.33	3.7	-0.372	-10%
HAIG-11-Q-SSM-S	SiO ₂	28.0	25.8	2.225	9%
HAIG-11-Q-SSM-S	SO ₃	0.564	0.215	0.349	
HAIG-11-Q-SSM-S	SrO	<0.0591	0.065	-0.006	
HAIG-11-Q-SSM-S	TiO ₂	0.174	0.126	0.048	
HAIG-11-Q-SSM-S	ZnO	0.110	0.107	0.003	
HAIG-11-Q-SSM-S	ZrO ₂	5.50	5.43	0.075	1%
HAIG-11-Q-SSM-S	Sum of Oxides	99.3	100	-0.640	-1%
HAIG-12-Q-SSM-S	Al ₂ O ₃	21.4	21.1	0.299	1%
HAIG-12-Q-SSM-S	B ₂ O ₃	15.9	16.1	-0.194	-1%
HAIG-12-Q-SSM-S	Bi ₂ O ₃	0.441	0.455	-0.014	
HAIG-12-Q-SSM-S	CaO	0.902	0.91	-0.008	
HAIG-12-Q-SSM-S	CdO	0.0816	0.091	-0.009	
HAIG-12-Q-SSM-S	Cr ₂ O ₃	1.04	1.65	-0.605	-37%
HAIG-12-Q-SSM-S	F	0.299	0.522	-0.224	
HAIG-12-Q-SSM-S	Fe ₂ O ₃	0.217	0.17	0.047	
HAIG-12-Q-SSM-S	K ₂ O	1.31	1.34	-0.028	-2%
HAIG-12-Q-SSM-S	Li ₂ O	0.623	0.713	-0.090	
HAIG-12-Q-SSM-S	MgO	0.463	0.455	0.008	
HAIG-12-Q-SSM-S	MnO	0.0671	0.056	0.011	
HAIG-12-Q-SSM-S	Na ₂ O	19.9	19.4	0.517	3%
HAIG-12-Q-SSM-S	NiO	0.701	0.728	-0.027	
HAIG-12-Q-SSM-S	P ₂ O ₅	1.02	1.06	-0.040	-4%
HAIG-12-Q-SSM-S	SiO ₂	30.2	28.6	1.618	6%
HAIG-12-Q-SSM-S	SO ₃	0.760	0.309	0.451	
HAIG-12-Q-SSM-S	SrO	0.0770	0.094	-0.017	
HAIG-12-Q-SSM-S	TiO ₂	0.229	0.182	0.047	
HAIG-12-Q-SSM-S	ZnO	0.153	0.154	-0.001	
HAIG-12-Q-SSM-S	ZrO ₂	5.88	5.96	-0.081	-1%
HAIG-12-Q-SSM-S	Sum of Oxides	102	100	1.660	2%
HAIG-13-Q-SSM-S	Al ₂ O ₃	20.0	20.4	-0.419	-2%

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-13-Q-SSM-S	B ₂ O ₃	7.78	8.24	-0.456	-6%
HAIG-13-Q-SSM-S	Bi ₂ O ₃	0.524	0.574	-0.050	
HAIG-13-Q-SSM-S	CaO	1.11	1.15	-0.036	-3%
HAIG-13-Q-SSM-S	CdO	0.0976	0.115	-0.017	
HAIG-13-Q-SSM-S	Cr ₂ O ₃	0.0824	0.254	-0.172	
HAIG-13-Q-SSM-S	F	0.459	0.659	-0.200	
HAIG-13-Q-SSM-S	Fe ₂ O ₃	8.45	8.61	-0.164	-2%
HAIG-13-Q-SSM-S	K ₂ O	1.33	1.69	-0.359	-21%
HAIG-13-Q-SSM-S	Li ₂ O	4.49	4.81	-0.316	-7%
HAIG-13-Q-SSM-S	MgO	0.554	0.574	-0.020	
HAIG-13-Q-SSM-S	MnO	0.0813	0.07	0.011	
HAIG-13-Q-SSM-S	Na ₂ O	16.9	16.8	0.117	1%
HAIG-13-Q-SSM-S	NiO	0.852	0.919	-0.067	
HAIG-13-Q-SSM-S	P ₂ O ₅	0.605	0.644	-0.039	
HAIG-13-Q-SSM-S	SiO ₂	28.6	28.1	0.513	2%
HAIG-13-Q-SSM-S	SO ₃	0.963	0.39	0.573	
HAIG-13-Q-SSM-S	SrO	0.0973	0.118	-0.021	
HAIG-13-Q-SSM-S	TiO ₂	0.266	0.23	0.036	
HAIG-13-Q-SSM-S	ZnO	0.191	0.194	-0.003	
HAIG-13-Q-SSM-S	ZrO ₂	5.29	5.37	-0.078	-1%
HAIG-13-Q-SSM-S	Sum of Oxides	98.7	99.9	-1.165	-1%
HAIG-14-Q-SSM-S	Al ₂ O ₃	22.8	22.9	-0.132	-1%
HAIG-14-Q-SSM-S	B ₂ O ₃	16.3	16.8	-0.507	-3%
HAIG-14-Q-SSM-S	Bi ₂ O ₃	<0.111	0.087	0.024	
HAIG-14-Q-SSM-S	CaO	0.186	0.173	0.013	
HAIG-14-Q-SSM-S	CdO	<0.0286	0.017	0.012	
HAIG-14-Q-SSM-S	Cr ₂ O ₃	0.922	1.76	-0.838	-48%
HAIG-14-Q-SSM-S	F	0.0623	0.1	-0.038	
HAIG-14-Q-SSM-S	Fe ₂ O ₃	9.99	9.98	0.014	0%
HAIG-14-Q-SSM-S	K ₂ O	0.350	0.255	0.095	
HAIG-14-Q-SSM-S	Li ₂ O	5.03	5.34	-0.313	-6%
HAIG-14-Q-SSM-S	MgO	0.0984	0.087	0.011	
HAIG-14-Q-SSM-S	MnO	0.0282	0.011	0.017	
HAIG-14-Q-SSM-S	Na ₂ O	19.2	18.6	0.575	3%
HAIG-14-Q-SSM-S	NiO	0.134	0.139	-0.005	
HAIG-14-Q-SSM-S	P ₂ O ₅	0.674	0.795	-0.121	
HAIG-14-Q-SSM-S	SiO ₂	23.3	22.2	1.065	5%
HAIG-14-Q-SSM-S	SO ₃	0.978	0.059	0.919	
HAIG-14-Q-SSM-S	SrO	<0.0591	0.018	0.041	
HAIG-14-Q-SSM-S	TiO ₂	<0.0834	0.035	0.048	
HAIG-14-Q-SSM-S	ZnO	<0.0622	0.029	0.033	
HAIG-14-Q-SSM-S	ZrO ₂	0.597	0.614	-0.017	
HAIG-14-Q-SSM-S	Sum of Oxides	101	100	0.897	1%
HAIG-15-Q-SSM-S	Al ₂ O ₃	22.6	22.4	0.180	1%
HAIG-15-Q-SSM-S	B ₂ O ₃	8.48	8.65	-0.174	-2%
HAIG-15-Q-SSM-S	Bi ₂ O ₃	0.280	0.297	-0.017	
HAIG-15-Q-SSM-S	CaO	0.586	0.595	-0.009	

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-15-Q-SSM-S	CdO	0.0517	0.059	-0.007	
HAIG-15-Q-SSM-S	Cr ₂ O ₃	1.39	1.95	-0.557	-29%
HAIG-15-Q-SSM-S	F	0.217	0.341	-0.124	
HAIG-15-Q-SSM-S	Fe ₂ O ₃	1.26	1.29	-0.030	-2%
HAIG-15-Q-SSM-S	K ₂ O	0.892	0.874	0.018	
HAIG-15-Q-SSM-S	Li ₂ O	5.63	5.93	-0.300	-5%
HAIG-15-Q-SSM-S	MgO	0.298	0.297	0.001	
HAIG-15-Q-SSM-S	MnO	0.0370	0.036	0.001	
HAIG-15-Q-SSM-S	Na ₂ O	15.4	14.9	0.467	3%
HAIG-15-Q-SSM-S	NiO	0.450	0.476	-0.026	
HAIG-15-Q-SSM-S	P ₂ O ₅	0.253	0.176	0.077	
HAIG-15-Q-SSM-S	SiO ₂	42.0	40.1	1.937	5%
HAIG-15-Q-SSM-S	SO ₃	0.933	0.202	0.731	
HAIG-15-Q-SSM-S	SrO	<0.0591	0.061	-0.002	
HAIG-15-Q-SSM-S	TiO ₂	0.160	0.119	0.041	
HAIG-15-Q-SSM-S	ZnO	0.101	0.101	0	
HAIG-15-Q-SSM-S	ZrO ₂	1.08	1.1	-0.023	-2%
HAIG-15-Q-SSM-S	Sum of Oxides	102	100	2.184	2%
HAIG-16-Q-SSM-S	Al ₂ O ₃	21.2	21.6	-0.390	-2%
HAIG-16-Q-SSM-S	B ₂ O ₃	9.84	10.4	-0.563	-5%
HAIG-16-Q-SSM-S	Bi ₂ O ₃	0.217	0.223	-0.006	
HAIG-16-Q-SSM-S	CaO	0.451	0.445	0.006	
HAIG-16-Q-SSM-S	CdO	0.0378	0.045	-0.007	
HAIG-16-Q-SSM-S	Cr ₂ O ₃	1.08	2	-0.920	-46%
HAIG-16-Q-SSM-S	F	0.156	0.256	-0.101	
HAIG-16-Q-SSM-S	Fe ₂ O ₃	4.21	4.21	-0.003	0%
HAIG-16-Q-SSM-S	K ₂ O	0.730	0.654	0.076	
HAIG-16-Q-SSM-S	Li ₂ O	2.38	2.54	-0.158	-6%
HAIG-16-Q-SSM-S	MgO	0.234	0.223	0.011	
HAIG-16-Q-SSM-S	MnO	0.0342	0.027	0.007	
HAIG-16-Q-SSM-S	Na ₂ O	19.2	19	0.175	1%
HAIG-16-Q-SSM-S	NiO	0.338	0.356	-0.018	
HAIG-16-Q-SSM-S	P ₂ O ₅	1.91	2.21	-0.303	-14%
HAIG-16-Q-SSM-S	SiO ₂	31.4	30.5	0.894	3%
HAIG-16-Q-SSM-S	SO ₃	0.712	0.151	0.561	
HAIG-16-Q-SSM-S	SrO	<0.0591	0.046	0.013	
HAIG-16-Q-SSM-S	TiO ₂	0.139	0.089	0.050	
HAIG-16-Q-SSM-S	ZnO	0.0765	0.075	0.001	
HAIG-16-Q-SSM-S	ZrO ₂	4.89	4.93	-0.040	-1%
HAIG-16-Q-SSM-S	Sum of Oxides	99.3	100	-0.714	-1%
HAIG-17-Q-SSM-S	Al ₂ O ₃	20.7	20.6	0.090	0%
HAIG-17-Q-SSM-S	B ₂ O ₃	12.7	13.1	-0.381	-3%
HAIG-17-Q-SSM-S	Bi ₂ O ₃	0.293	0.305	-0.012	
HAIG-17-Q-SSM-S	CaO	0.604	0.61	-0.006	
HAIG-17-Q-SSM-S	CdO	0.0553	0.061	-0.006	
HAIG-17-Q-SSM-S	Cr ₂ O ₃	0.089	0.132	-0.043	
HAIG-17-Q-SSM-S	F	0.216	0.35	-0.134	
HAIG-17-Q-SSM-S	Fe ₂ O ₃	0.763	0.763	0	

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-17-Q-SSM-S	K ₂ O	0.974	0.896	0.078	
HAIG-17-Q-SSM-S	Li ₂ O	2.41	2.63	-0.224	-9%
HAIG-17-Q-SSM-S	MgO	0.316	0.305	0.011	
HAIG-17-Q-SSM-S	MnO	0.0401	0.037	0.003	
HAIG-17-Q-SSM-S	Na ₂ O	18.7	17.5	1.204	7%
HAIG-17-Q-SSM-S	NiO	0.468	0.488	-0.020	
HAIG-17-Q-SSM-S	P ₂ O ₅	0.957	1.05	-0.093	-9%
HAIG-17-Q-SSM-S	SiO ₂	37.8	36.5	1.259	3%
HAIG-17-Q-SSM-S	SO ₃	0.886	0.207	0.679	
HAIG-17-Q-SSM-S	SrO	<0.0591	0.063	-0.004	
HAIG-17-Q-SSM-S	TiO ₂	0.168	0.122	0.046	
HAIG-17-Q-SSM-S	ZnO	0.103	0.103	0	
HAIG-17-Q-SSM-S	ZrO ₂	4.12	4.13	-0.007	0%
HAIG-17-Q-SSM-S	Sum of Oxides	102	100	2.439	2%
HAIG-18-Q-SSM-S	Al ₂ O ₃	26.1	28.6	-2.478	-9%
HAIG-18-Q-SSM-S	B ₂ O ₃	8.62	11.2	-2.579	-23%
HAIG-18-Q-SSM-S	Bi ₂ O ₃	0.332	0.366	-0.034	
HAIG-18-Q-SSM-S	CaO	0.687	0.732	-0.045	
HAIG-18-Q-SSM-S	CdO	0.0605	0.073	-0.012	
HAIG-18-Q-SSM-S	Cr ₂ O ₃	0.260	0.745	-0.485	
HAIG-18-Q-SSM-S	F	0.224	0.42	-0.196	
HAIG-18-Q-SSM-S	Fe ₂ O ₃	0.484	0.518	-0.034	
HAIG-18-Q-SSM-S	K ₂ O	0.775	1.08	-0.305	-28%
HAIG-18-Q-SSM-S	Li ₂ O	5.02	5.87	-0.848	-14%
HAIG-18-Q-SSM-S	MgO	0.345	0.366	-0.021	
HAIG-18-Q-SSM-S	MnO	0.042	0.045	-0.003	
HAIG-18-Q-SSM-S	Na ₂ O	16.6	18.7	-2.120	-11%
HAIG-18-Q-SSM-S	NiO	0.526	0.586	-0.060	
HAIG-18-Q-SSM-S	P ₂ O ₅	3.45	3.97	-0.516	-13%
HAIG-18-Q-SSM-S	SiO ₂	22.6	22.9	-0.330	-1%
HAIG-18-Q-SSM-S	SO ₃	0.913	0.249	0.664	
HAIG-18-Q-SSM-S	SrO	0.0596	0.075	-0.015	
HAIG-18-Q-SSM-S	TiO ₂	0.159	0.146	0.013	
HAIG-18-Q-SSM-S	ZnO	0.118	0.124	-0.006	
HAIG-18-Q-SSM-S	ZrO ₂	3.06	3.31	-0.247	-7%
HAIG-18-Q-SSM-S	Sum of Oxides	90.4	100	-9.659	-10%
HAIG-19-Q-SSM-S	Al ₂ O ₃	26.6	27.6	-1.005	-4%
HAIG-19-Q-SSM-S	B ₂ O ₃	7.49	8.02	-0.526	-7%
HAIG-19-Q-SSM-S	Bi ₂ O ₃	0.121	0.136	-0.015	
HAIG-19-Q-SSM-S	CaO	0.275	0.271	0.004	
HAIG-19-Q-SSM-S	CdO	<0.0286	0.027	0.002	
HAIG-19-Q-SSM-S	Cr ₂ O ₃	0.292	0.846	-0.554	
HAIG-19-Q-SSM-S	F	0.102	0.156	-0.054	
HAIG-19-Q-SSM-S	Fe ₂ O ₃	6.04	6.14	-0.103	-2%
HAIG-19-Q-SSM-S	K ₂ O	0.358	0.398	-0.040	
HAIG-19-Q-SSM-S	Li ₂ O	5.16	5.5	-0.338	-6%
HAIG-19-Q-SSM-S	MgO	0.141	0.136	0.005	
HAIG-19-Q-SSM-S	MnO	0.0266	0.017	0.010	

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-19-Q-SSM-S	Na ₂ O	19.5	19.8	-0.288	-1%
HAIG-19-Q-SSM-S	NiO	0.202	0.217	-0.015	
HAIG-19-Q-SSM-S	P ₂ O ₅	1.38	1.69	-0.305	-18%
HAIG-19-Q-SSM-S	SiO ₂	26.2	26.1	0.053	0%
HAIG-19-Q-SSM-S	SO ₃	0.874	0.092	0.782	
HAIG-19-Q-SSM-S	SrO	<0.0591	0.028	0.031	
HAIG-19-Q-SSM-S	TiO ₂	0.107	0.054	0.053	
HAIG-19-Q-SSM-S	ZnO	<0.0622	0.046	0.016	
HAIG-19-Q-SSM-S	ZrO ₂	2.61	2.69	-0.083	-3%
HAIG-19-Q-SSM-S	Sum of Oxides	97.6	100	-2.373	-2%
HAIG-20-Q-SSM-S	Al ₂ O ₃	20.0	20.9	-0.871	-4%
HAIG-20-Q-SSM-S	B ₂ O ₃	18.8	20	-1.244	-6%
HAIG-20-Q-SSM-S	Bi ₂ O ₃	0.197	0.217	-0.020	
HAIG-20-Q-SSM-S	CaO	0.417	0.434	-0.017	
HAIG-20-Q-SSM-S	CdO	0.0386	0.043	-0.004	
HAIG-20-Q-SSM-S	Cr ₂ O ₃	1.11	1.27	-0.160	-13%
HAIG-20-Q-SSM-S	F	0.146	0.249	-0.103	
HAIG-20-Q-SSM-S	Fe ₂ O ₃	0.725	0.735	-0.010	
HAIG-20-Q-SSM-S	K ₂ O	0.615	0.638	-0.023	
HAIG-20-Q-SSM-S	Li ₂ O	3.12	3.53	-0.414	-12%
HAIG-20-Q-SSM-S	MgO	0.217	0.217	0	
HAIG-20-Q-SSM-S	MnO	0.0265	0.026	0	
HAIG-20-Q-SSM-S	Na ₂ O	15.7	14.1	1.571	11%
HAIG-20-Q-SSM-S	NiO	0.328	0.347	-0.019	
HAIG-20-Q-SSM-S	P ₂ O ₅	3.96	4.48	-0.522	-12%
HAIG-20-Q-SSM-S	SiO ₂	29.1	29.3	-0.206	-1%
HAIG-20-Q-SSM-S	SO ₃	1.16	0.148	1.011	683%
HAIG-20-Q-SSM-S	SrO	<0.0591	0.045	0.014	
HAIG-20-Q-SSM-S	TiO ₂	0.0932	0.087	0.006	
HAIG-20-Q-SSM-S	ZnO	0.0714	0.073	-0.002	
HAIG-20-Q-SSM-S	ZrO ₂	2.89	3.13	-0.236	-8%
HAIG-20-Q-SSM-S	Sum of Oxides	98.7	100	-1.248	-1%
HAIG-21-Q-SSM-S	Al ₂ O ₃	21.9	22.7	-0.829	-4%
HAIG-21-Q-SSM-S	B ₂ O ₃	10.3	11.8	-1.488	-13%
HAIG-21-Q-SSM-S	Bi ₂ O ₃	0.443	0.466	-0.023	
HAIG-21-Q-SSM-S	CaO	0.902	0.932	-0.030	
HAIG-21-Q-SSM-S	CdO	0.0839	0.093	-0.009	
HAIG-21-Q-SSM-S	Cr ₂ O ₃	0.268	0.445	-0.177	
HAIG-21-Q-SSM-S	F	0.320	0.535	-0.216	
HAIG-21-Q-SSM-S	Fe ₂ O ₃	8.11	8.15	-0.040	0%
HAIG-21-Q-SSM-S	K ₂ O	1.19	1.37	-0.181	-13%
HAIG-21-Q-SSM-S	Li ₂ O	4.18	4.64	-0.463	-10%
HAIG-21-Q-SSM-S	MgO	0.461	0.466	-0.005	
HAIG-21-Q-SSM-S	MnO	0.0696	0.057	0.013	
HAIG-21-Q-SSM-S	Na ₂ O	16.4	15.9	0.512	3%
HAIG-21-Q-SSM-S	NiO	0.708	0.746	-0.038	
HAIG-21-Q-SSM-S	P ₂ O ₅	3.92	4.3	-0.376	-9%
HAIG-21-Q-SSM-S	SiO ₂	25.6	25.5	0.118	0%

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-21-Q-SSM-S	SO ₃	0.934	0.317	0.617	
HAIG-21-Q-SSM-S	SrO	0.0779	0.096	-0.018	
HAIG-21-Q-SSM-S	TiO ₂	0.197	0.186	0.011	
HAIG-21-Q-SSM-S	ZnO	0.157	0.158	-0.001	
HAIG-21-Q-SSM-S	ZrO ₂	1.12	1.18	-0.063	-5%
HAIG-21-Q-SSM-S	Sum of Oxides	97.4	100	-2.686	-3%
HAIG-22-Q-SSM-S	Al ₂ O ₃	20.0	20.7	-0.671	-3%
HAIG-22-Q-SSM-S	B ₂ O ₃	8.84	9.29	-0.451	-5%
HAIG-22-Q-SSM-S	Bi ₂ O ₃	0.650	0.675	-0.025	
HAIG-22-Q-SSM-S	CaO	1.29	1.35	-0.055	-4%
HAIG-22-Q-SSM-S	CdO	0.123	0.135	-0.012	
HAIG-22-Q-SSM-S	Cr ₂ O ₃	1.31	1.72	-0.414	-24%
HAIG-22-Q-SSM-S	F	0.512	0.775	-0.263	
HAIG-22-Q-SSM-S	Fe ₂ O ₃	1.16	1.18	-0.023	-2%
HAIG-22-Q-SSM-S	K ₂ O	1.76	1.98	-0.218	-11%
HAIG-22-Q-SSM-S	Li ₂ O	3.92	4.32	-0.396	-9%
HAIG-22-Q-SSM-S	MgO	0.663	0.675	-0.012	
HAIG-22-Q-SSM-S	MnO	0.0813	0.082	-0.001	
HAIG-22-Q-SSM-S	Na ₂ O	14.4	13.2	1.190	9%
HAIG-22-Q-SSM-S	NiO	1.02	1.08	-0.055	-5%
HAIG-22-Q-SSM-S	P ₂ O ₅	2.38	2.58	-0.203	-8%
HAIG-22-Q-SSM-S	SiO ₂	37.7	37.1	0.552	1%
HAIG-22-Q-SSM-S	SO ₃	0.991	0.459	0.532	
HAIG-22-Q-SSM-S	SrO	0.109	0.139	-0.030	
HAIG-22-Q-SSM-S	TiO ₂	0.287	0.27	0.017	
HAIG-22-Q-SSM-S	ZnO	0.222	0.228	-0.006	
HAIG-22-Q-SSM-S	ZrO ₂	2.06	2.13	-0.070	-3%
HAIG-22-Q-SSM-S	Sum of Oxides	99.5	100	-0.617	-1%
HAIG-23-Q-SSM-S	Al ₂ O ₃	20.5	20.9	-0.399	-2%
HAIG-23-Q-SSM-S	B ₂ O ₃	17.0	17.5	-0.523	-3%
HAIG-23-Q-SSM-S	Bi ₂ O ₃	0.374	0.401	-0.027	
HAIG-23-Q-SSM-S	CaO	0.762	0.803	-0.041	
HAIG-23-Q-SSM-S	CdO	0.0699	0.08	-0.010	
HAIG-23-Q-SSM-S	Cr ₂ O ₃	0.711	0.881	-0.170	
HAIG-23-Q-SSM-S	F	0.277	0.461	-0.184	
HAIG-23-Q-SSM-S	Fe ₂ O ₃	0.212	0.192	0.020	
HAIG-23-Q-SSM-S	K ₂ O	1.24	1.18	0.059	5%
HAIG-23-Q-SSM-S	Li ₂ O	5.37	5.73	-0.364	-6%
HAIG-23-Q-SSM-S	MgO	0.386	0.401	-0.015	
HAIG-23-Q-SSM-S	MnO	0.0468	0.049	-0.002	
HAIG-23-Q-SSM-S	Na ₂ O	12.8	11.1	1.693	15%
HAIG-23-Q-SSM-S	NiO	0.595	0.642	-0.047	
HAIG-23-Q-SSM-S	P ₂ O ₅	3.07	3.42	-0.350	-10%
HAIG-23-Q-SSM-S	SiO ₂	34.8	33.5	1.264	4%
HAIG-23-Q-SSM-S	SO ₃	1.28	0.273	1.012	371%
HAIG-23-Q-SSM-S	SrO	0.0658	0.083	-0.017	
HAIG-23-Q-SSM-S	TiO ₂	0.164	0.161	0.003	
HAIG-23-Q-SSM-S	ZnO	0.130	0.136	-0.006	

Table A-4. Comparison of Measured and Targeted Compositions (continued)

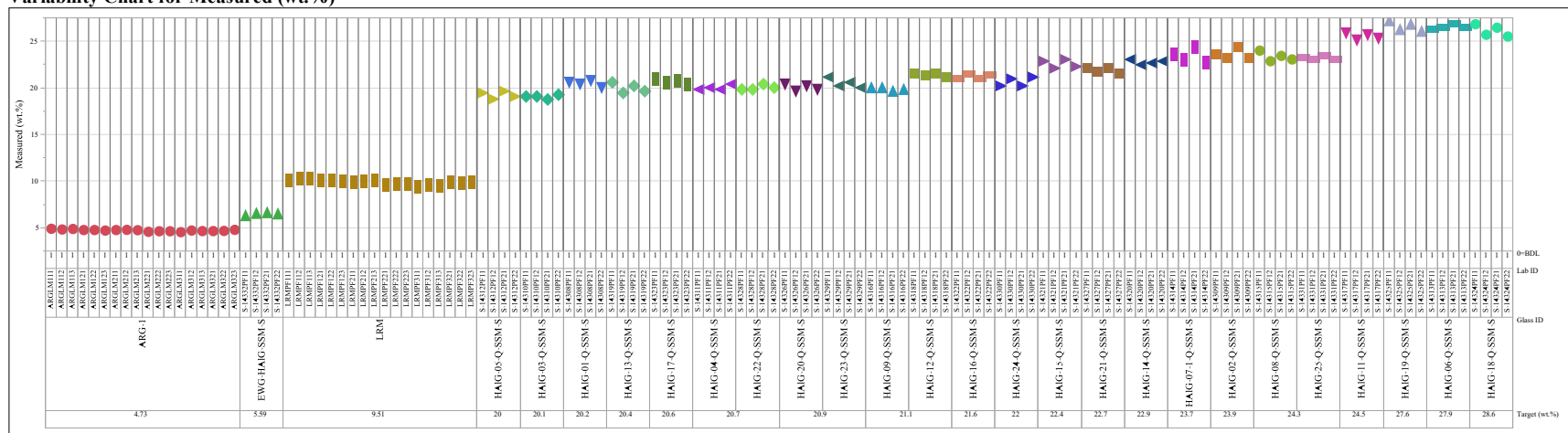
PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
HAIG-23-Q-SSM-S	ZrO ₂	2.03	2.1	-0.074	-4%
HAIG-23-Q-SSM-S	Sum of Oxides	102	100	1.823	2%
HAIG-24-Q-SSM-S	Al ₂ O ₃	20.6	22	-1.357	-6%
HAIG-24-Q-SSM-S	B ₂ O ₃	14.4	15.5	-1.067	-7%
HAIG-24-Q-SSM-S	Bi ₂ O ₃	0.962	1	-0.038	-4%
HAIG-24-Q-SSM-S	CaO	3.45	3.5	-0.054	-2%
HAIG-24-Q-SSM-S	CdO	0.0904	0.1	-0.010	
HAIG-24-Q-SSM-S	Cr ₂ O ₃	0.654	0.75	-0.096	
HAIG-24-Q-SSM-S	F	0.180	0.3	-0.120	
HAIG-24-Q-SSM-S	Fe ₂ O ₃	5.49	5.5	-0.010	0%
HAIG-24-Q-SSM-S	K ₂ O	0.761	0.7	0.061	
HAIG-24-Q-SSM-S	Li ₂ O	2.53	3	-0.470	-16%
HAIG-24-Q-SSM-S	MgO	0.509	0.5	0.009	
HAIG-24-Q-SSM-S	MnO	0.965	1	-0.035	-3%
HAIG-24-Q-SSM-S	Na ₂ O	13.5	11.5	1.970	17%
HAIG-24-Q-SSM-S	NiO	0.380	0.4	-0.020	
HAIG-24-Q-SSM-S	P ₂ O ₅	0.871	1	-0.129	-13%
HAIG-24-Q-SSM-S	SiO ₂	31.2	31.5	-0.266	-1%
HAIG-24-Q-SSM-S	SO ₃	1.09	0.3	0.786	262%
HAIG-24-Q-SSM-S	SrO	0.0963	0.12	-0.024	
HAIG-24-Q-SSM-S	TiO ₂	<0.0834	0	0.083	
HAIG-24-Q-SSM-S	ZnO	<0.0622	0	0.062	
HAIG-24-Q-SSM-S	ZrO ₂	0.930	1	-0.070	-7%
HAIG-24-Q-SSM-S	Sum of Oxides	98.9	99.7	-0.795	-1%
HAIG-25-Q-SSM-S	Al ₂ O ₃	23.2	24.3	-1.106	-5%
HAIG-25-Q-SSM-S	B ₂ O ₃	14.0	14.8	-0.810	-5%
HAIG-25-Q-SSM-S	Bi ₂ O ₃	<0.111	0.096	0.015	
HAIG-25-Q-SSM-S	CaO	0.200	0.192	0.008	
HAIG-25-Q-SSM-S	CdO	<0.0286	0.019	0.010	
HAIG-25-Q-SSM-S	Cr ₂ O ₃	0.543	0.649	-0.106	
HAIG-25-Q-SSM-S	F	0.0624	0.11	-0.048	
HAIG-25-Q-SSM-S	Fe ₂ O ₃	10.3	10.7	-0.385	-4%
HAIG-25-Q-SSM-S	K ₂ O	0.436	0.283	0.153	
HAIG-25-Q-SSM-S	Li ₂ O	1.79	1.8	-0.013	-1%
HAIG-25-Q-SSM-S	MgO	0.104	0.096	0.008	
HAIG-25-Q-SSM-S	MnO	0.0307	0.012	0.019	
HAIG-25-Q-SSM-S	Na ₂ O	18.6	17.5	1.069	6%
HAIG-25-Q-SSM-S	NiO	0.148	0.154	-0.006	
HAIG-25-Q-SSM-S	P ₂ O ₅	3.87	4.36	-0.488	-11%
HAIG-25-Q-SSM-S	SiO ₂	24.9	24.8	0.069	0%
HAIG-25-Q-SSM-S	SO ₃	0.853	0.065	0.788	
HAIG-25-Q-SSM-S	SrO	<0.0591	0.02	0.039	
HAIG-25-Q-SSM-S	TiO ₂	<0.0854	0.038	0.047	
HAIG-25-Q-SSM-S	ZnO	<0.0622	0.033	0.029	
HAIG-25-Q-SSM-S	ZrO ₂	<0.135	0.041	0.094	
HAIG-25-Q-SSM-S	Sum of Oxides	99.5	100	-0.612	-1%
LRM	Al ₂ O ₃	9.88	9.51	0.370	4%
LRM	B ₂ O ₃	7.54	7.85	-0.314	-4%

Table A-4. Comparison of Measured and Targeted Compositions (continued)

PNNL ID	Oxide	Mean Measurement (wt.%)	Targeted (wt.%)	Difference of Measured versus Targeted	% Difference Measured versus Targeted
LRM	Bi ₂ O ₃	<0.111	0	0.111	
LRM	CaO	0.492	0.54	-0.048	
LRM	CdO	0.159	0.16	-0.001	
LRM	Cr ₂ O ₃	0.185	0.19	-0.005	
LRM	F	0.903	0.86	0.043	
LRM	Fe ₂ O ₃	1.46	1.38	0.078	6%
LRM	K ₂ O	1.58	1.48	0.103	7%
LRM	Li ₂ O	<0.222	0.11	0.112	
LRM	MgO	0.107	0.1	0.007	
LRM	MnO	0.0814	0.08	0.001	
LRM	Na ₂ O	20.9	20	0.864	4%
LRM	NiO	0.174	0.19	-0.016	
LRM	P ₂ O ₅	0.504	0.54	-0.036	
LRM	SiO ₂	55.1	54.2	0.851	2%
LRM	SO ₃	0.233	0.3	-0.067	
LRM	SrO	<0.0591	0	0.059	
LRM	TiO ₂	0.100	0.1	0	
LRM	ZnO	<0.0622	0	0.062	
LRM	ZrO ₂	1.00	0.93	0.073	8%
LRM	Sum of Oxides	101	98.6	2.249	2%

Exhibit A-1. Plots of Oxide Measurements by Glass Identifier by Targeted Concentrations

Oxide= Al_2O_3 , Prep Method=PF
 Variability Chart for Measured (wt.%)



Oxide= B_2O_3 , Prep Method=PF
 Variability Chart for Measured (wt.%)

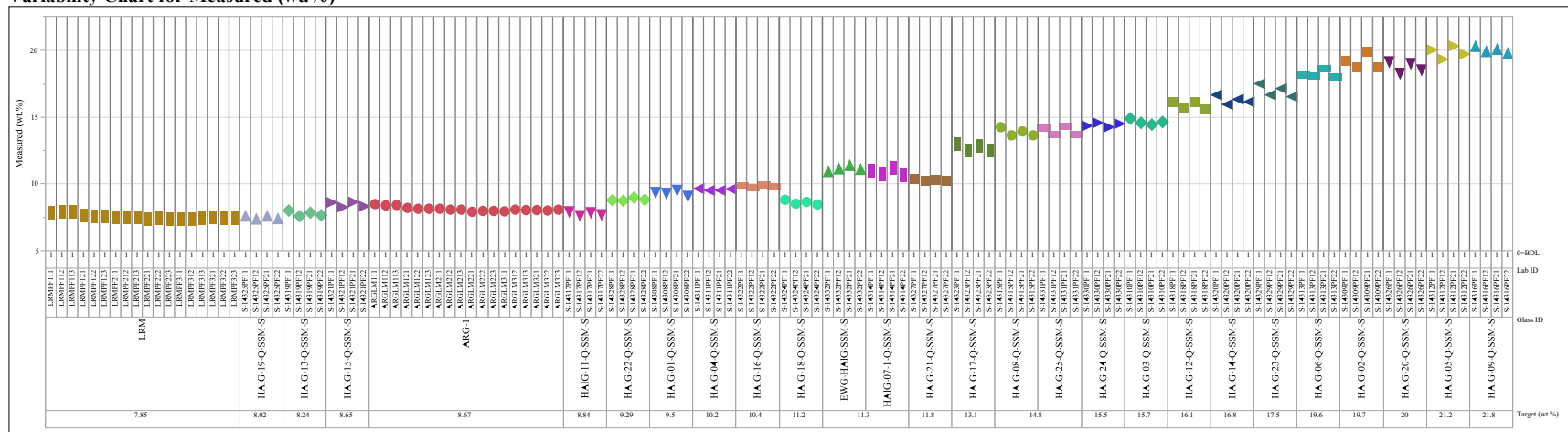
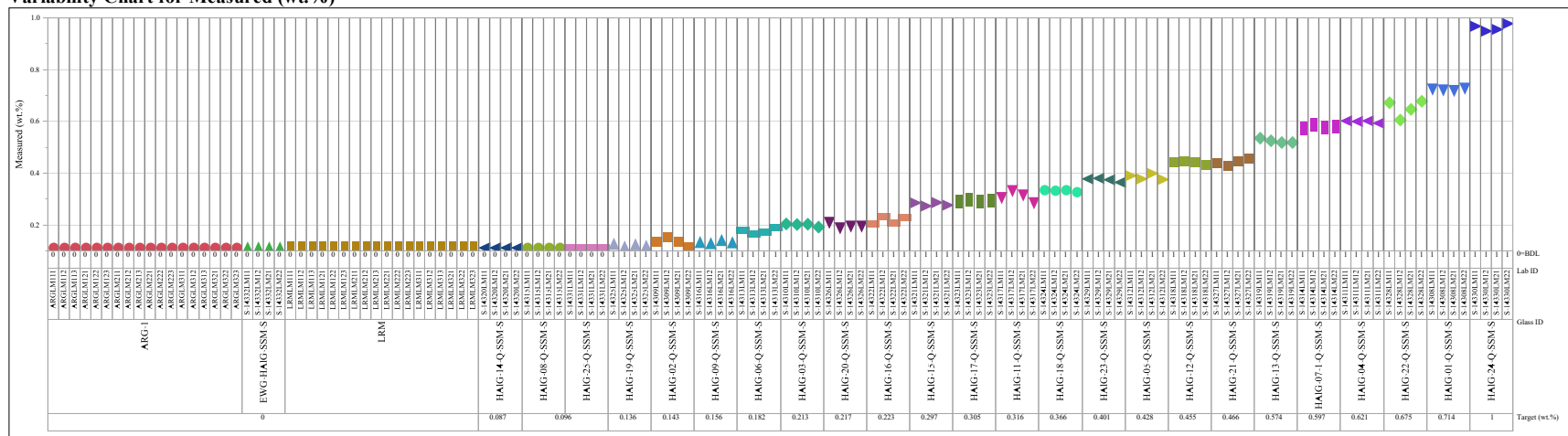


Exhibit A-1. Plots of Oxide Measurements by Glass Identifier by Targeted Concentrations (continued)

Oxide= Bi_2O_3 , Prep Method=LM
 Variability Chart for Measured (wt.%)



Oxide= CaO , Prep Method=LM
 Variability Chart for Measured (wt.%)

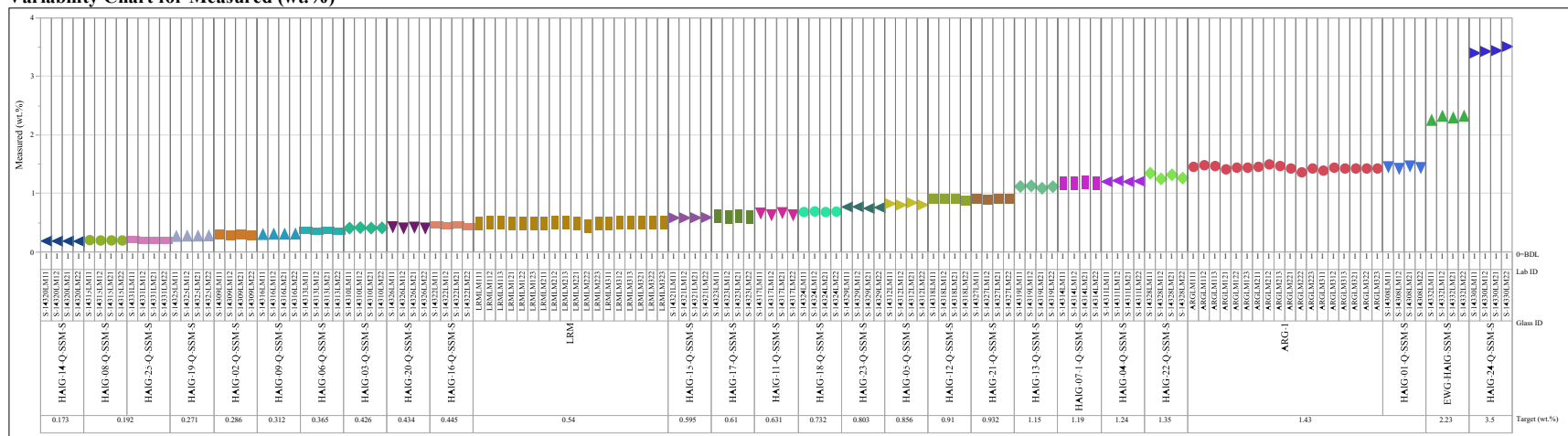
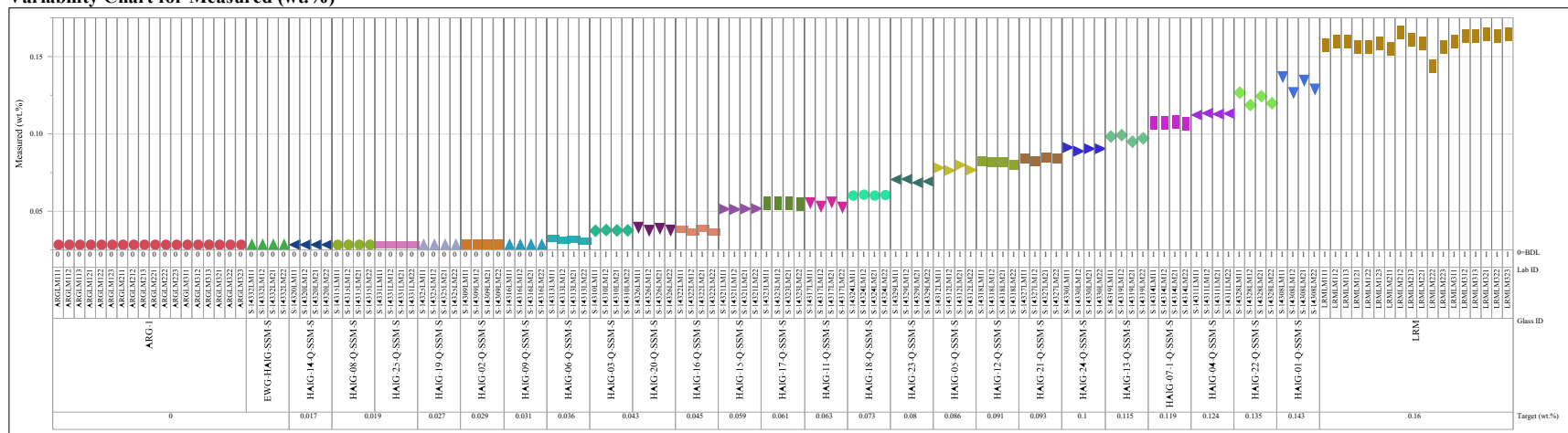


Exhibit A-1. Plots of Oxide Measurements by Glass Identifier by Targeted Concentrations (continued)

Oxide=CdO, Prep Method=LM
 Variability Chart for Measured (wt.%)



Oxide=Cr₂O₃, Prep Method=LM
 Variability Chart for Measured (wt.%)

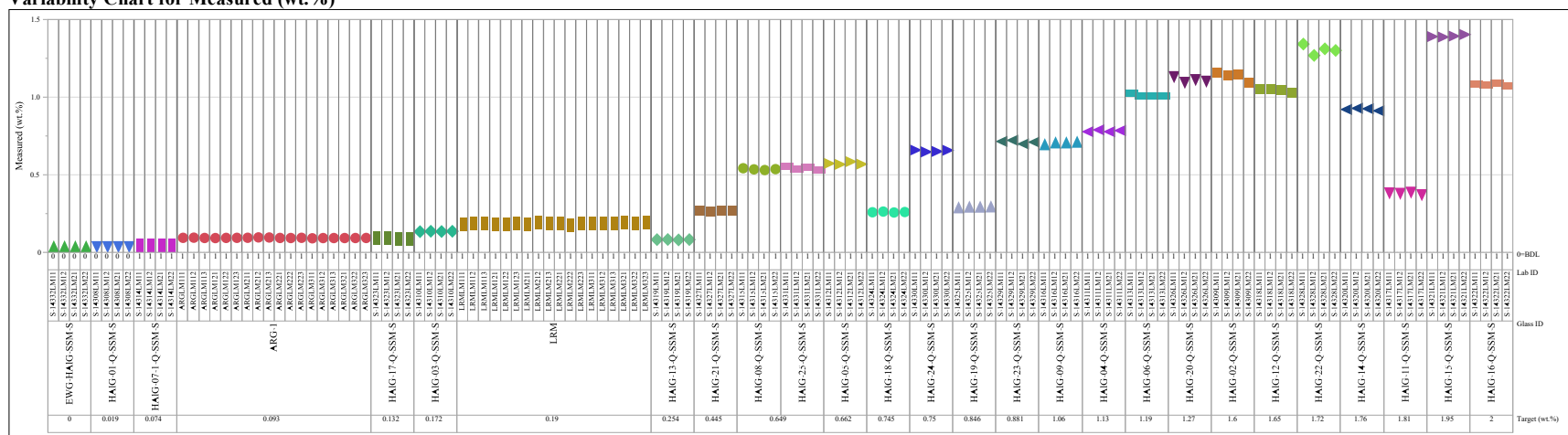
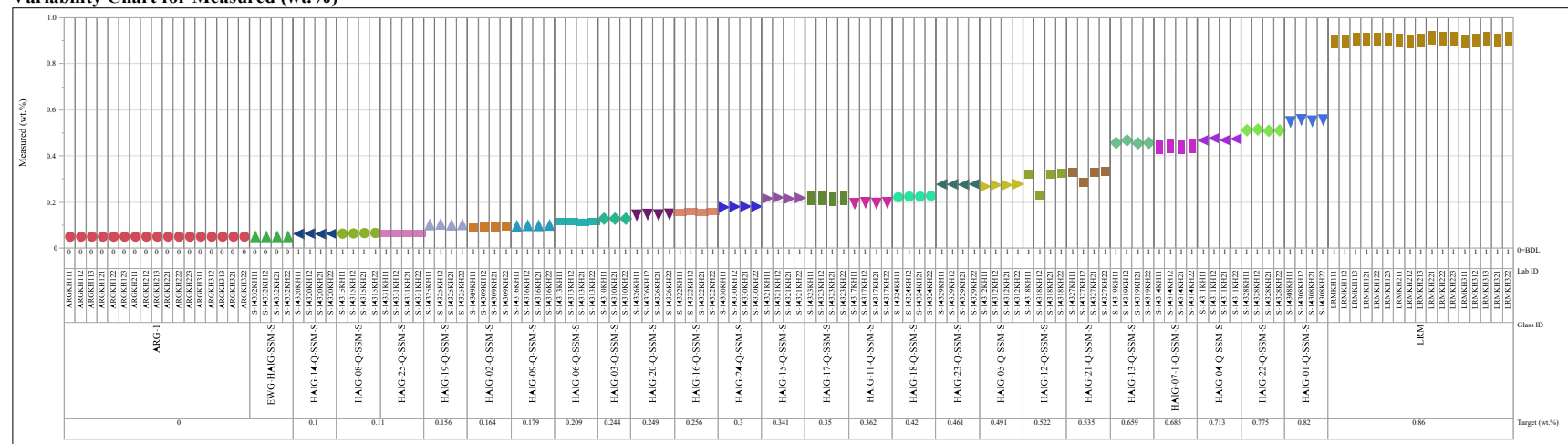


Exhibit A-1. Plots of Oxide Measurements by Glass Identifier by Targeted Concentrations (continued)

Oxide=F, Prep Method=KH

Variability Chart for Measured (wt.%)

Oxide=Fe₂O₃, Prep Method=LM

Variability Chart for Measured (wt.%)

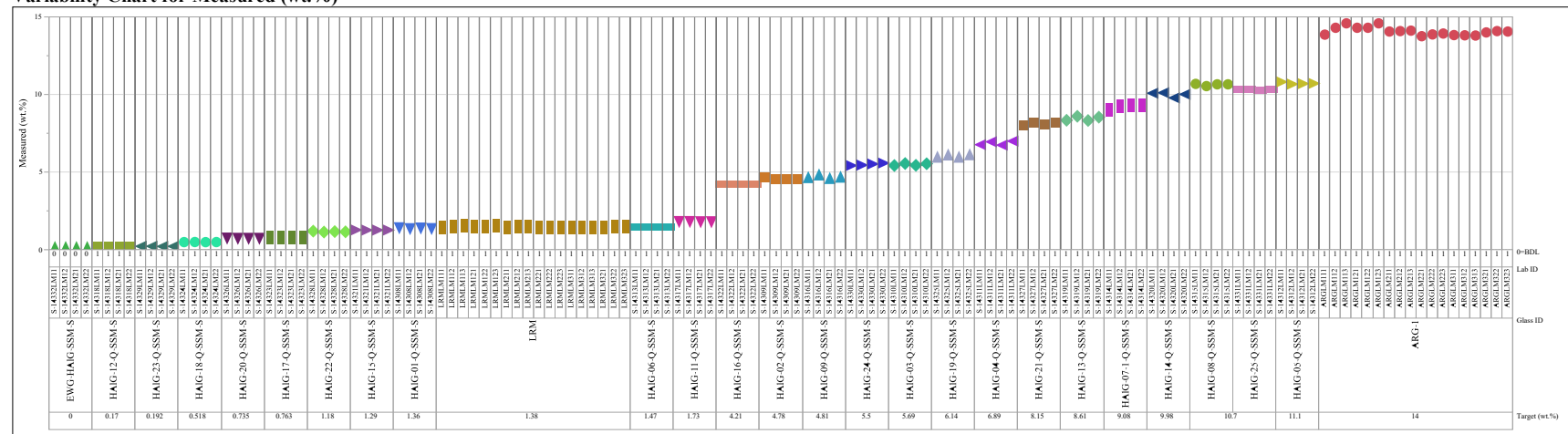
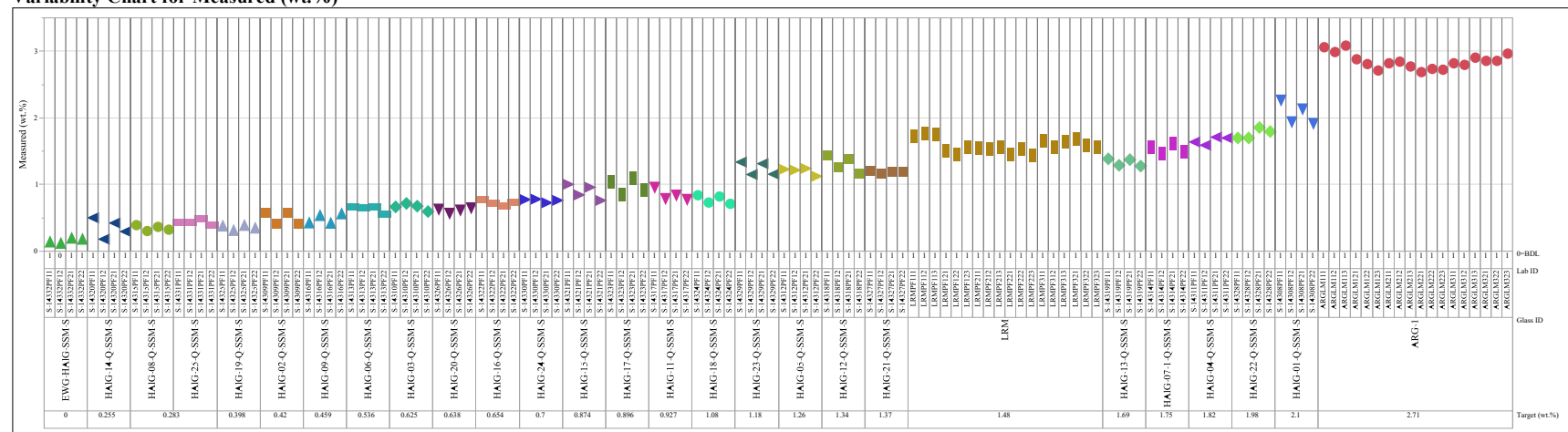


Exhibit A-1. Plots of Oxide Measurements by Glass Identifier by Targeted Concentrations (continued)

Oxide= K_2O , Prep Method=PF

Variability Chart for Measured (wt.%)

Oxide= Li_2O , Prep Method=PF

Variability Chart for Measured (wt.%)

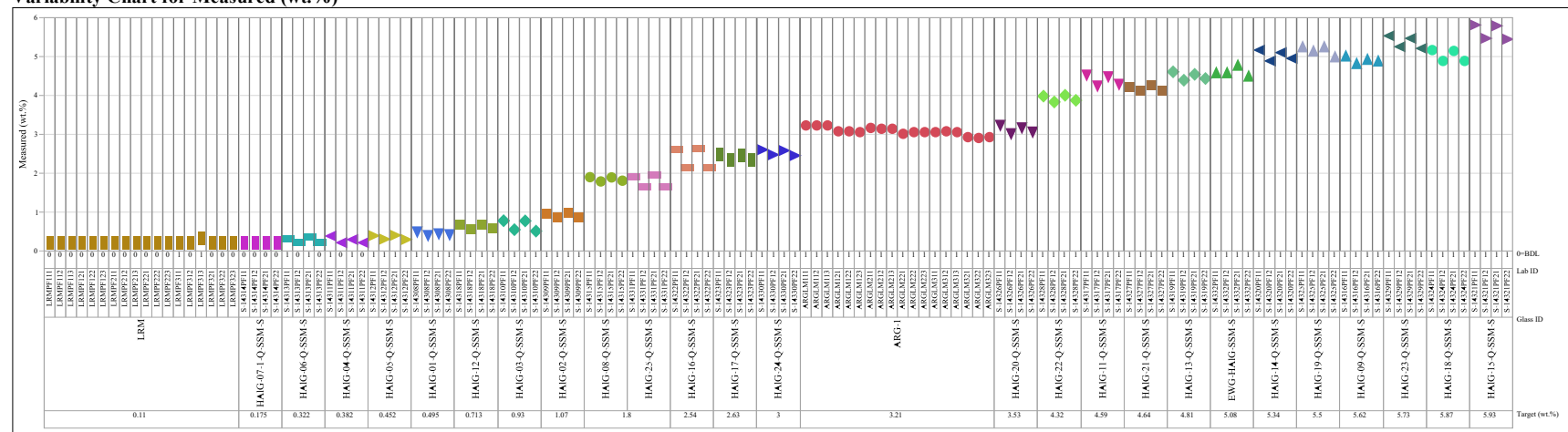
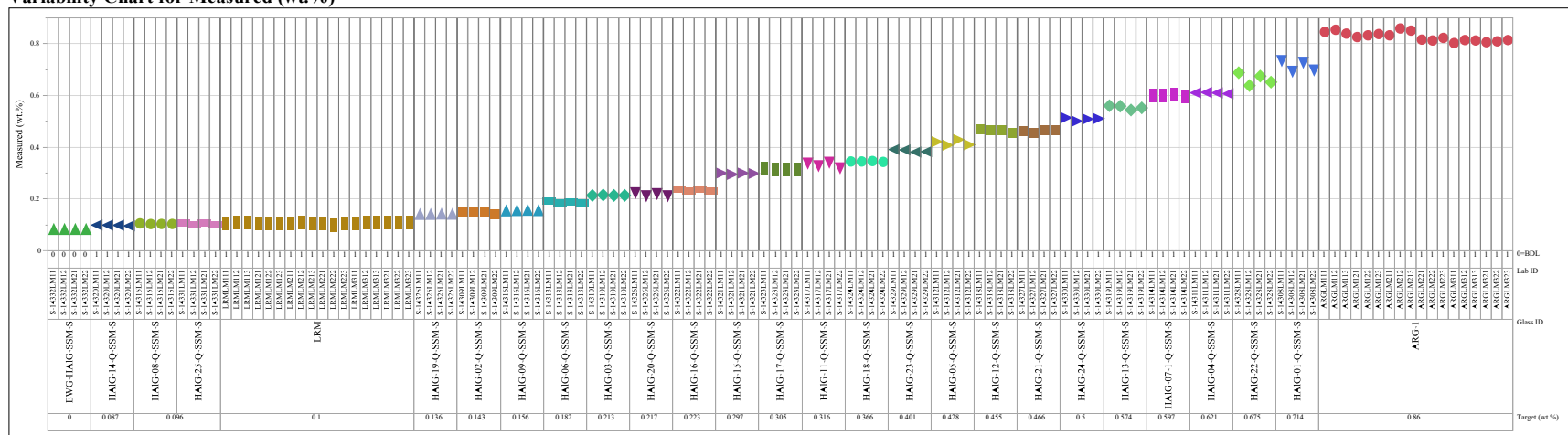


Exhibit A-1. Plots of Oxide Measurements by Glass Identifier by Targeted Concentrations (continued)

Oxide=MgO, Prep Method=LM
 Variability Chart for Measured (wt.%)



Oxide=MnO, Prep Method=LM
 Variability Chart for Measured (wt.%)

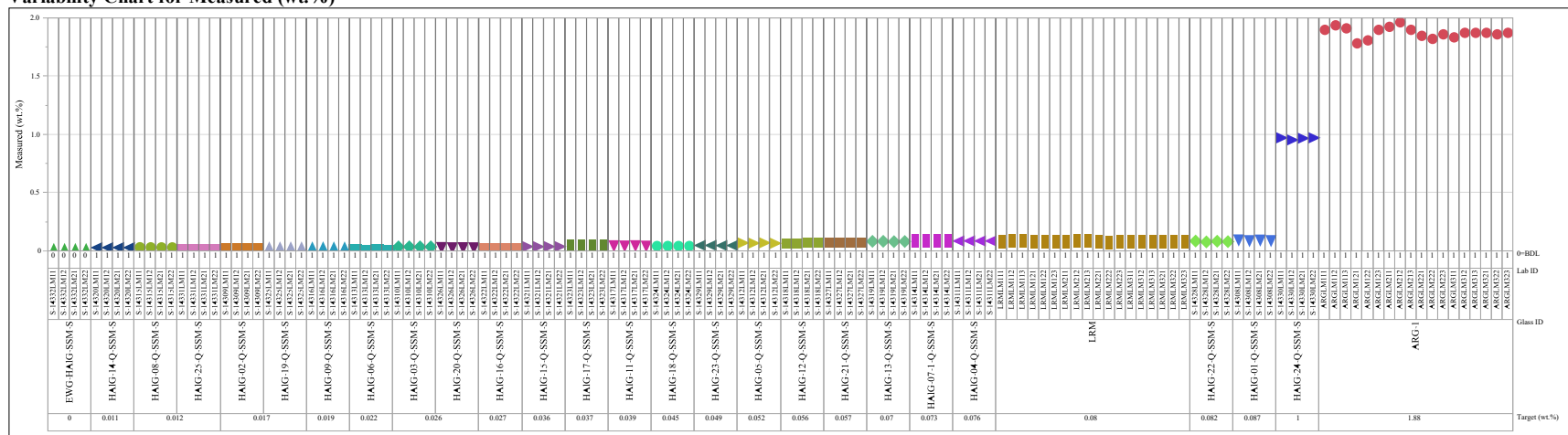
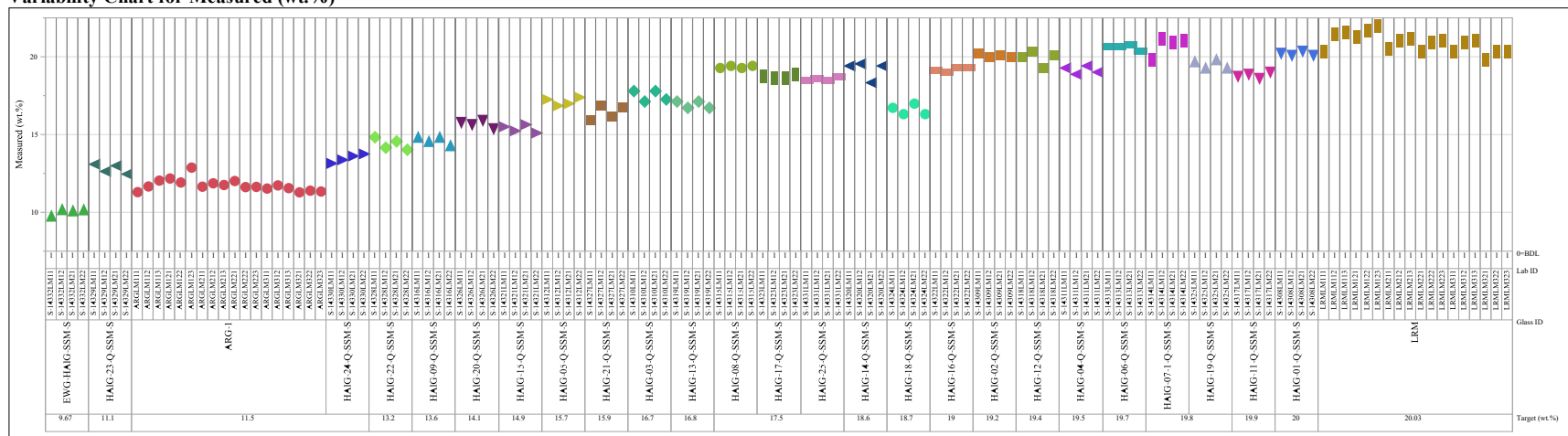


Exhibit A-1. Plots of Oxide Measurements by Glass Identifier by Targeted Concentrations (continued)

Oxide= Na_2O , Prep Method=LM
 Variability Chart for Measured (wt.%)



Oxide= NiO , Prep Method=LM
 Variability Chart for Measured (wt.%)

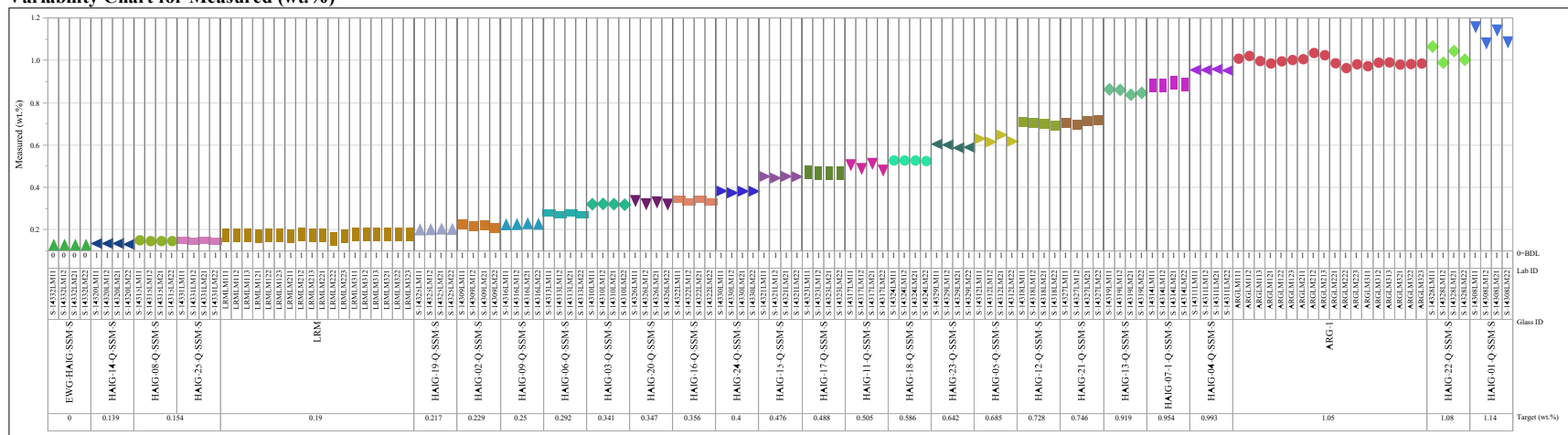
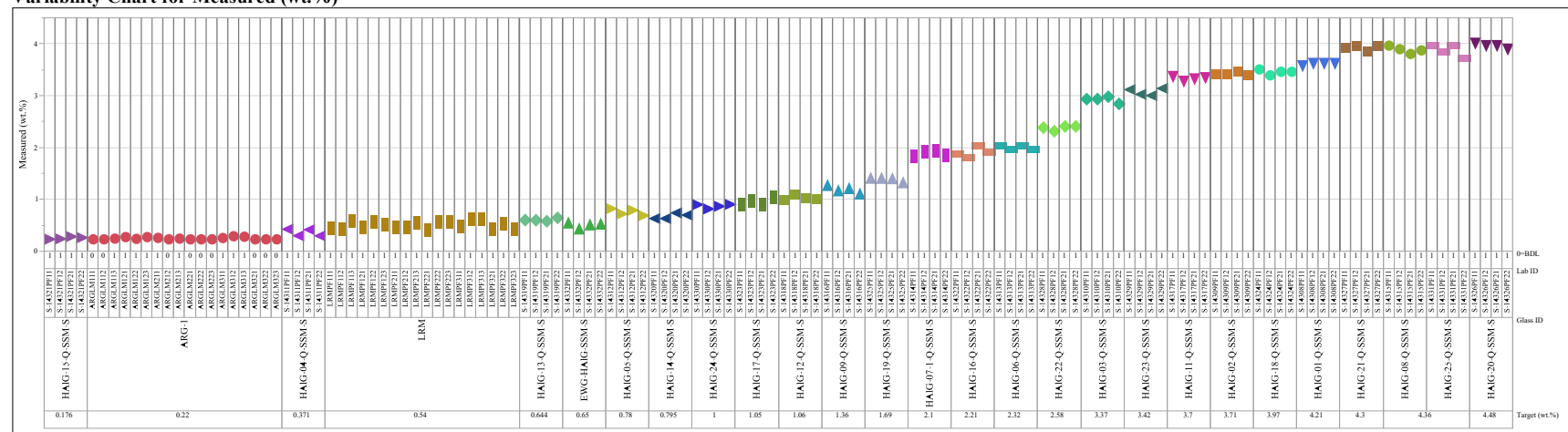


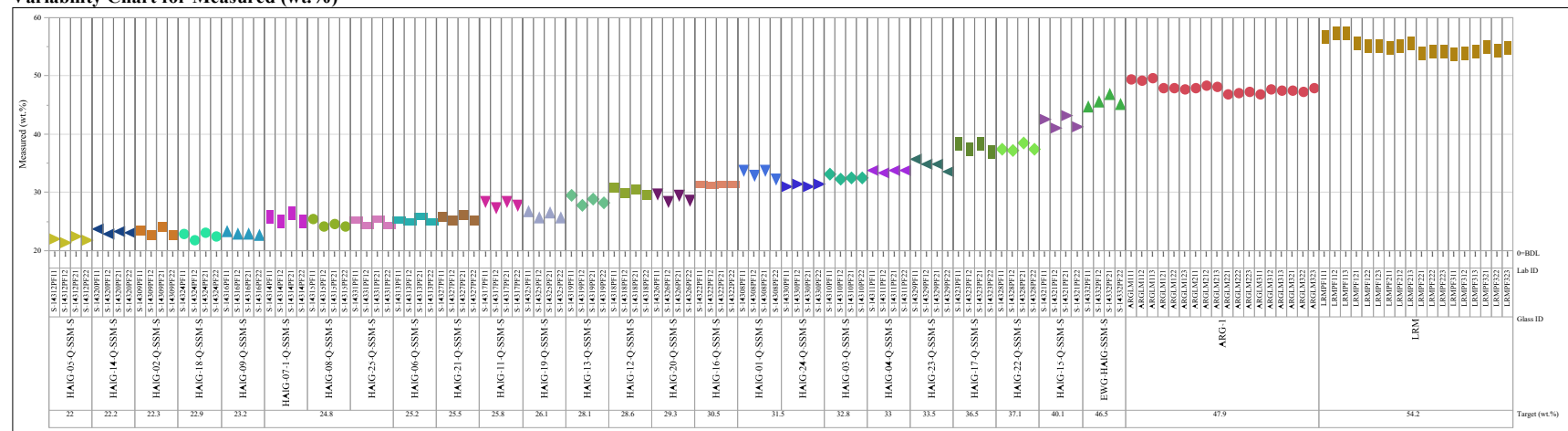
Exhibit A-1. Plots of Oxide Measurements by Glass Identifier by Targeted Concentrations (continued)

Oxide= P_2O_5 , Prep Method=PF

Variability Chart for Measured (wt.%)

Oxide= SiO_2 , Prep Method=PF

Variability Chart for Measured (wt.%)



Oxide=SO₃, Prep Method=LM
Variability Chart for Measured (wt.%)

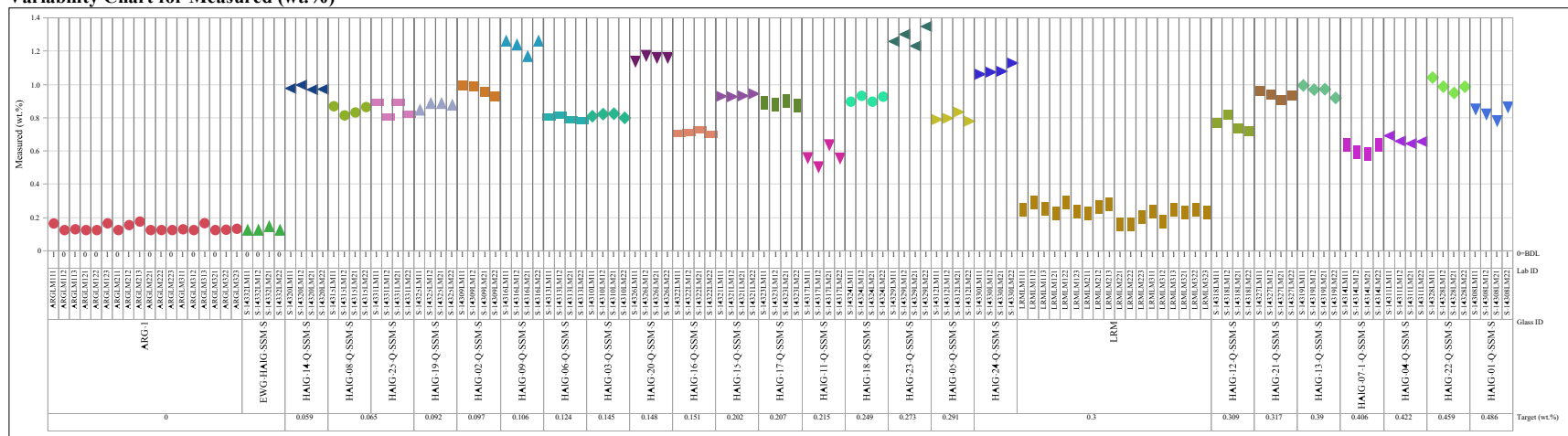
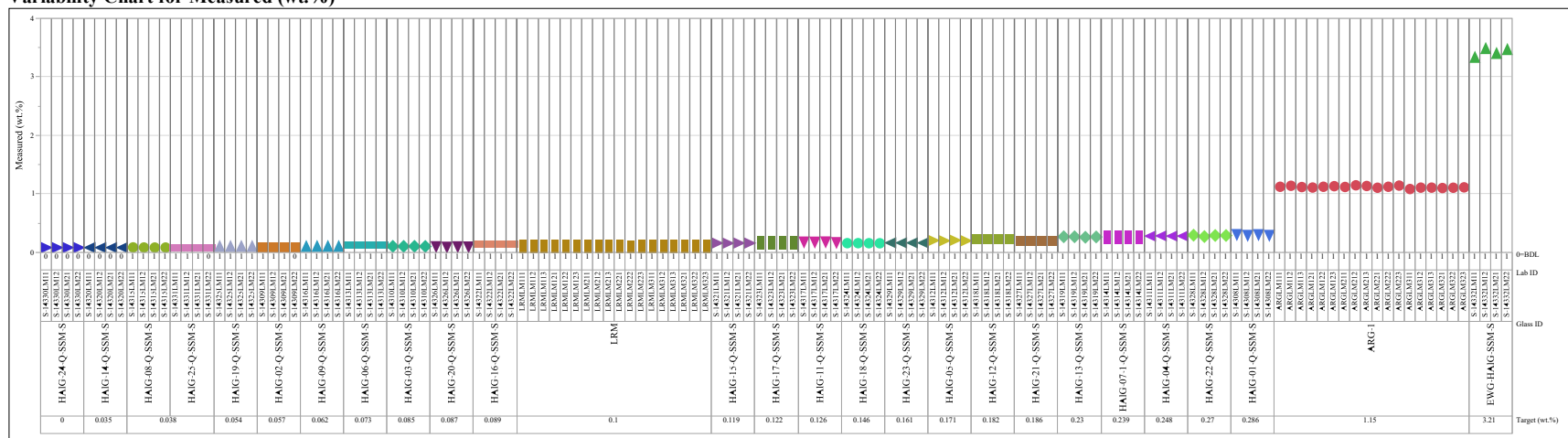
[illegible]

Exhibit A-1. Plots of Oxide Measurements by Glass Identifier by Targeted Concentrations (continued)

Oxide=TiO₂, Prep Method=LM
Variability Chart for Measured (wt.%)



Oxide=ZnO, Prep Method=LM
Variability Chart for Measured (wt.%)

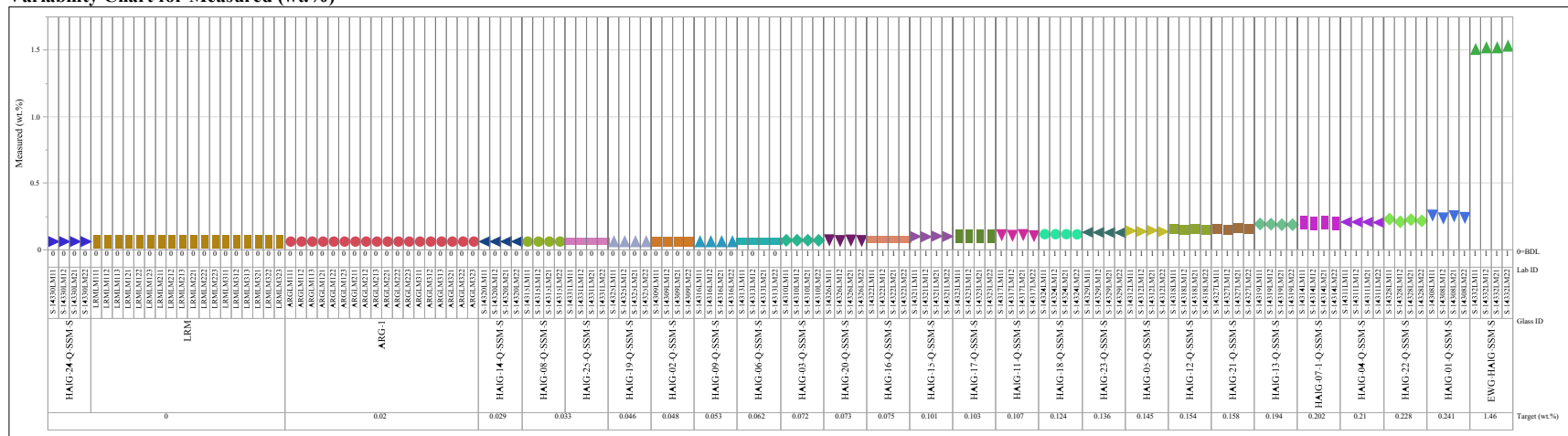


Exhibit A-1. Plots of Oxide Measurements by Glass Identifier by Targeted Concentrations (continued)

Oxide=ZrO₂, Prep Method=PF
Variability Chart for Measured (wt.%)

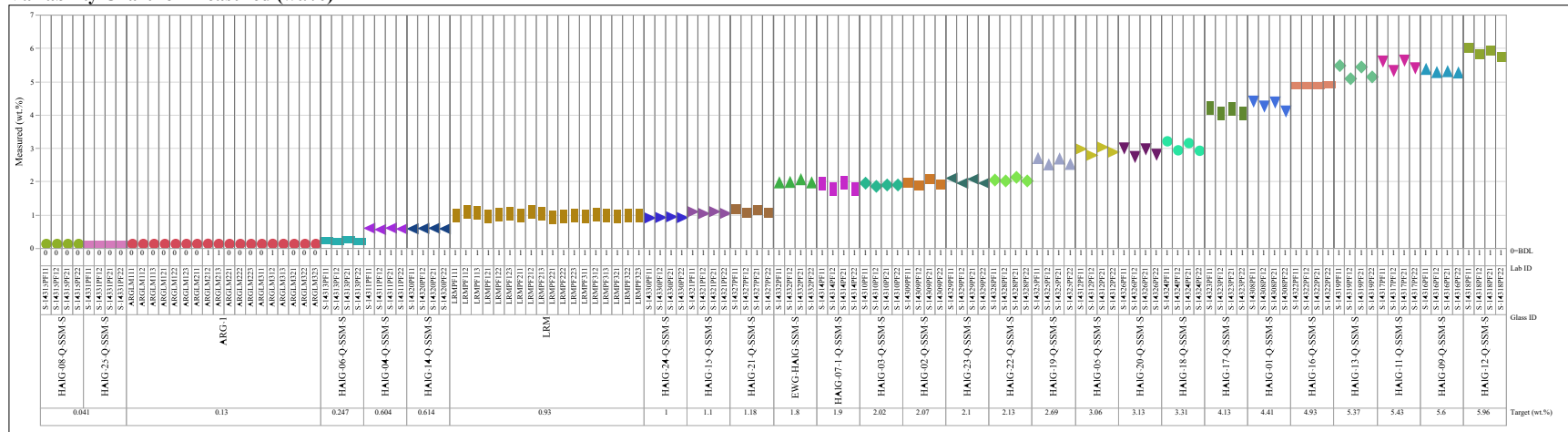
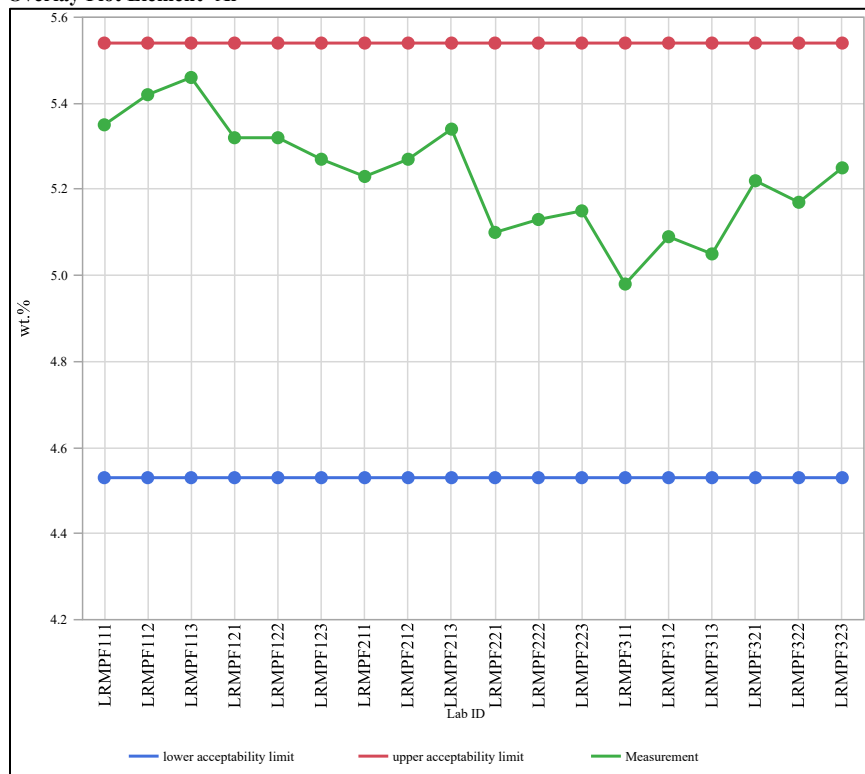


Exhibit A-2. Acceptability Evaluation for Measurements of the LRM Glass

Overlay Plot Element=A1



Overlay Plot Element=B

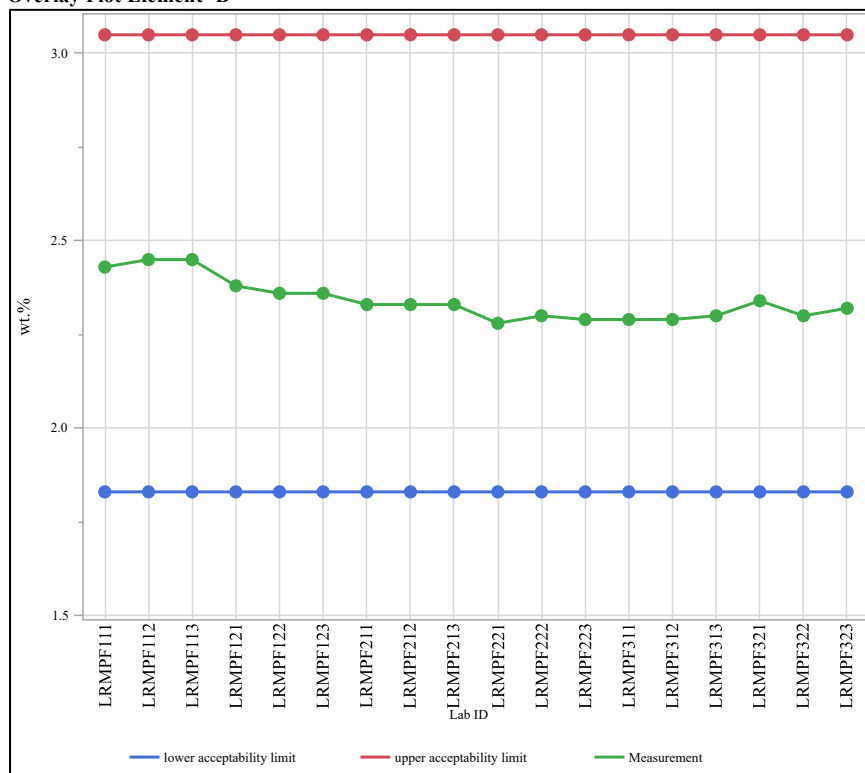
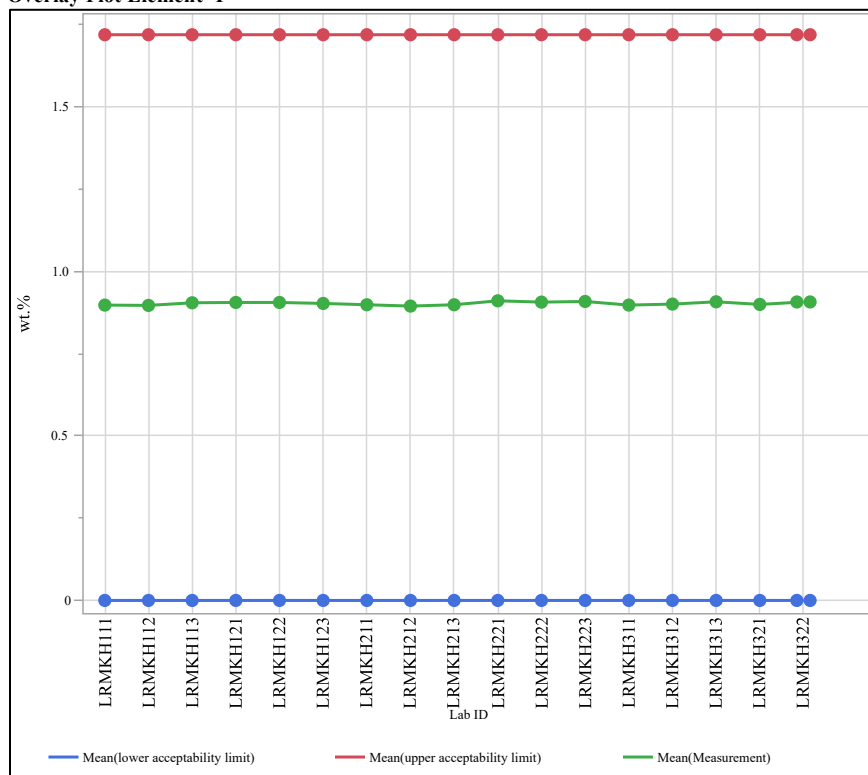


Exhibit A-2. Acceptability Evaluation for Measurements of the LRM Glass (continued)

Overlay Plot Element=F



Overlay Plot Element=Fe

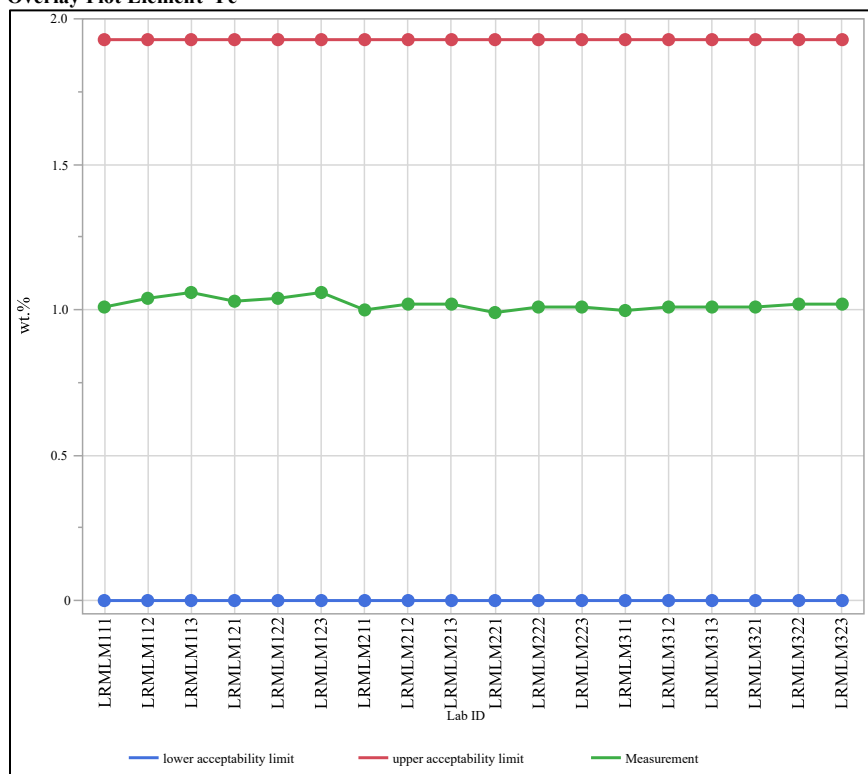
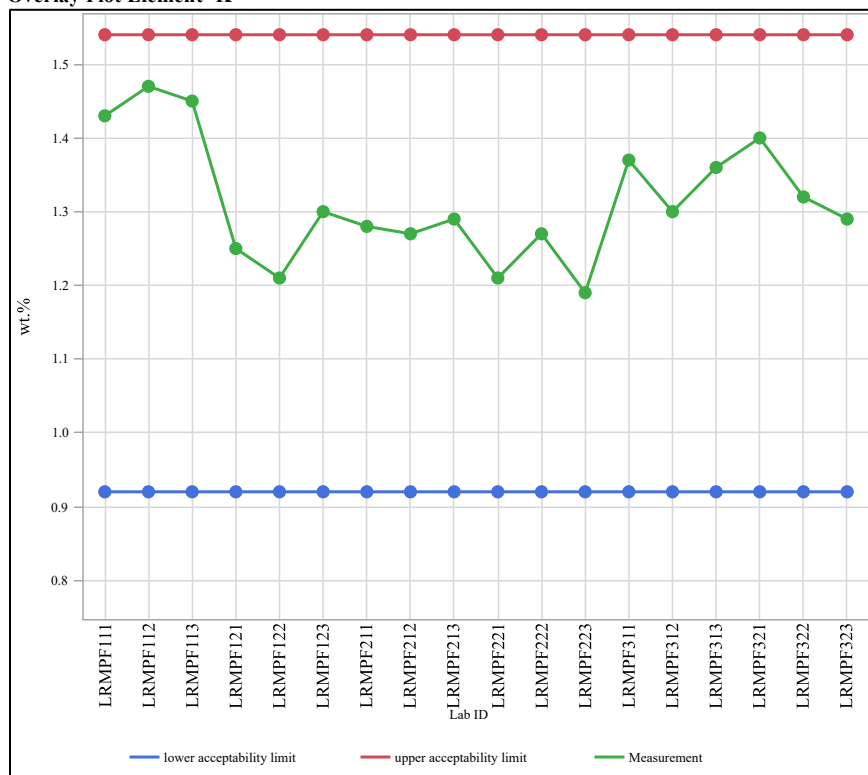


Exhibit A-2. Acceptability Evaluation for Measurements of the LRM Glass (continued)

Overlay Plot Element=K



Overlay Plot Element=Na

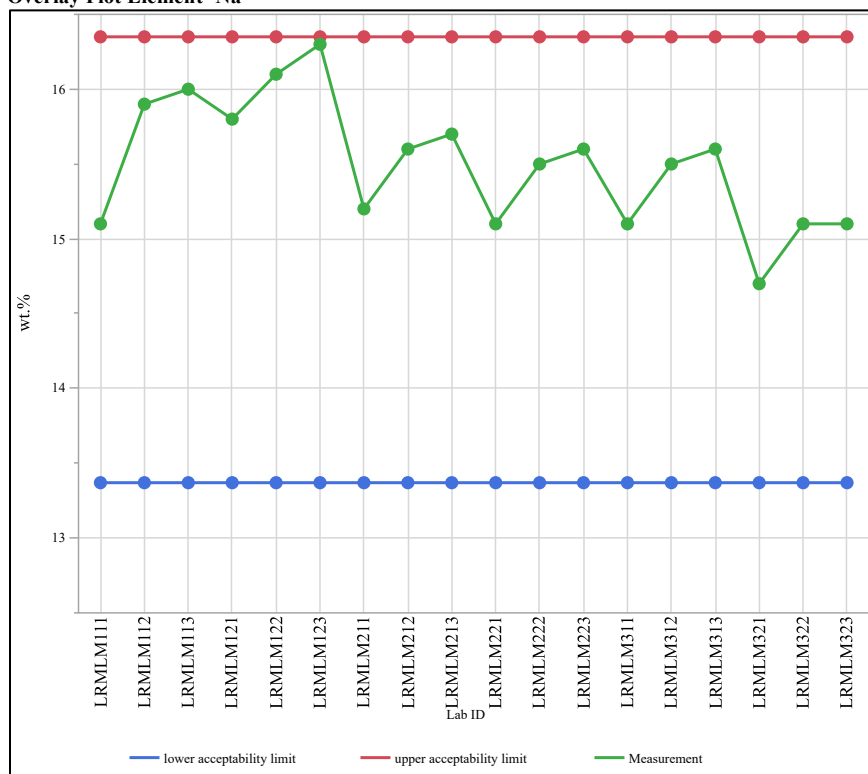
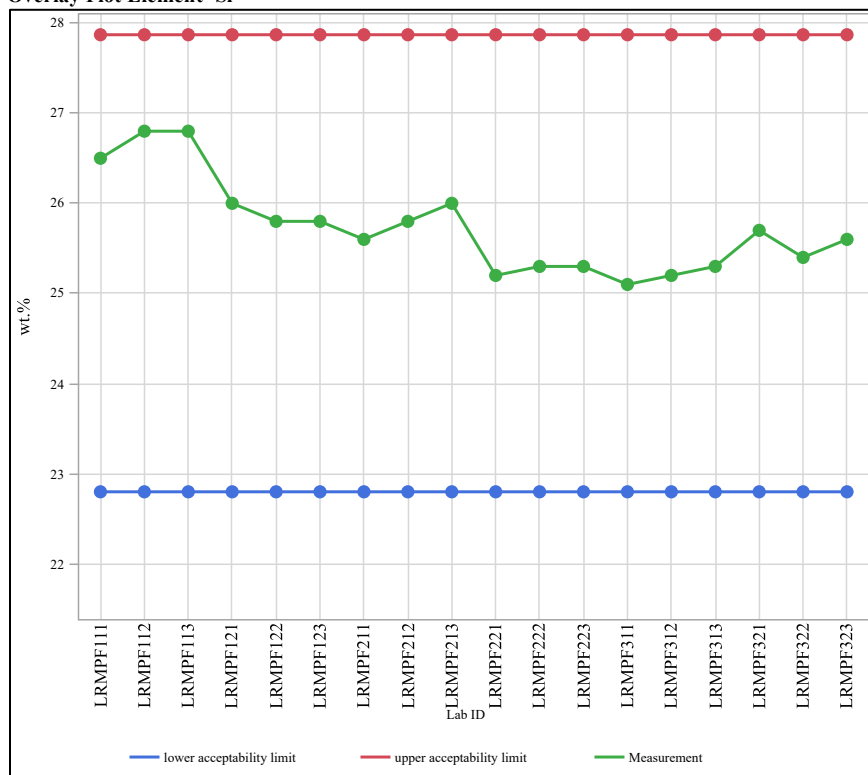


Exhibit A-2. Acceptability Evaluation for Measurements of the LRM Glass (continued)

Overlay Plot Element=Si



Overlay Plot Element=Zr

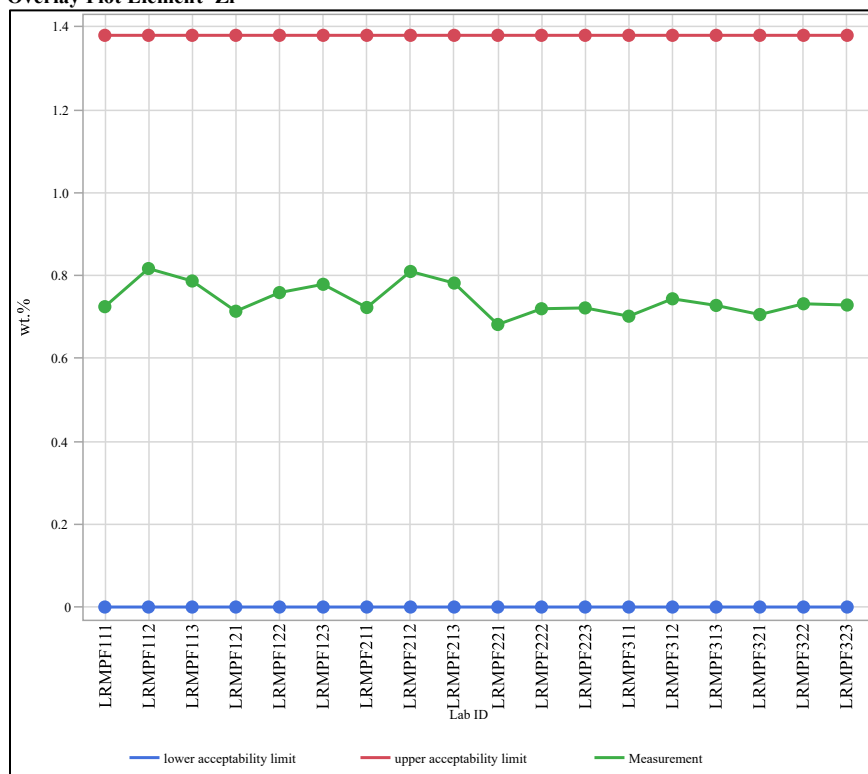
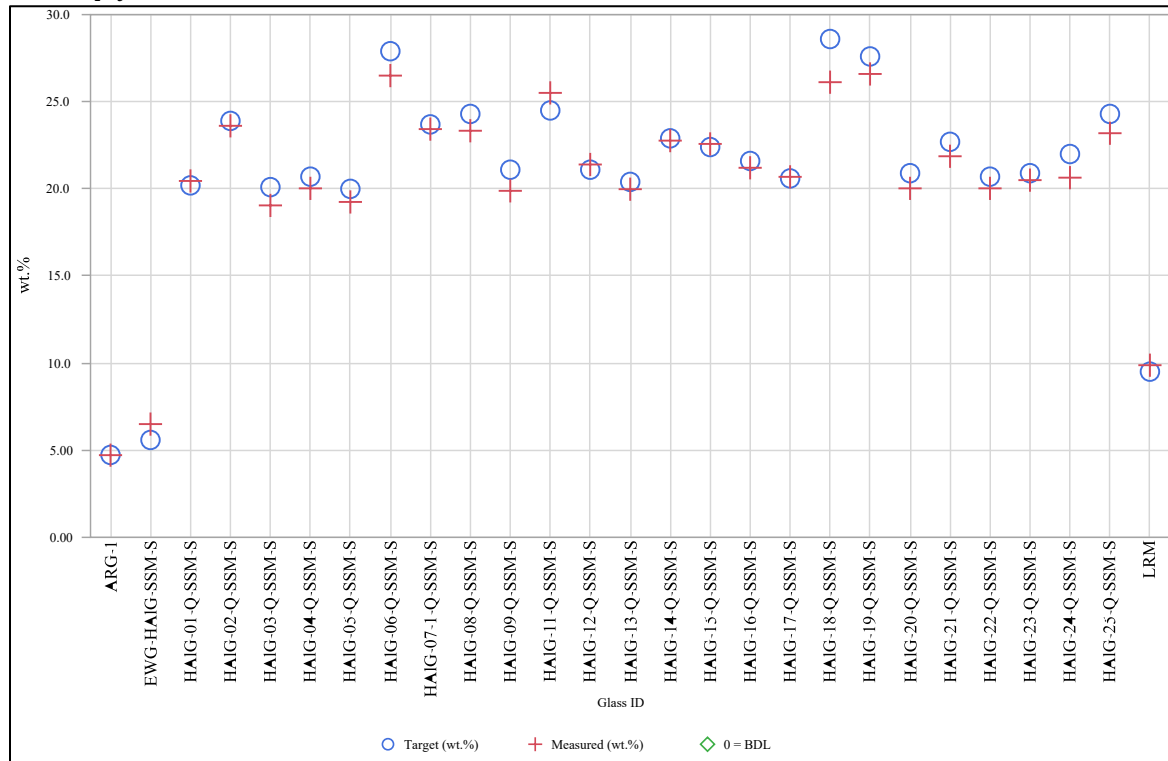


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide

Oxide= Al_2O_3



Oxide= B_2O_3

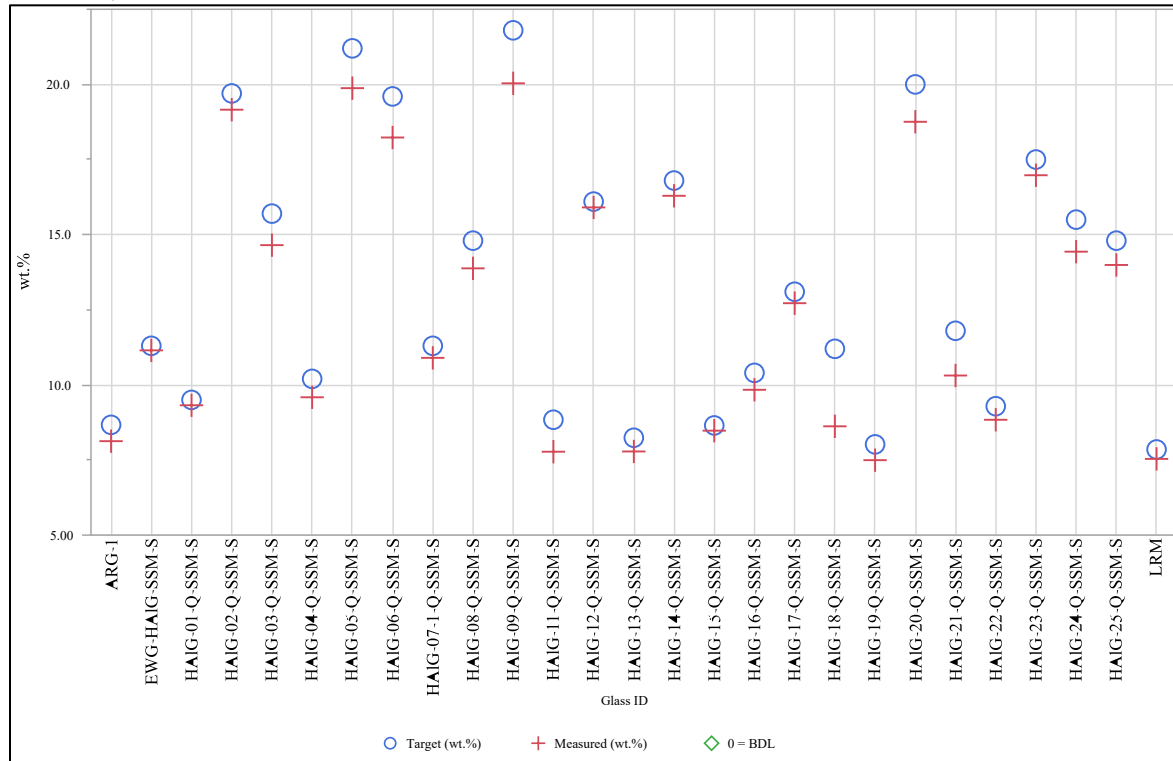
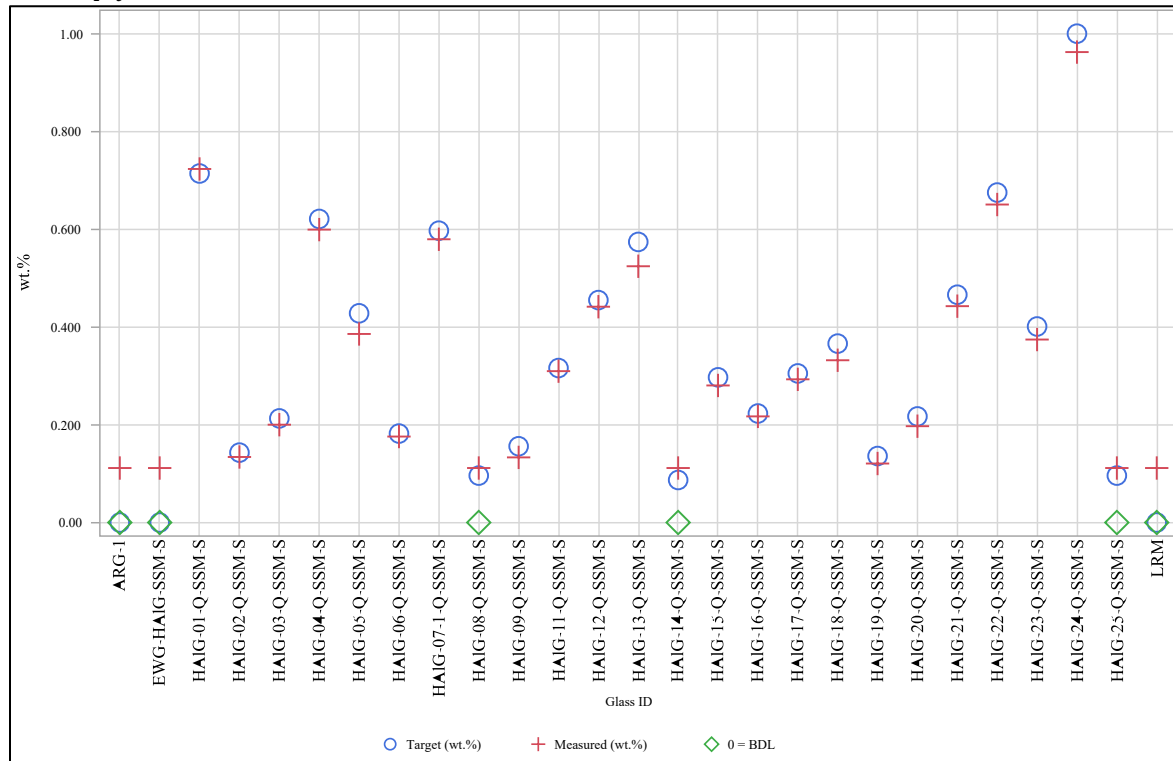


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide (continued)

Oxide= Bi_2O_3



Oxide= CaO

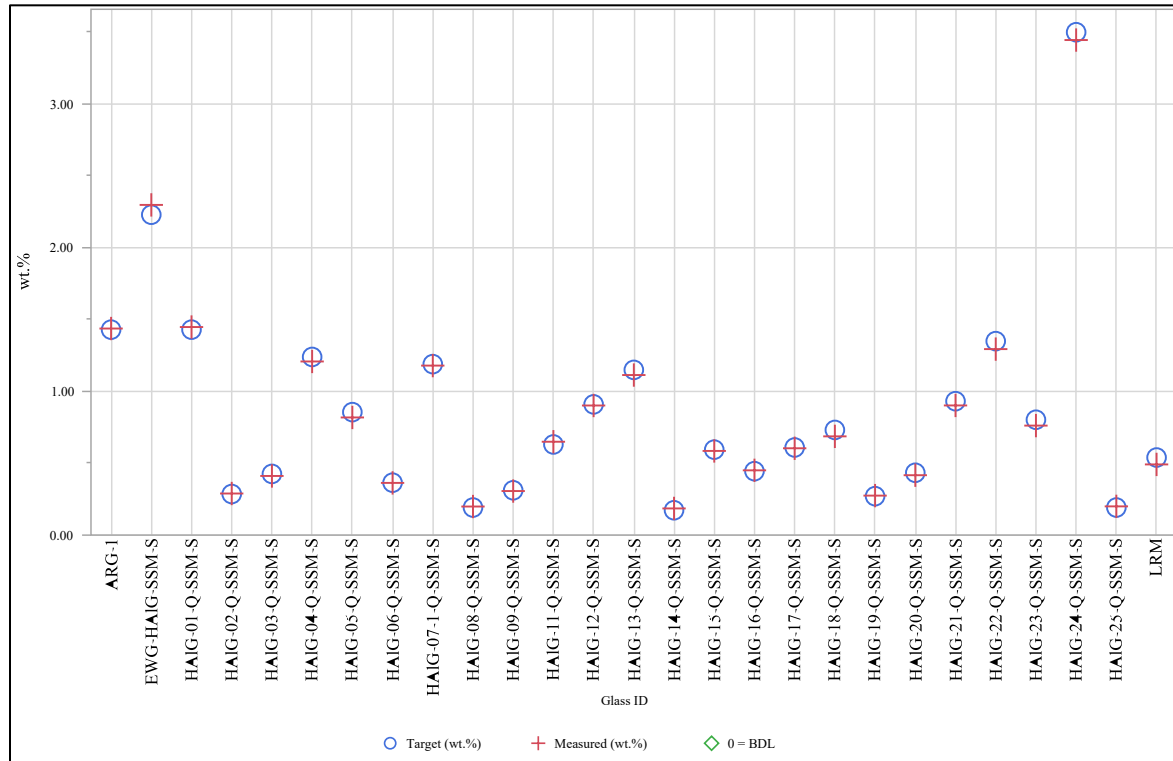
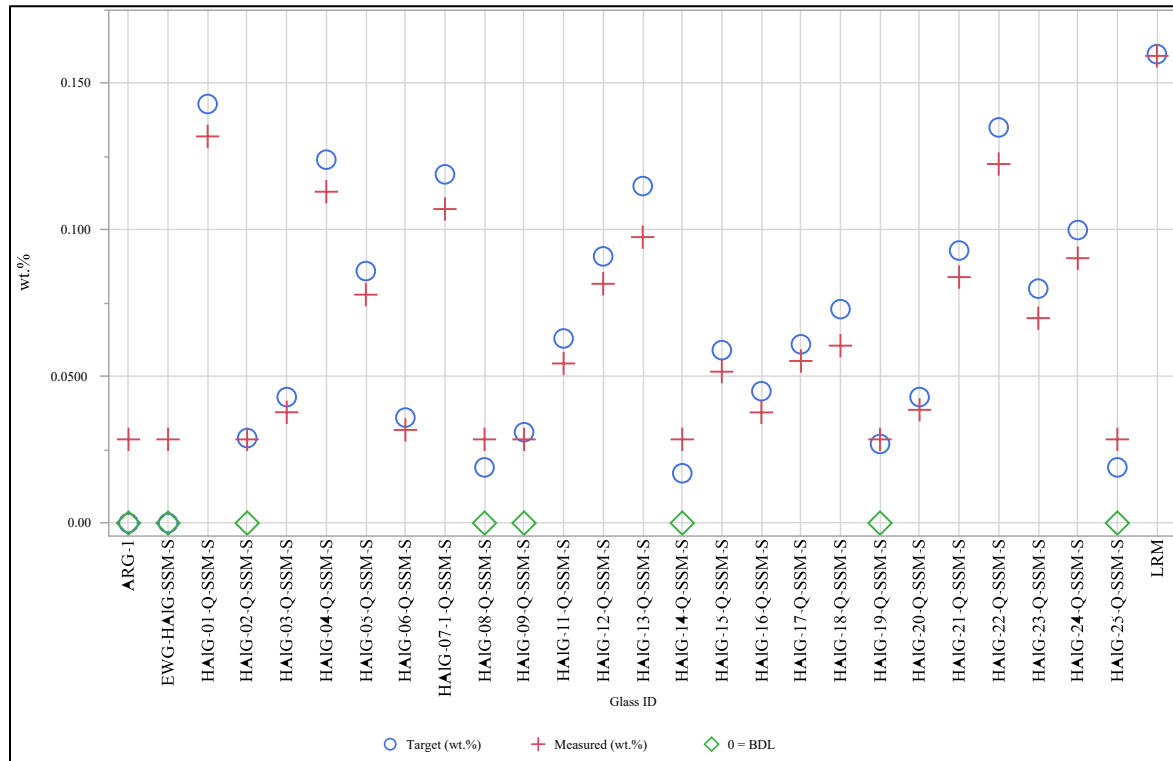


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide (continued)

Oxide=CdO



Oxide=Cr₂O₃

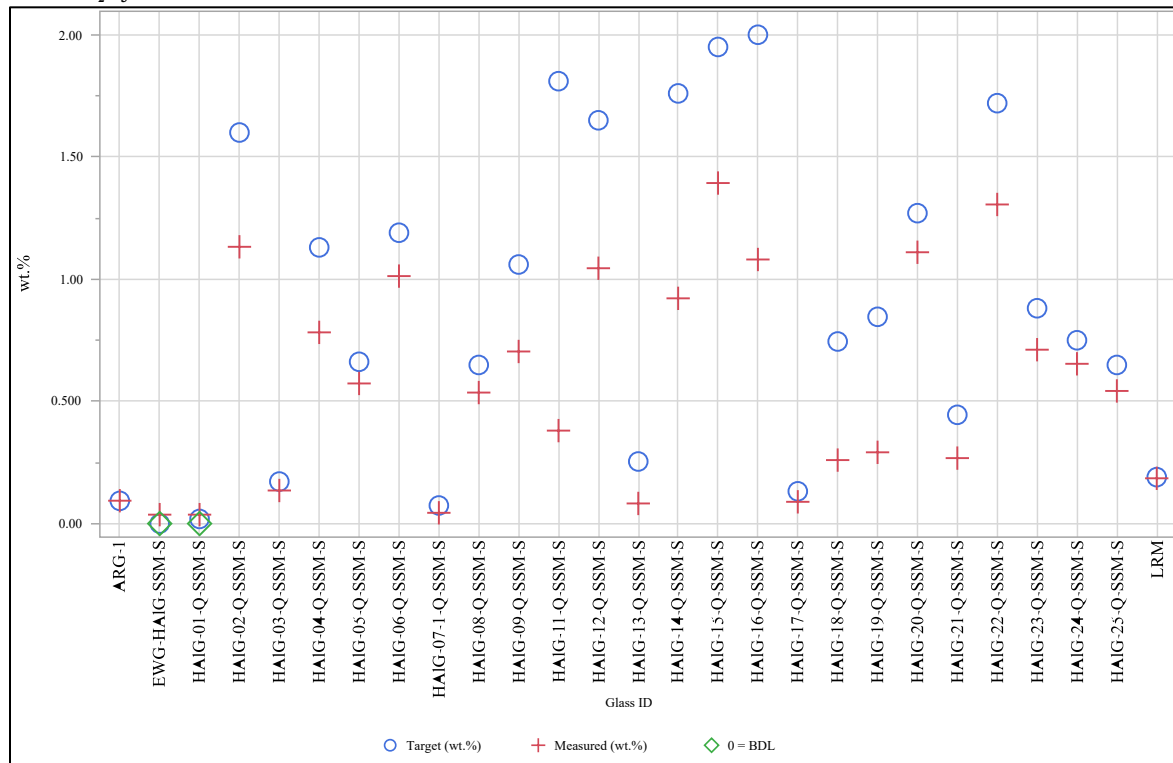
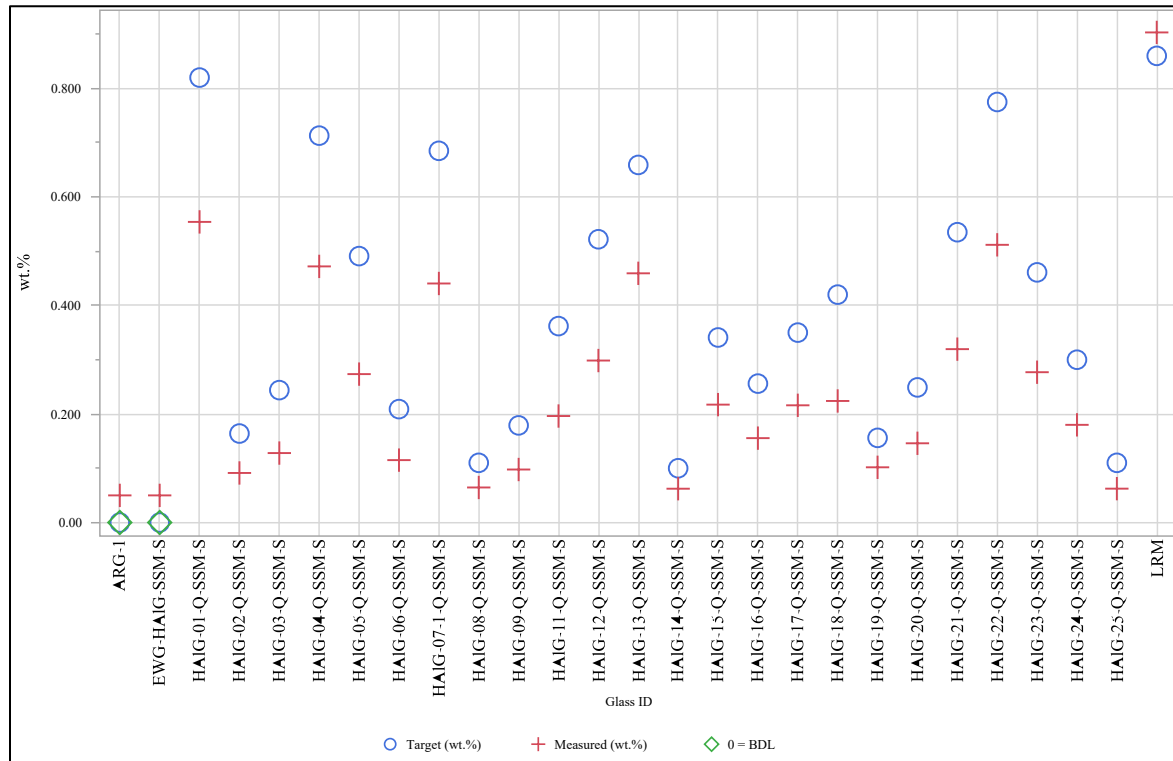


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide (continued)

Oxide=F⁻



Oxide=Fe₂O₃

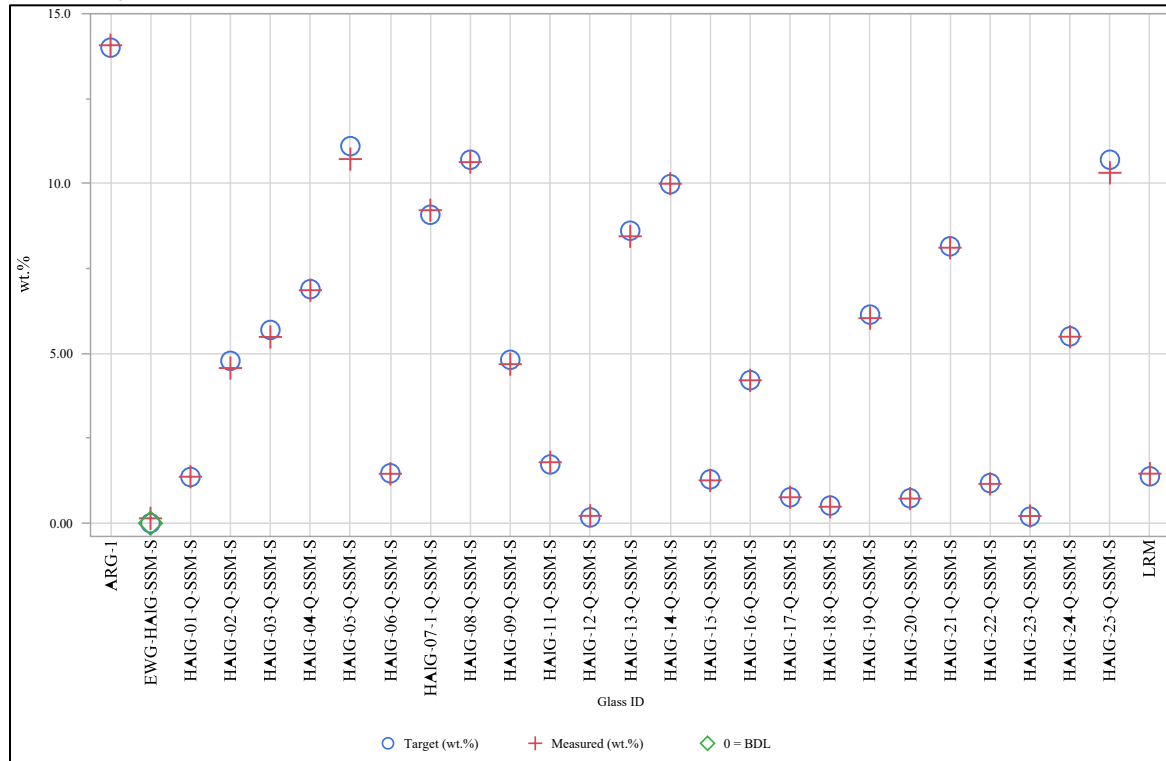
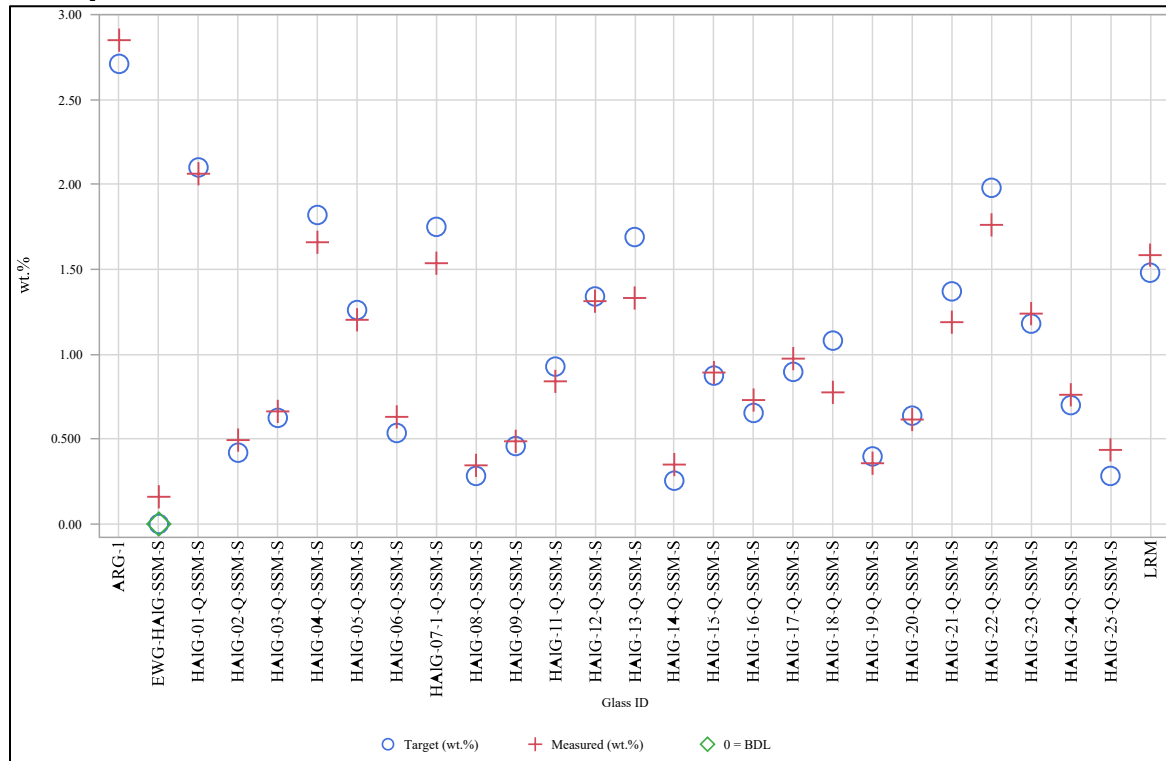


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide (continued)

Oxide= K_2O



Oxide= Li_2O

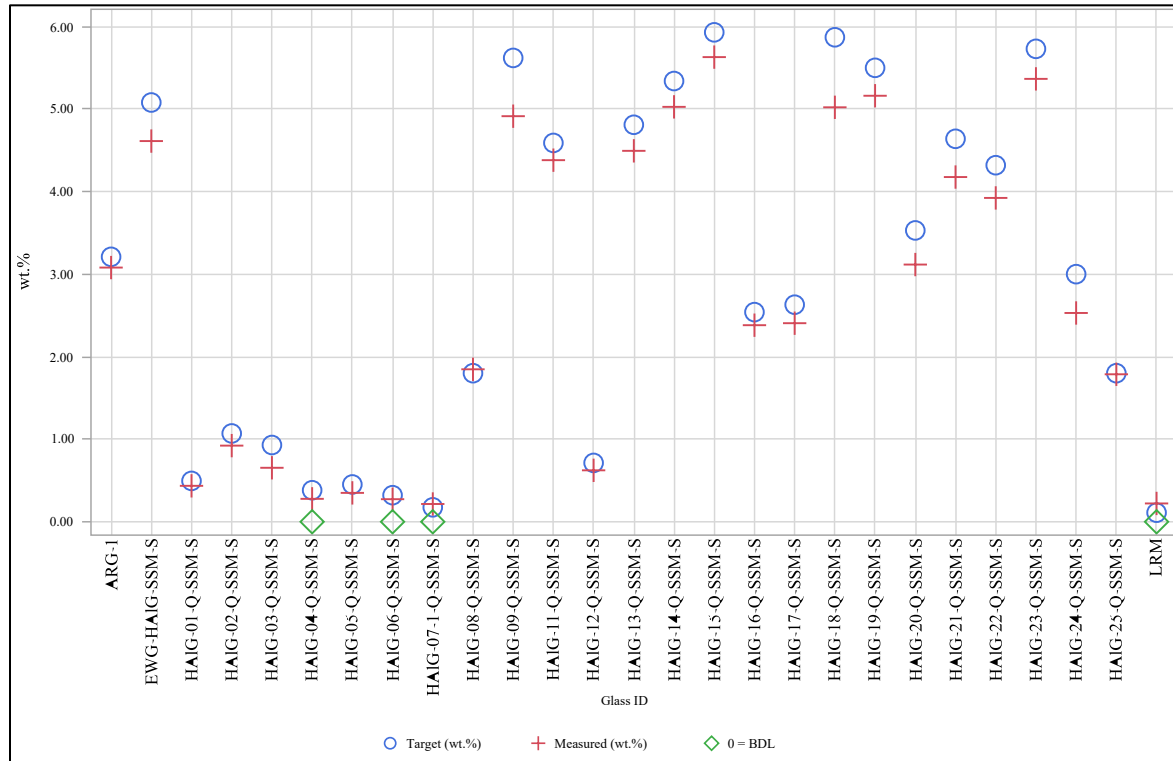
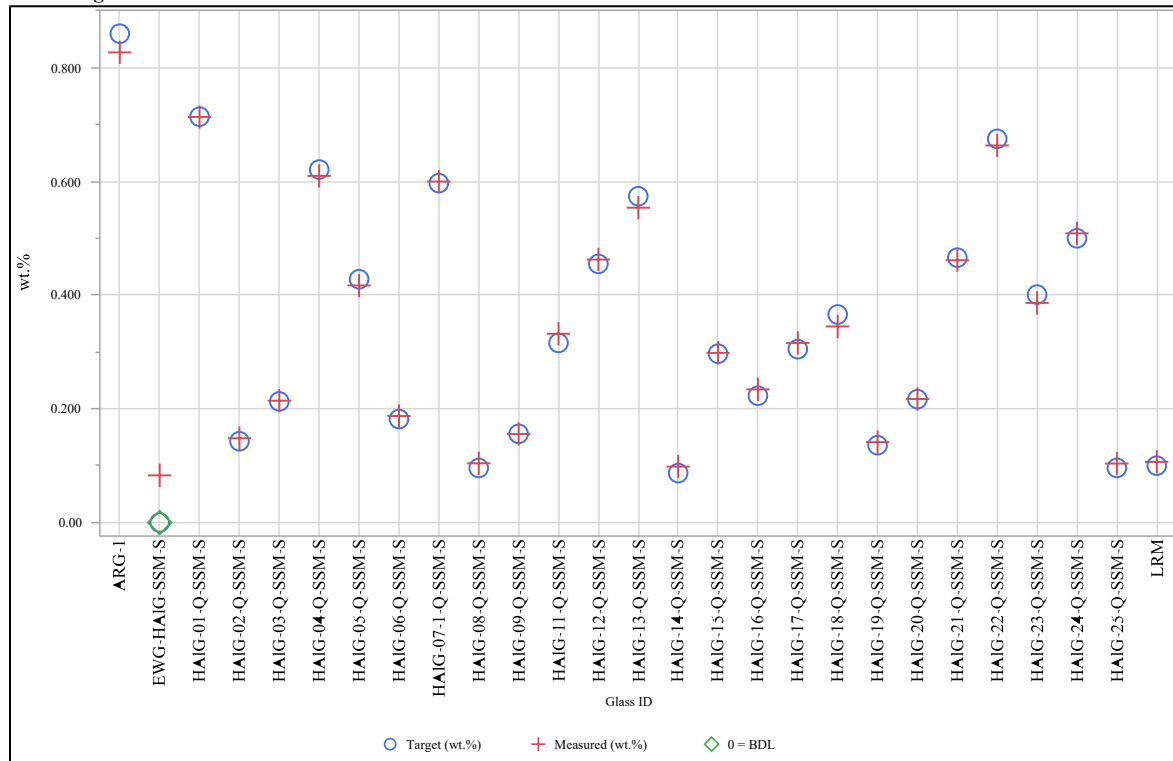


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide (continued)

Oxide=MgO



Oxide=MnO

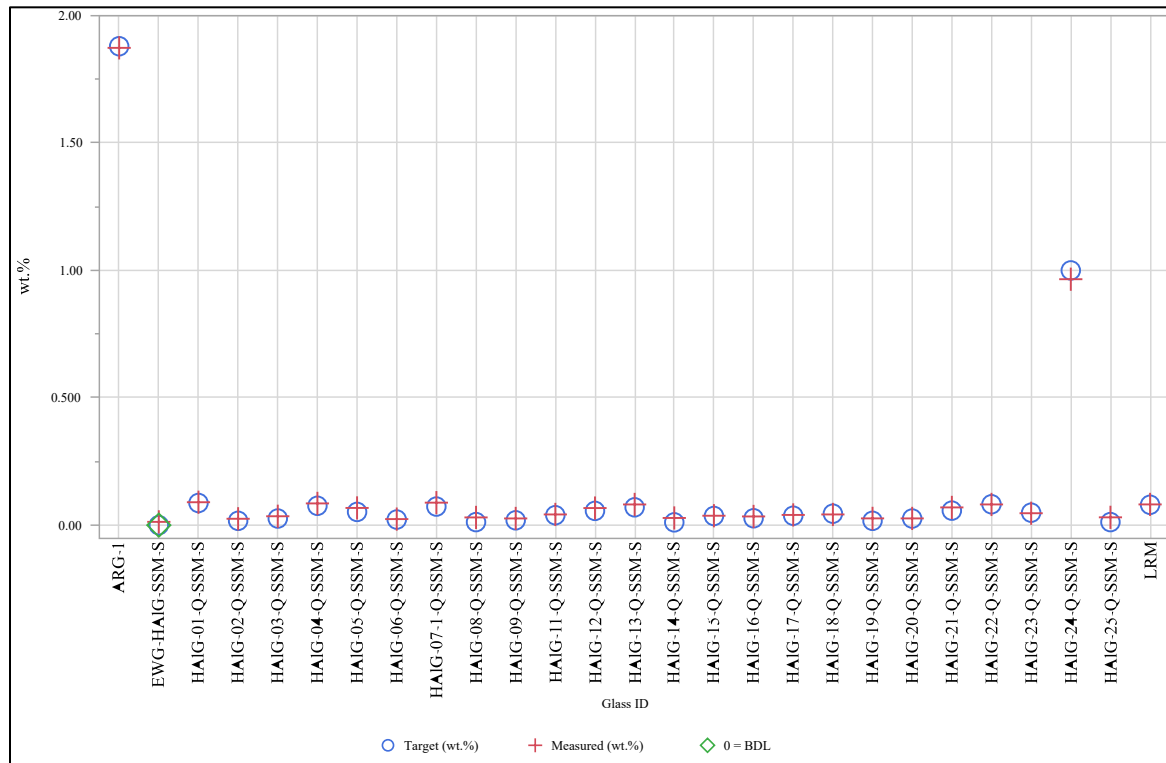
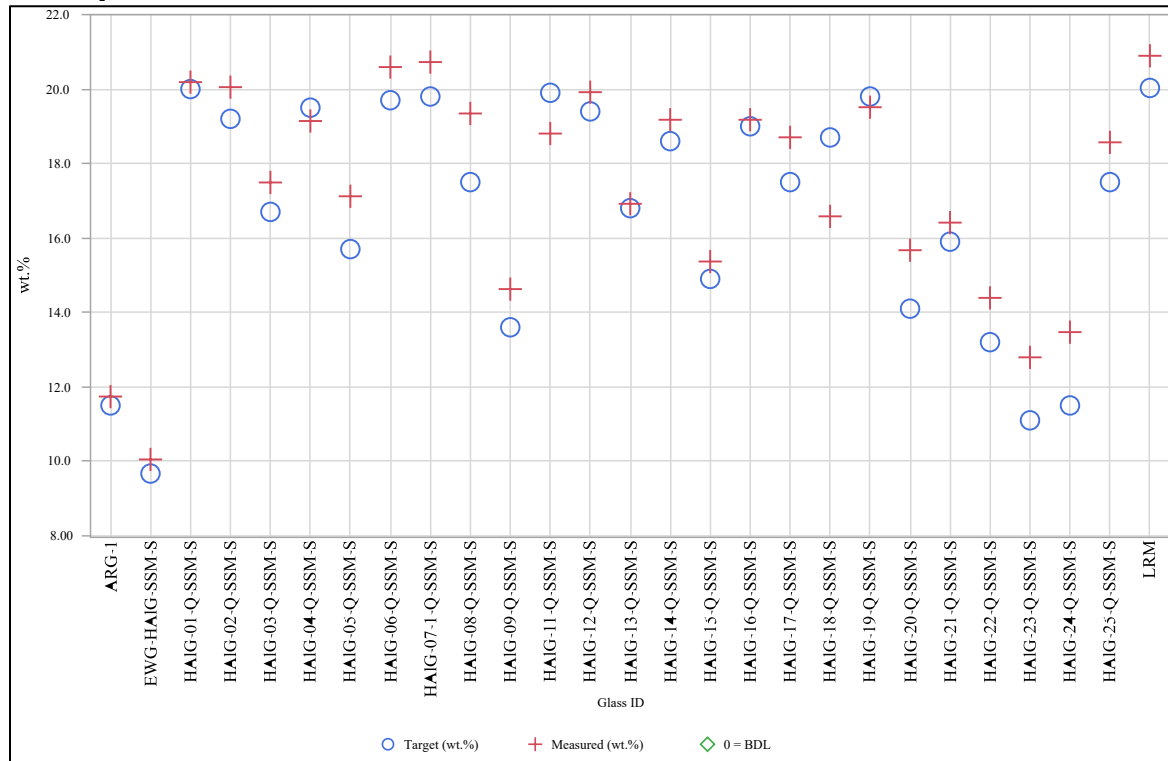


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide (continued)

Oxide= Na_2O



Oxide= NiO

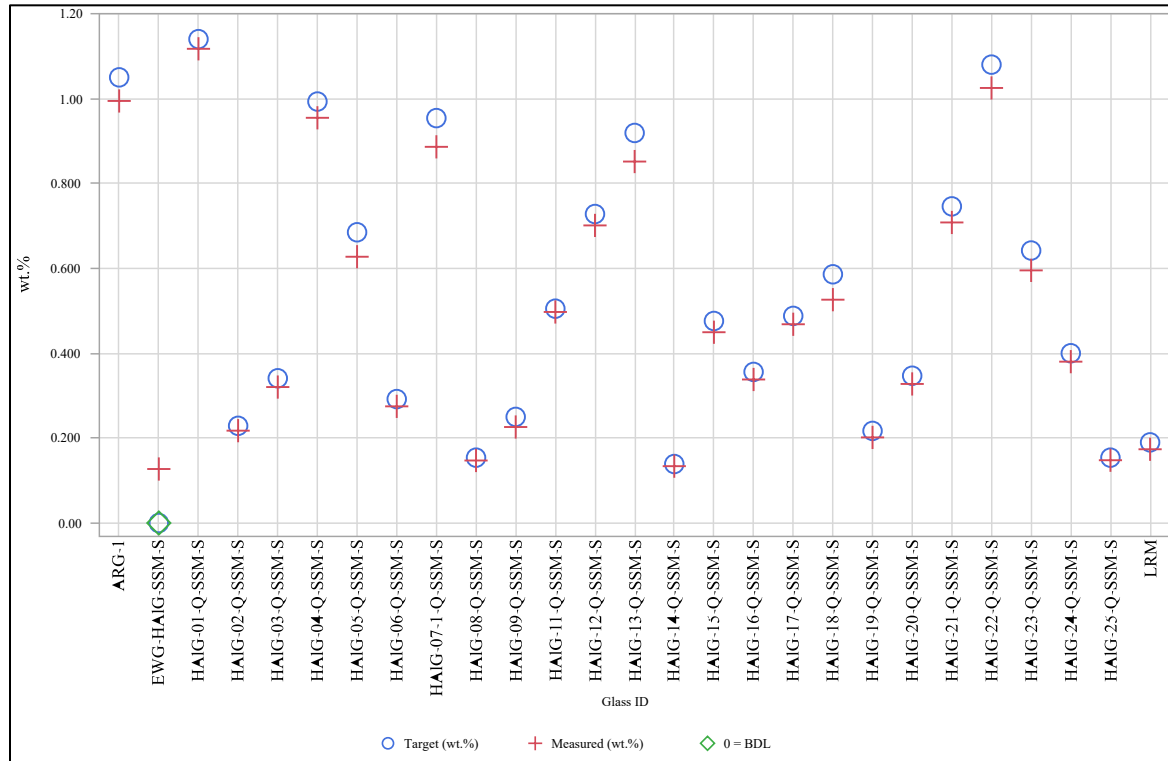
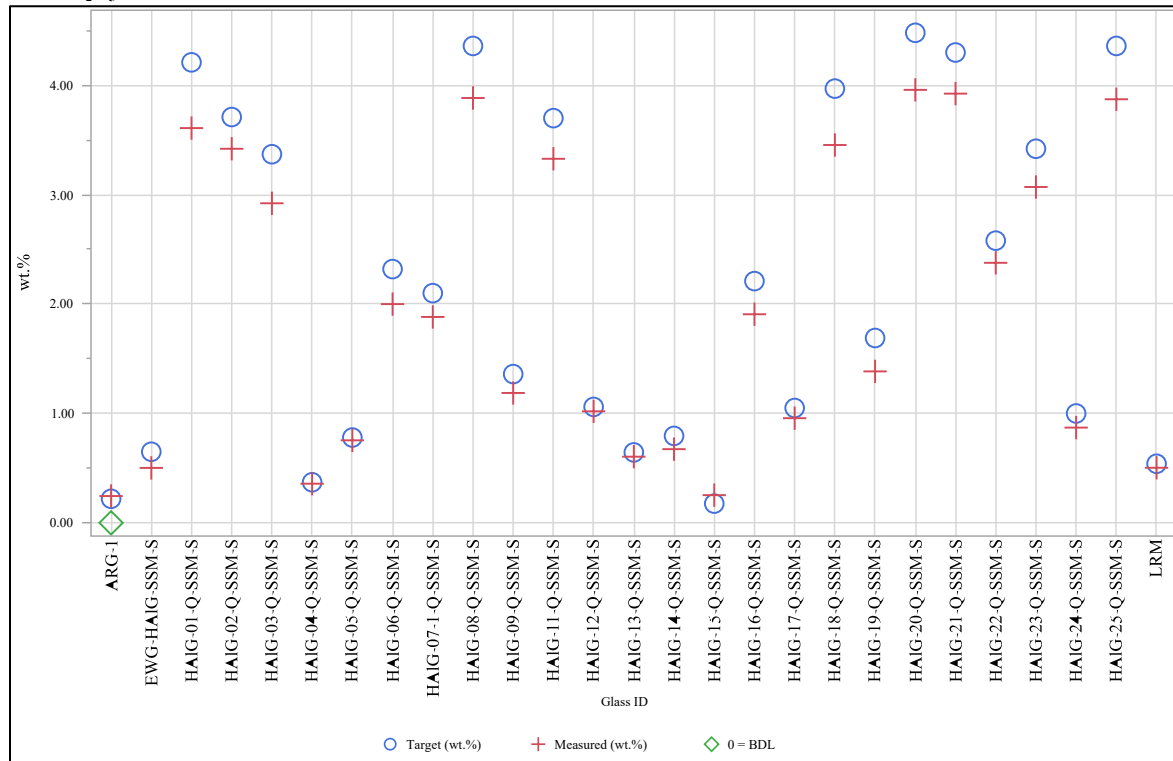


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide (continued)

Oxide= P_2O_5



Oxide= SiO_2

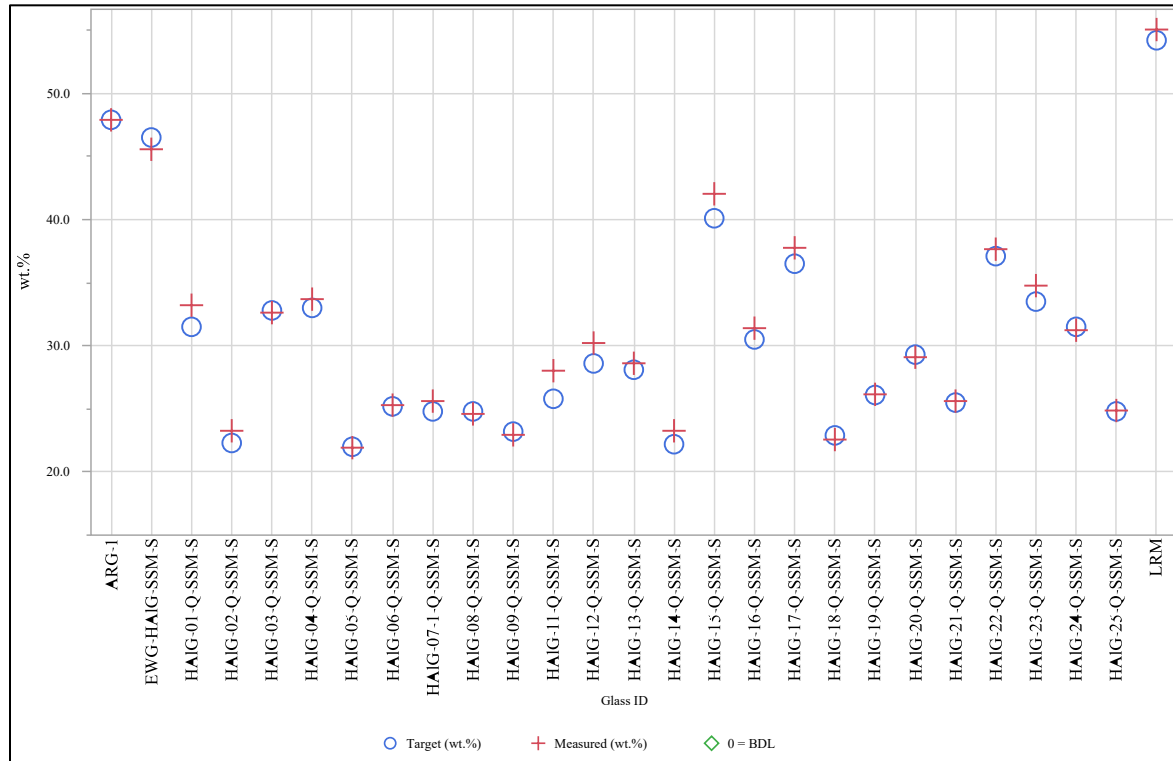
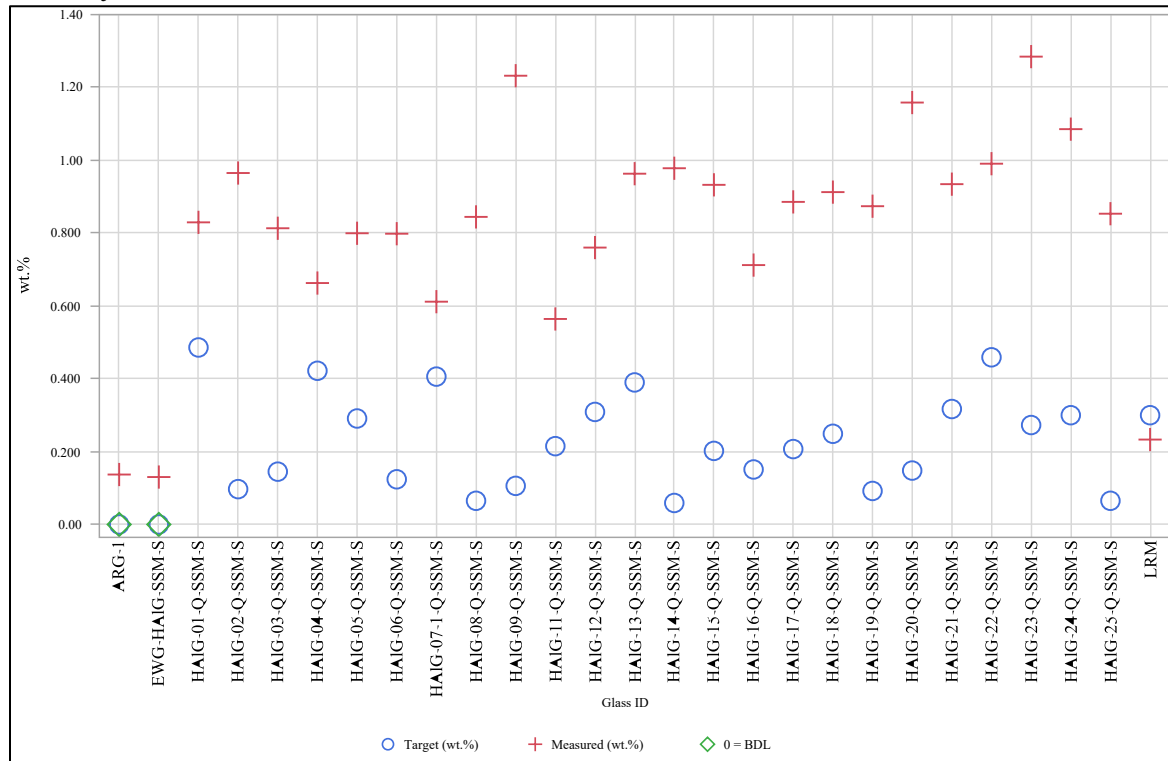


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide (continued)

Oxide= SO_3



Oxide= SrO

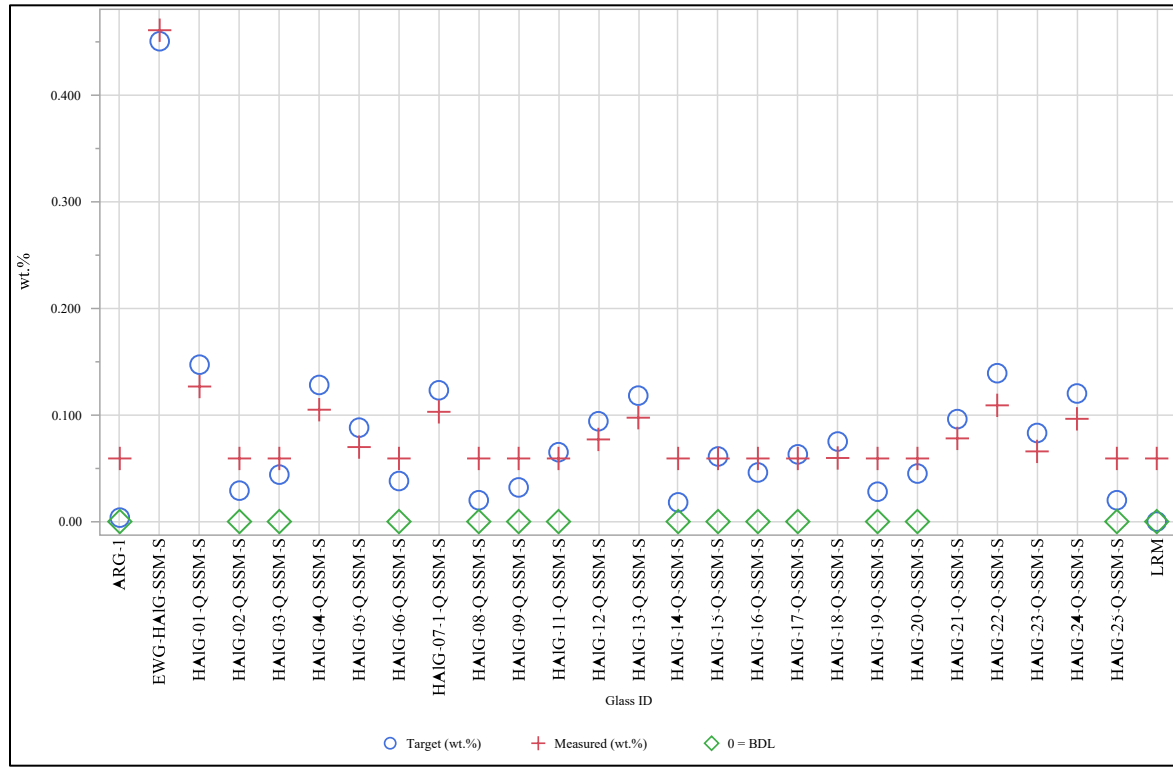
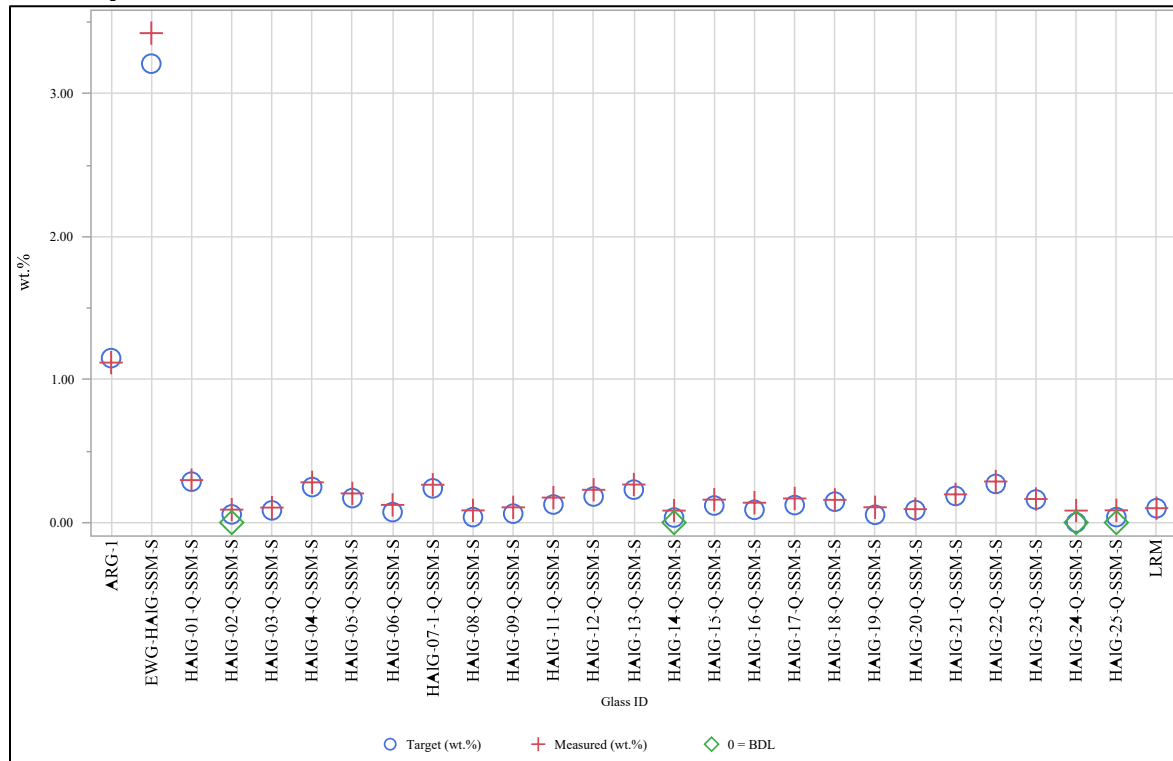


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide (continued)

Oxide=TiO₂



Oxide=ZnO

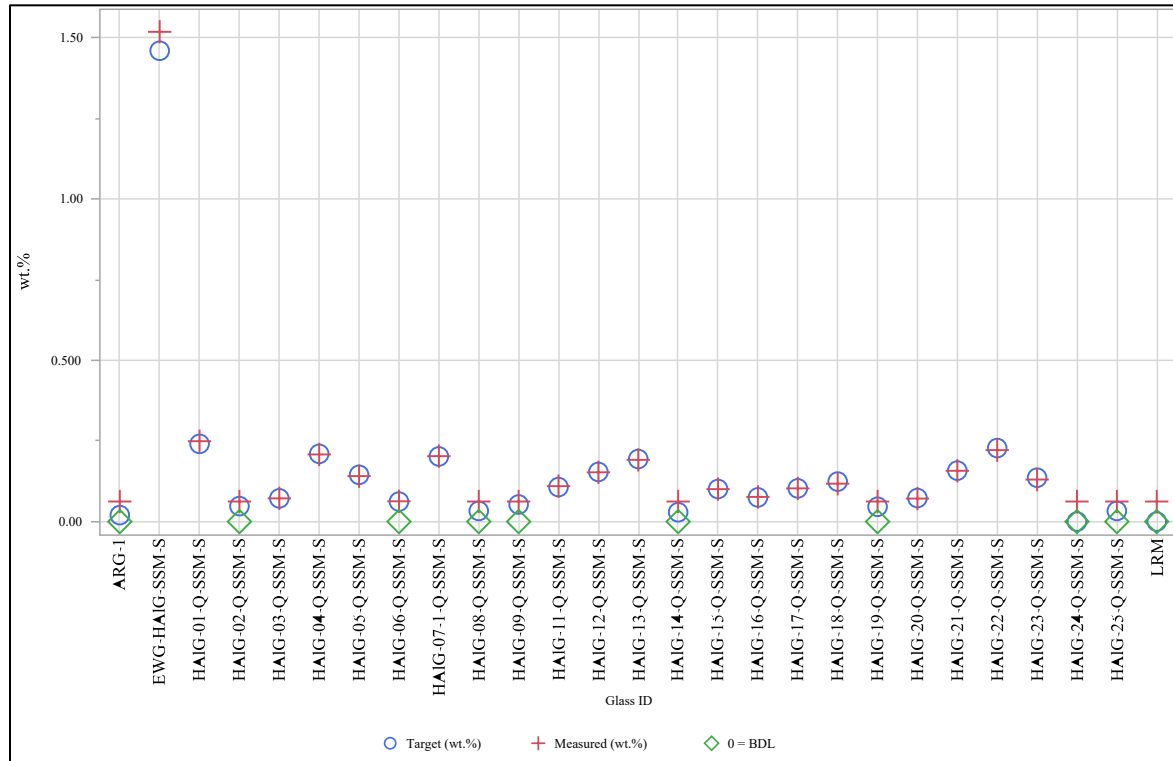


Exhibit A-3. Measured versus Targeted Concentrations by Glass ID by Oxide (continued)

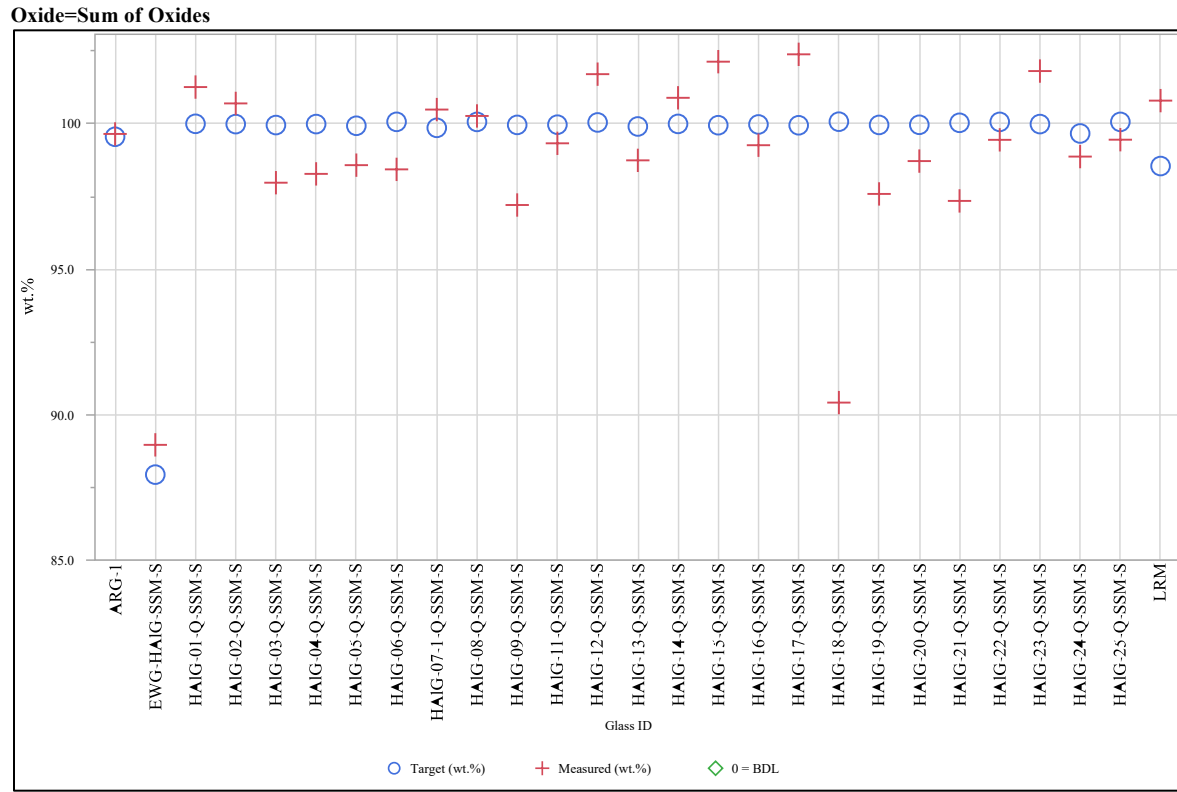
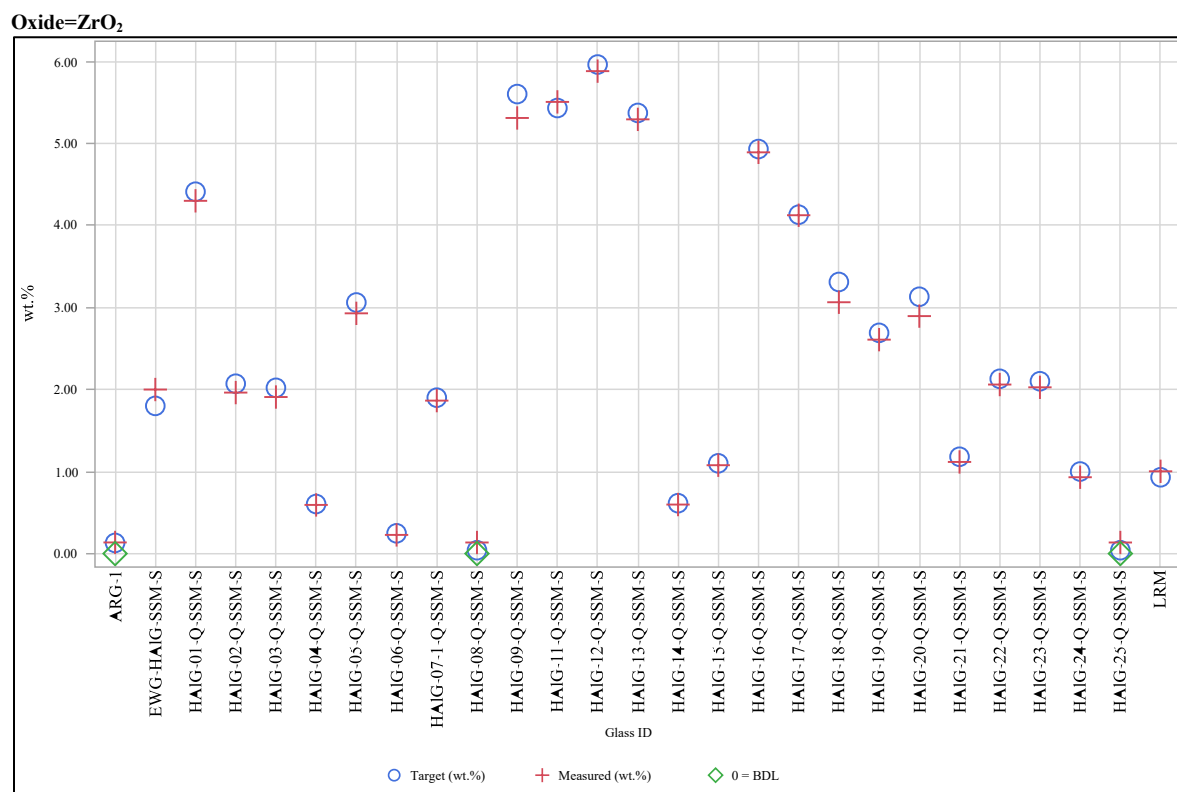
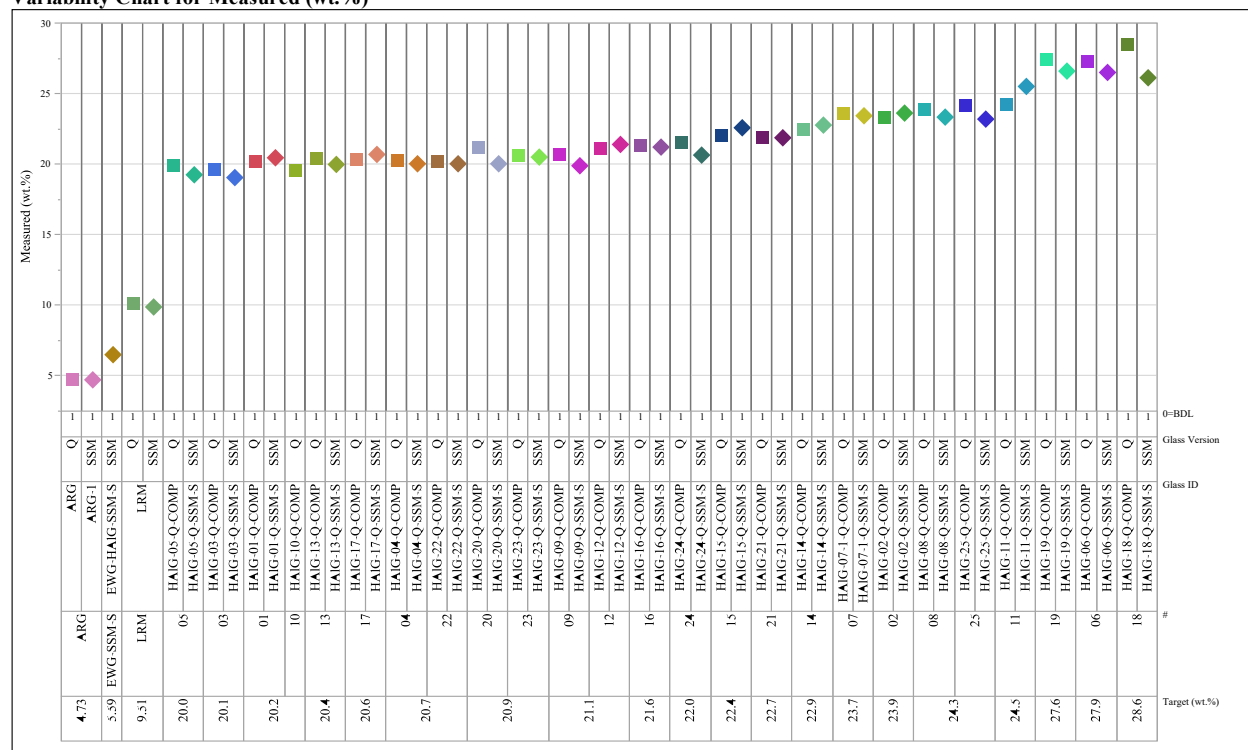


Exhibit A-4. Comparisons of the Measured Compositions of the Quenched and SSM Versions of the Study Glasses

Oxide=Al₂O₃

Variability Chart for Measured (wt.%)



Oxide=B₂O₃

Variability Chart for Measured (wt.%)

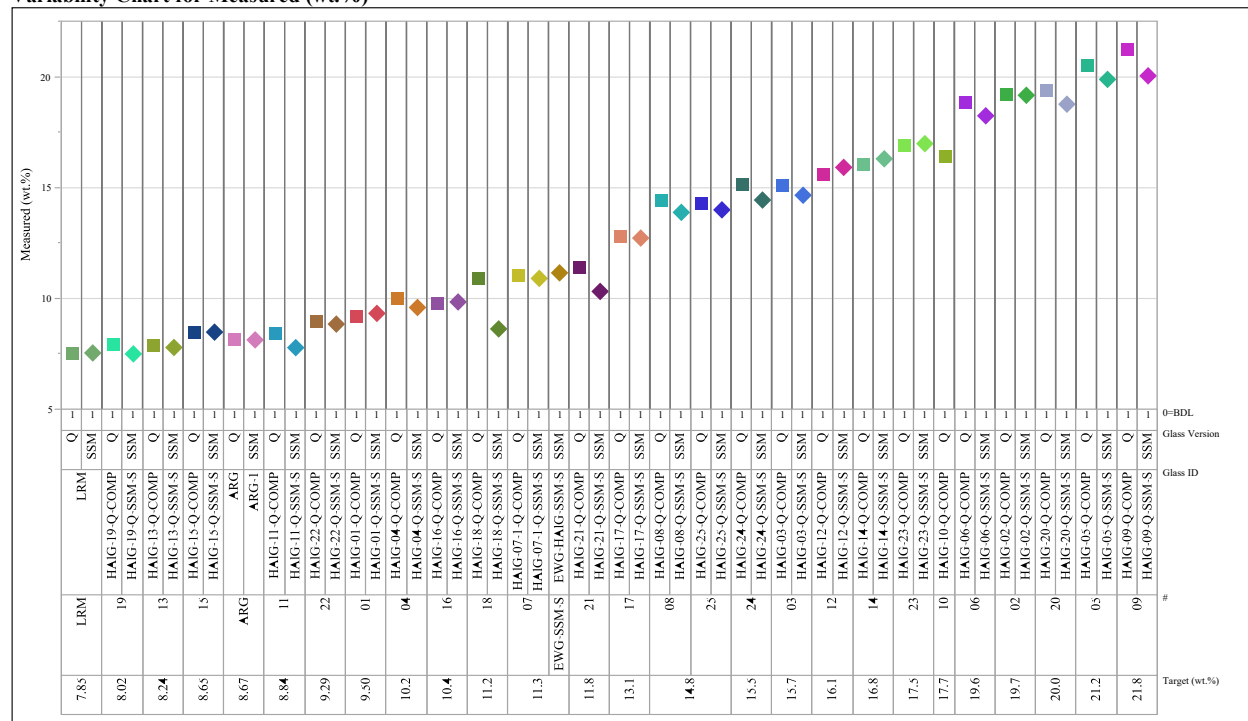
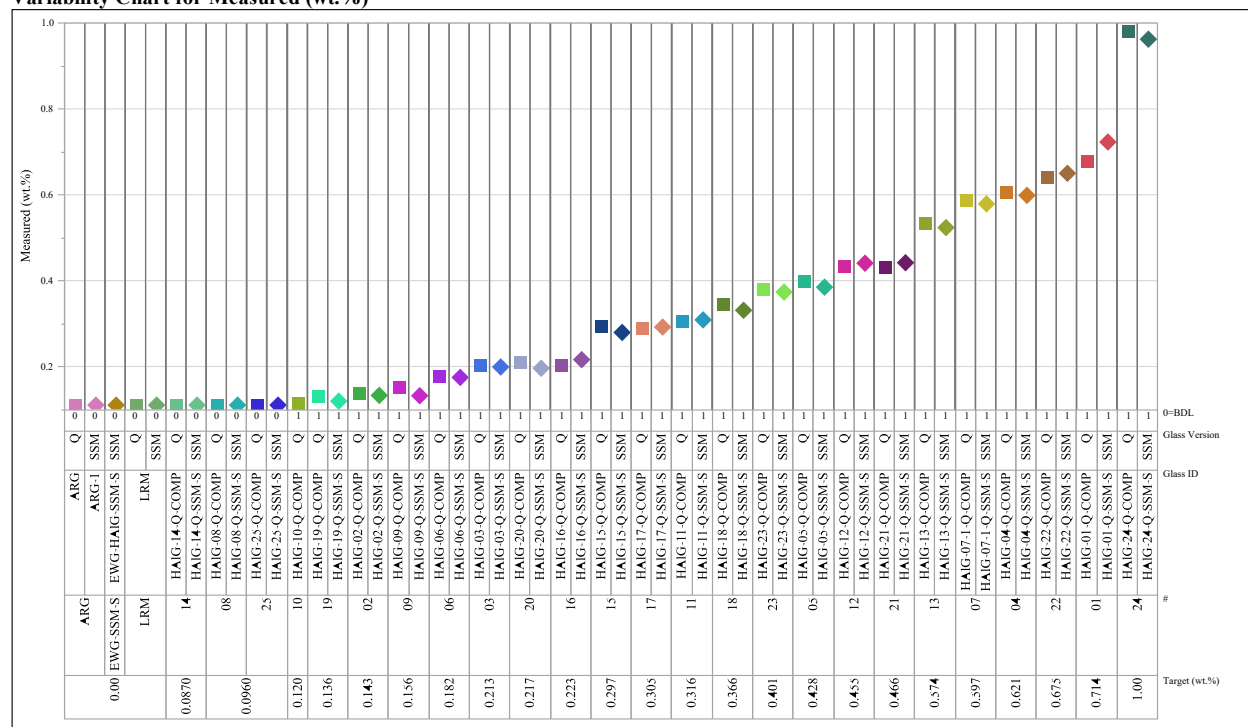


Exhibit A-4. Comparisons of the Measured Compositions of the Quenched and SSM Versions of the Study Glasses (continued)

Oxide=Bi₂O₃

Variability Chart for Measured (wt.%)



Oxide=CaO

Variability Chart for Measured (wt.%)

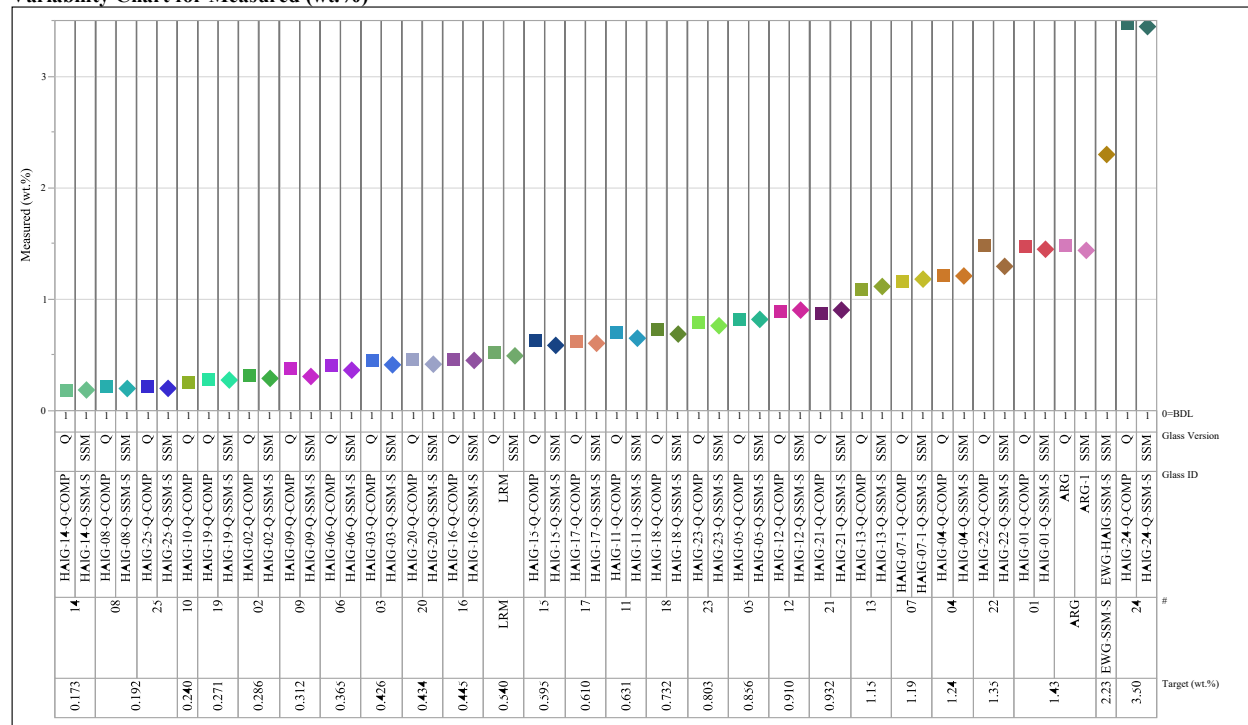
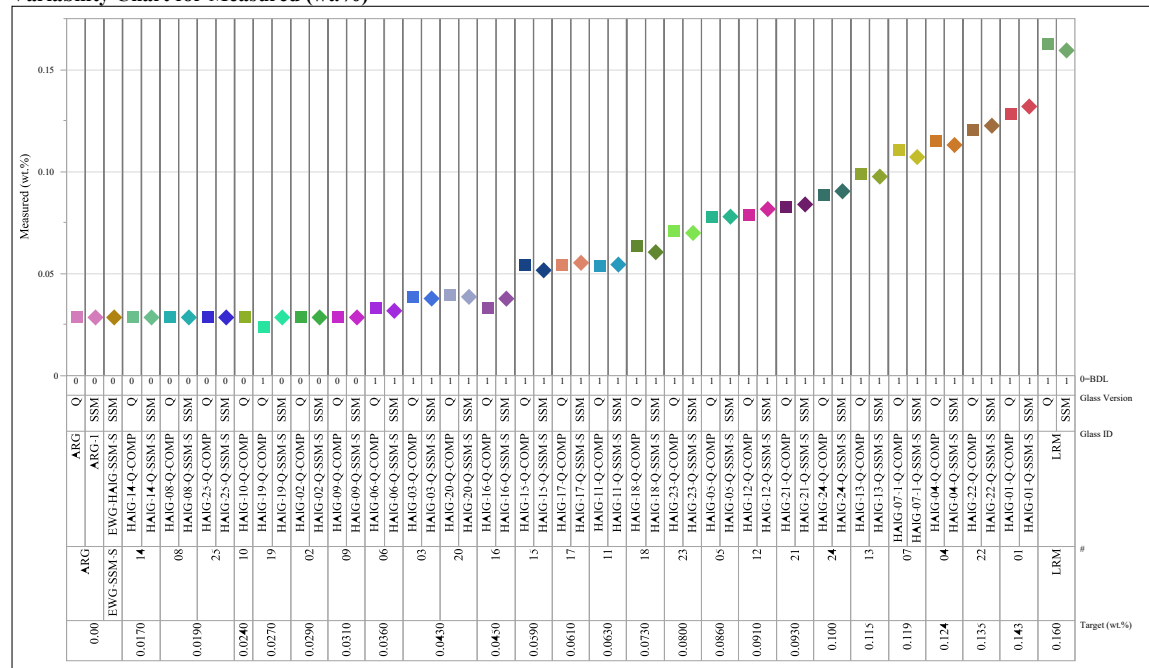


Exhibit A-4. Comparisons of the Measured Compositions of the Quenched and SSM Versions of the Study Glasses (continued)

Oxide=CdO

Variability Chart for Measured (wt.%)



Oxide=Cr₂O₃

Variability Chart for Measured (wt.%)

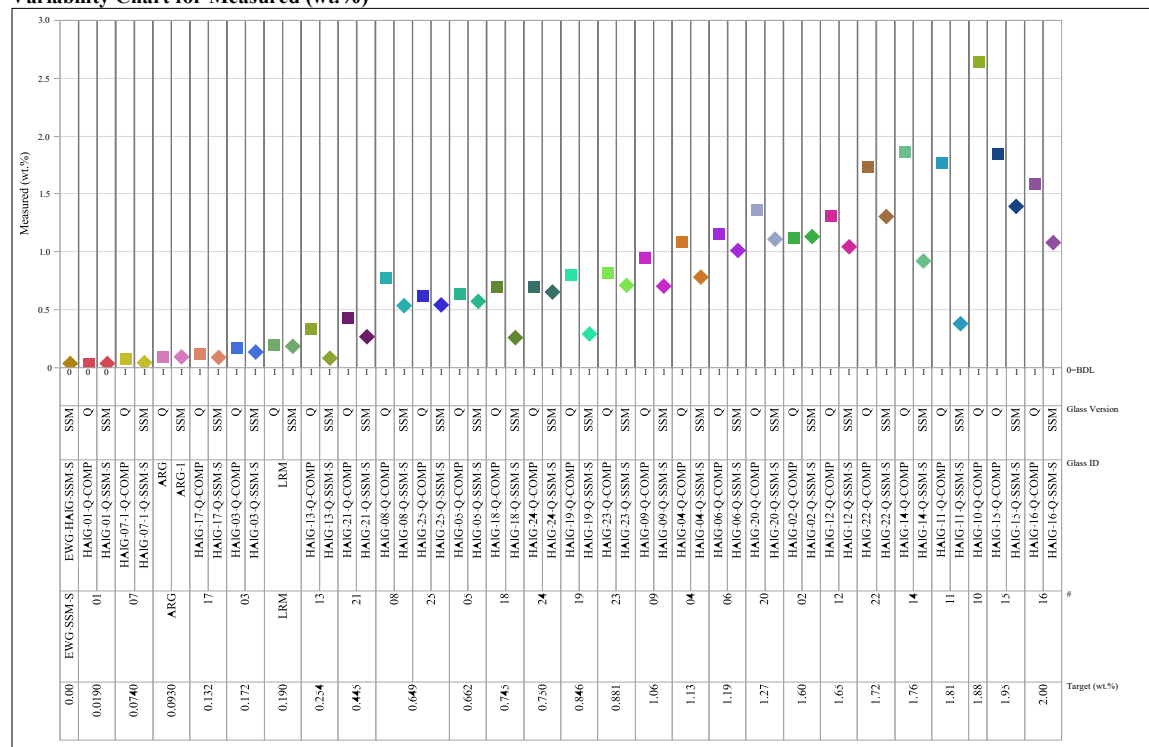
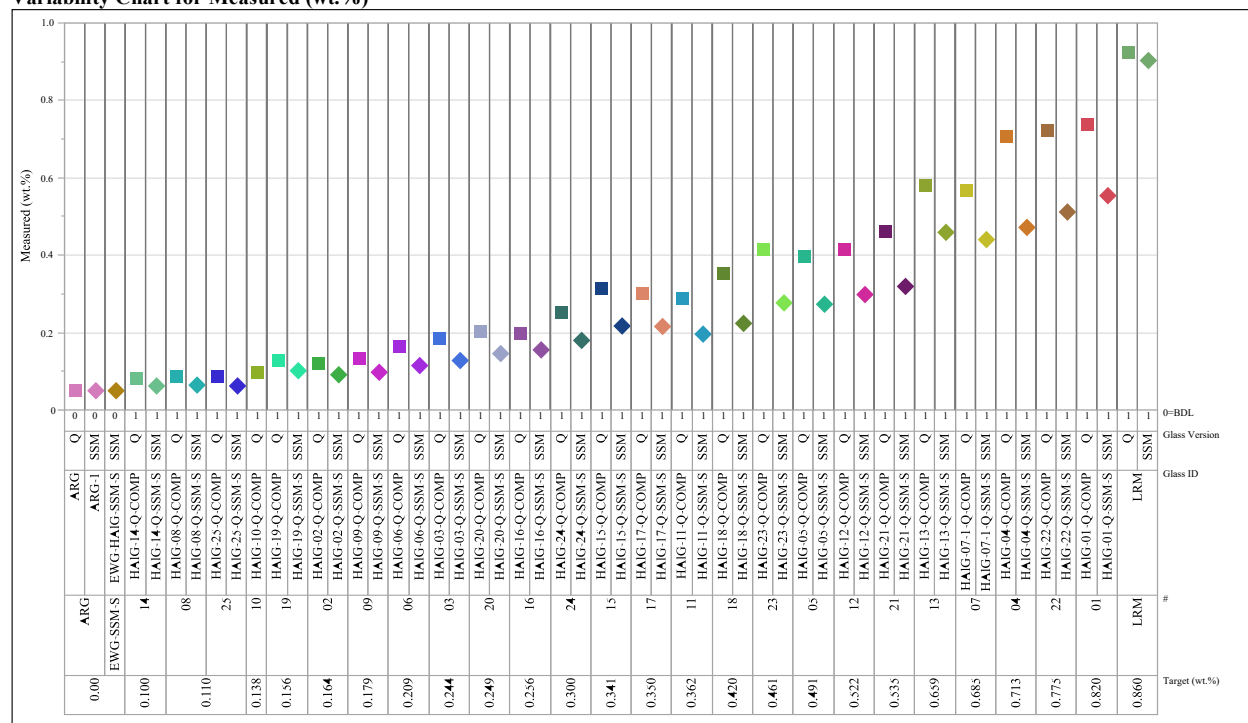


Exhibit A-4. Comparisons of the Measured Compositions of the Quenched and SSM Versions of the Study Glasses (continued)

Oxide=F⁻

Variability Chart for Measured (wt.%)



Oxide=Fe₂O₃

Variability Chart for Measured (wt.%)

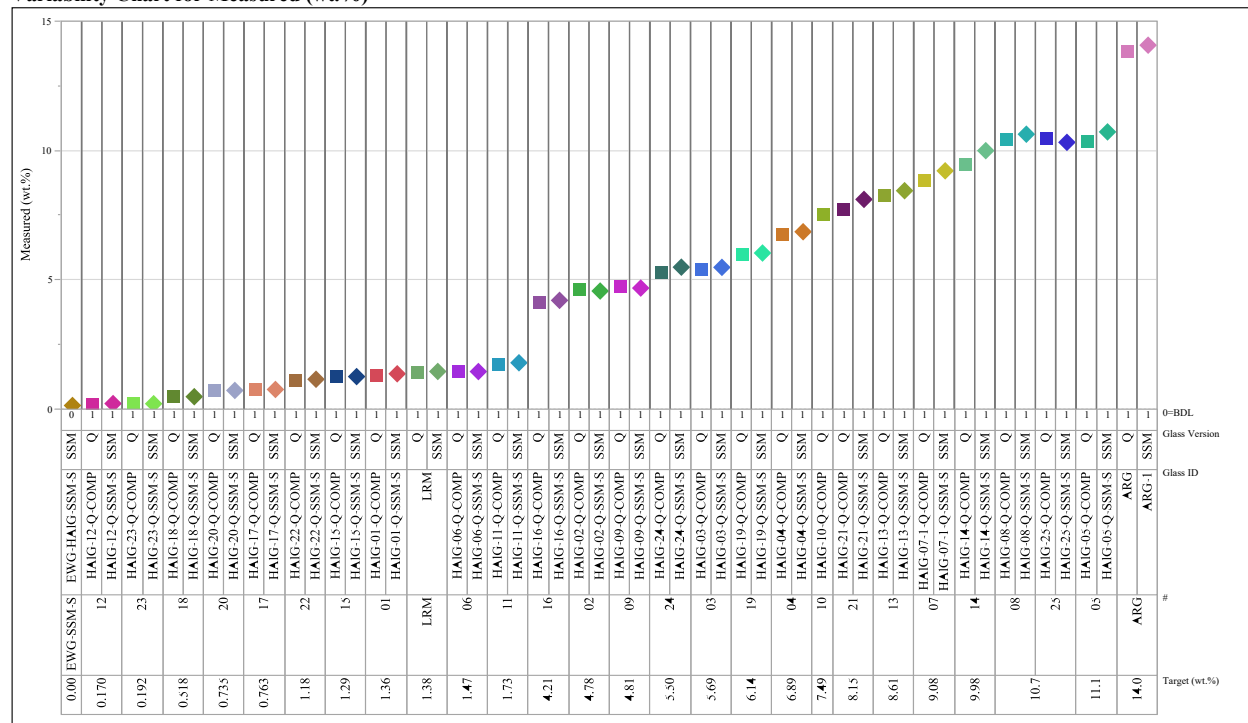
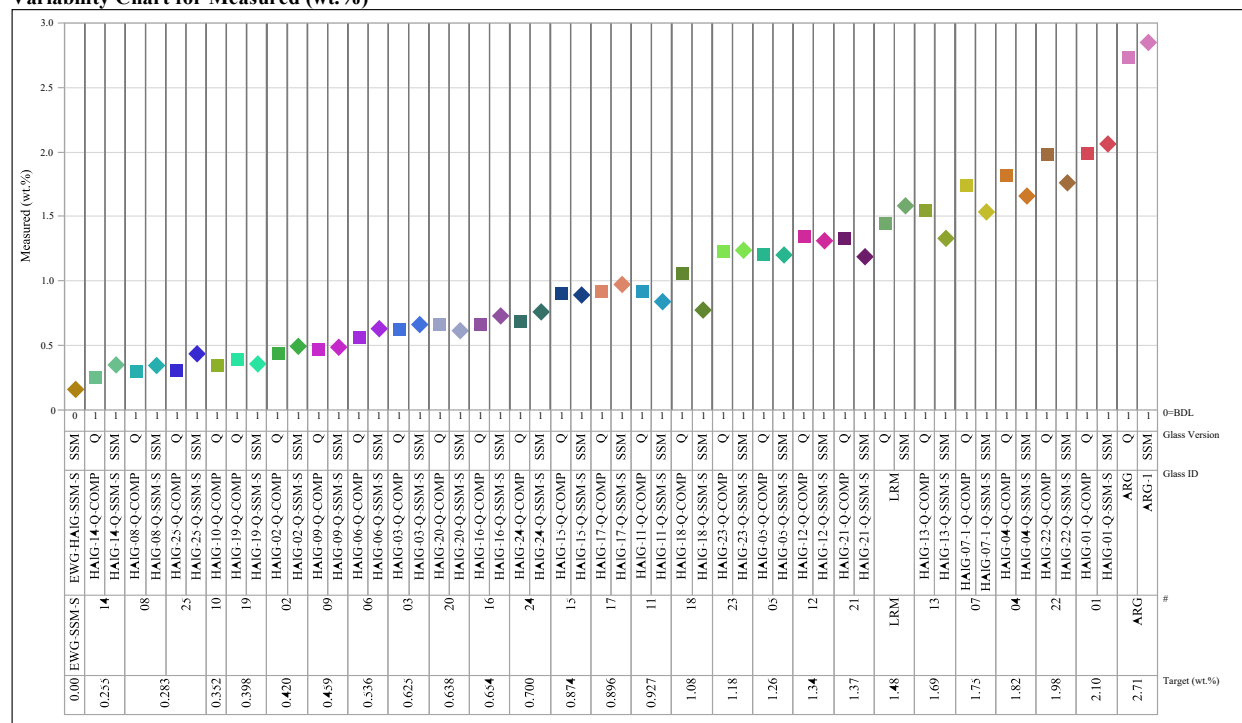


Exhibit A-4. Comparisons of the Measured Compositions of the Quenched and SSM Versions of the Study Glasses (continued)

Oxide=K₂O

Variability Chart for Measured (wt.%)



Oxide=Li₂O

Variability Chart for Measured (wt.%)

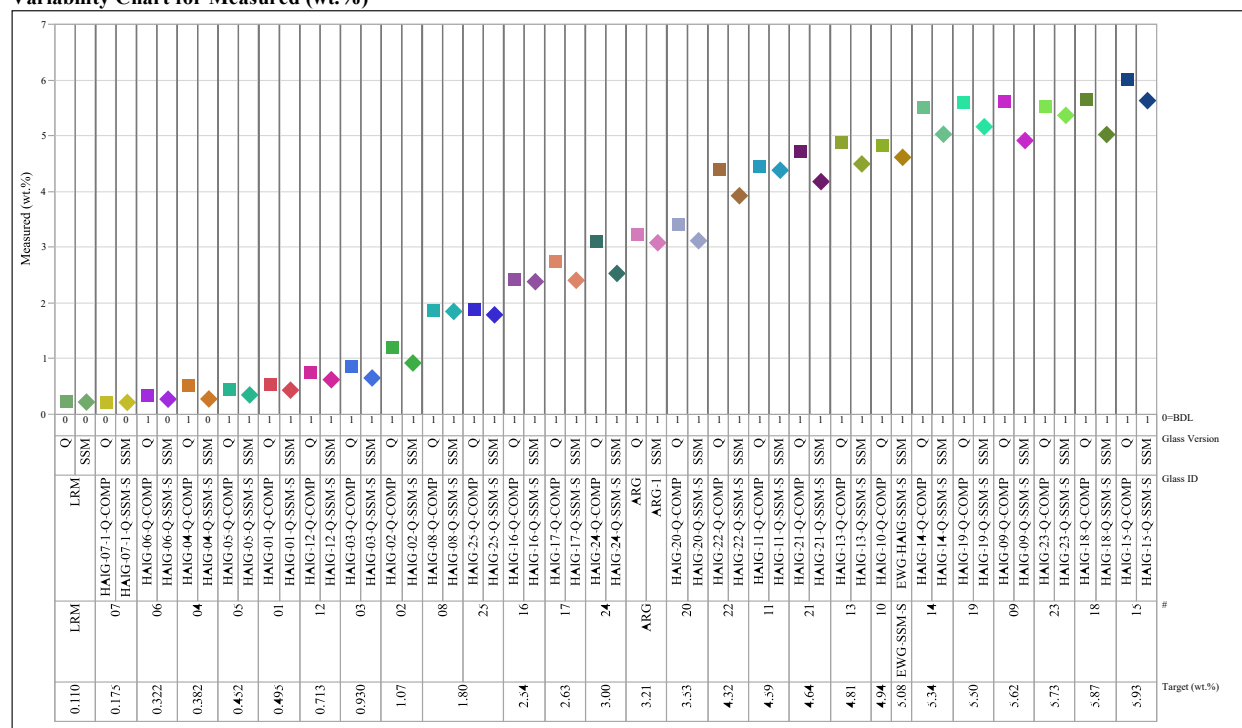
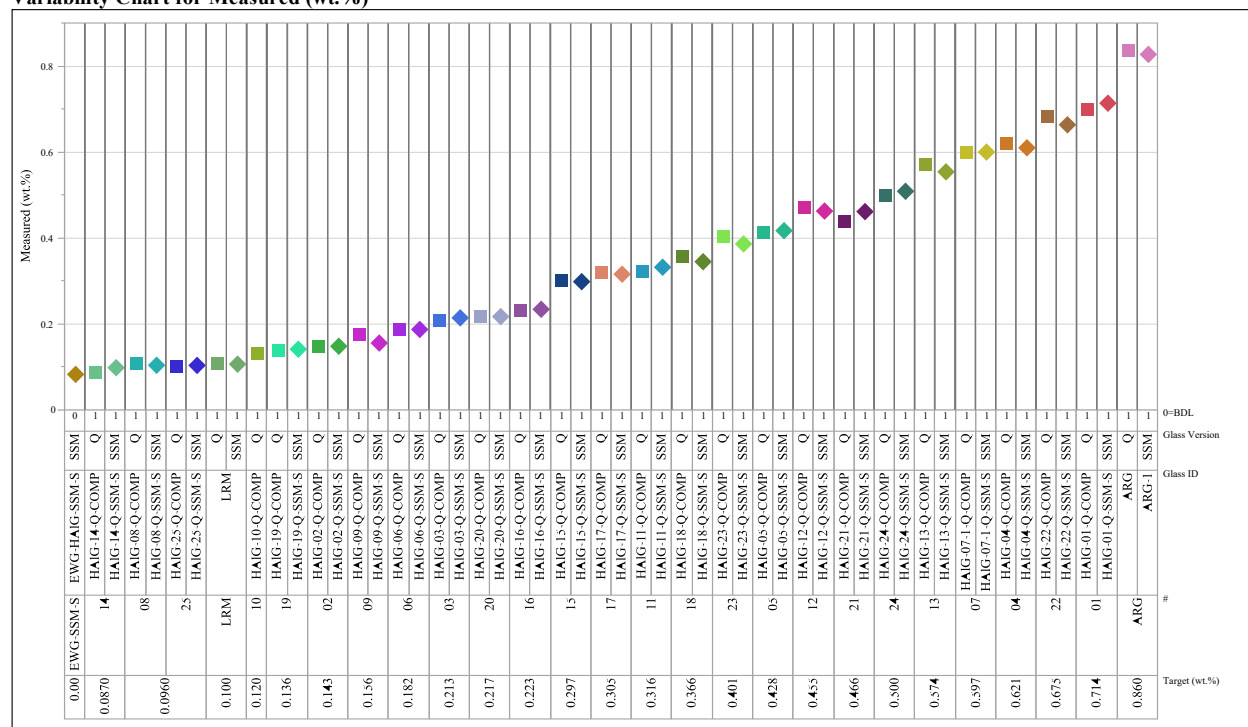


Exhibit A-4. Comparisons of the Measured Compositions of the Quenched and SSM Versions of the Study Glasses (continued)

Oxide=MgO

Variability Chart for Measured (wt.%)



Oxide=MnO

Variability Chart for Measured (wt.%)

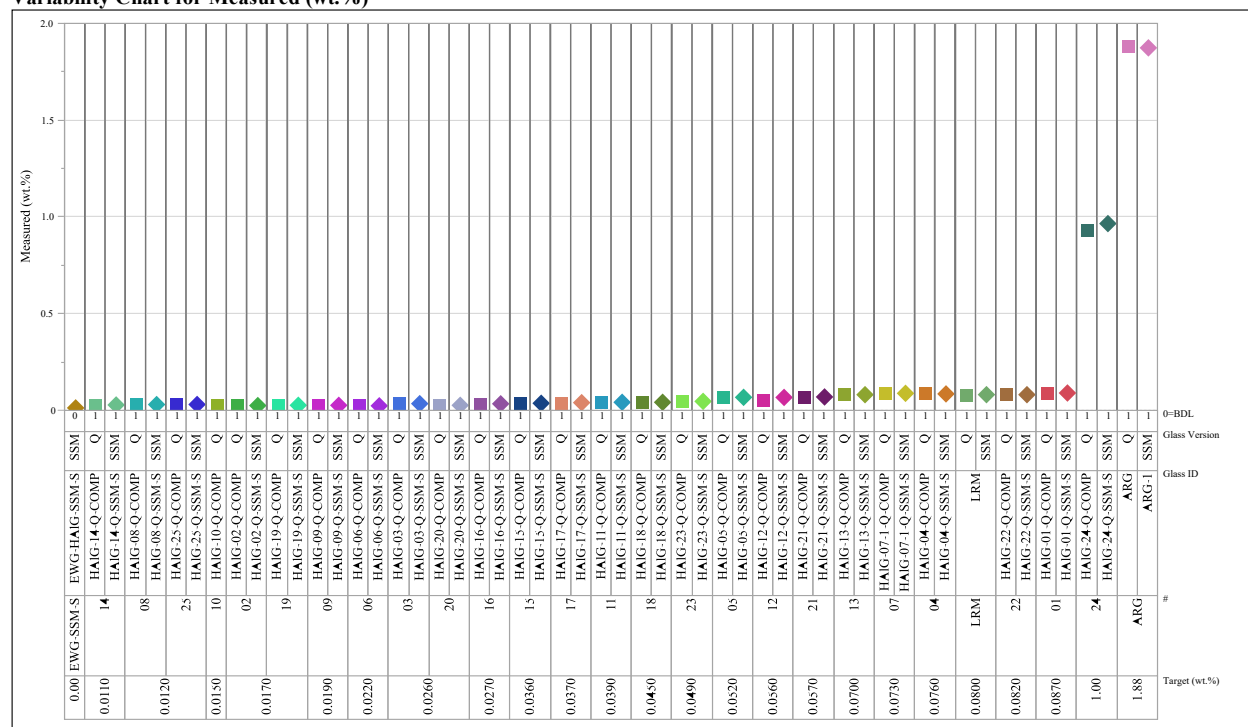
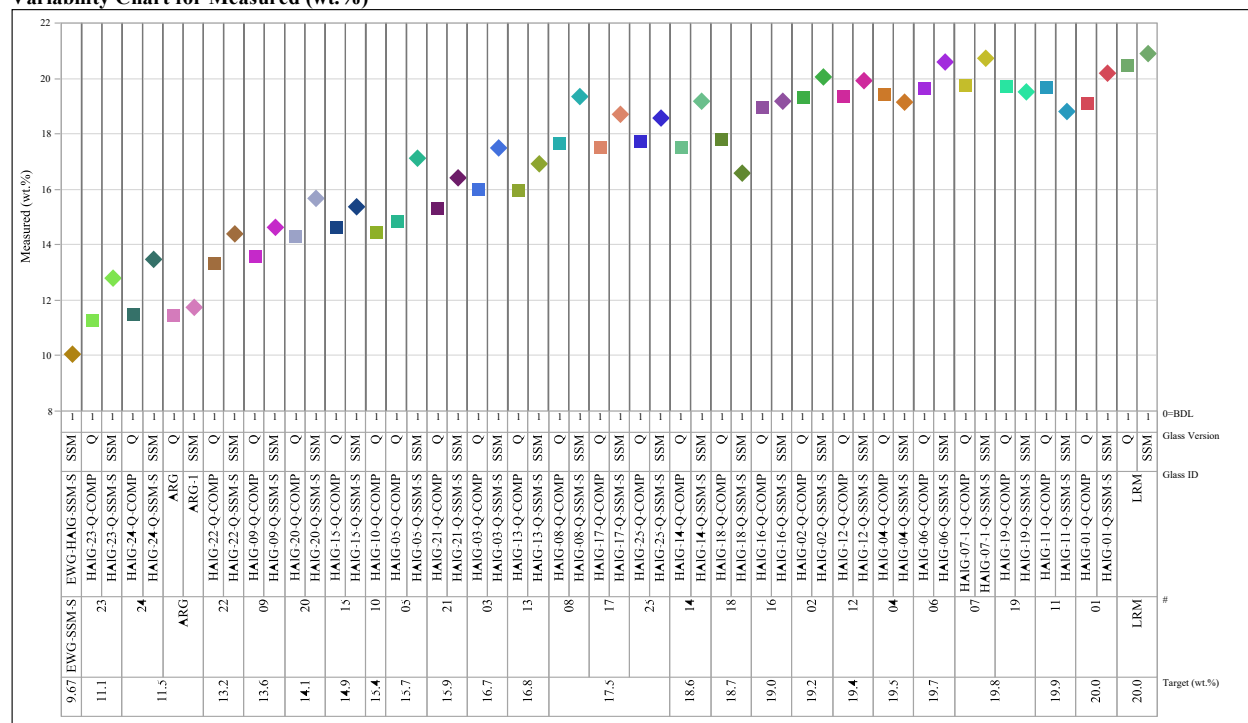


Exhibit A-4. Comparisons of the Measured Compositions of the Quenched and SSM Versions of the Study Glasses (continued)

Oxide= Na_2O

Variability Chart for Measured (wt.%)



Oxide= NiO

Variability Chart for Measured (wt.%)

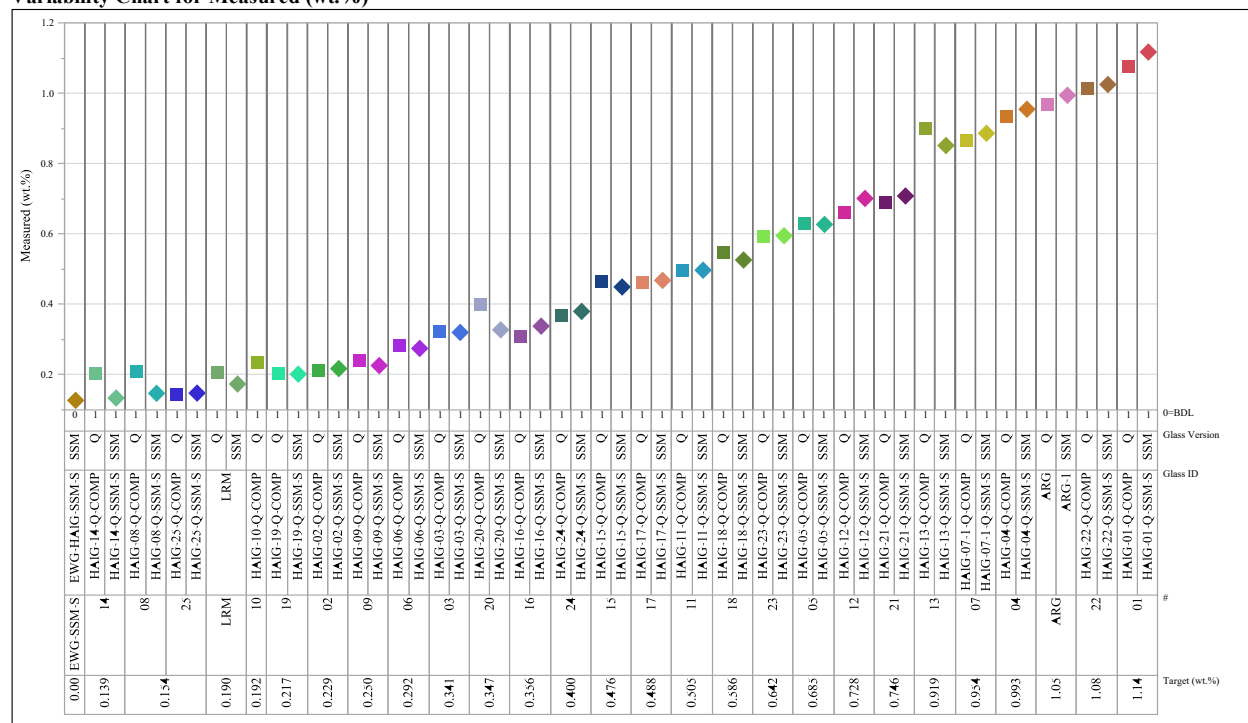
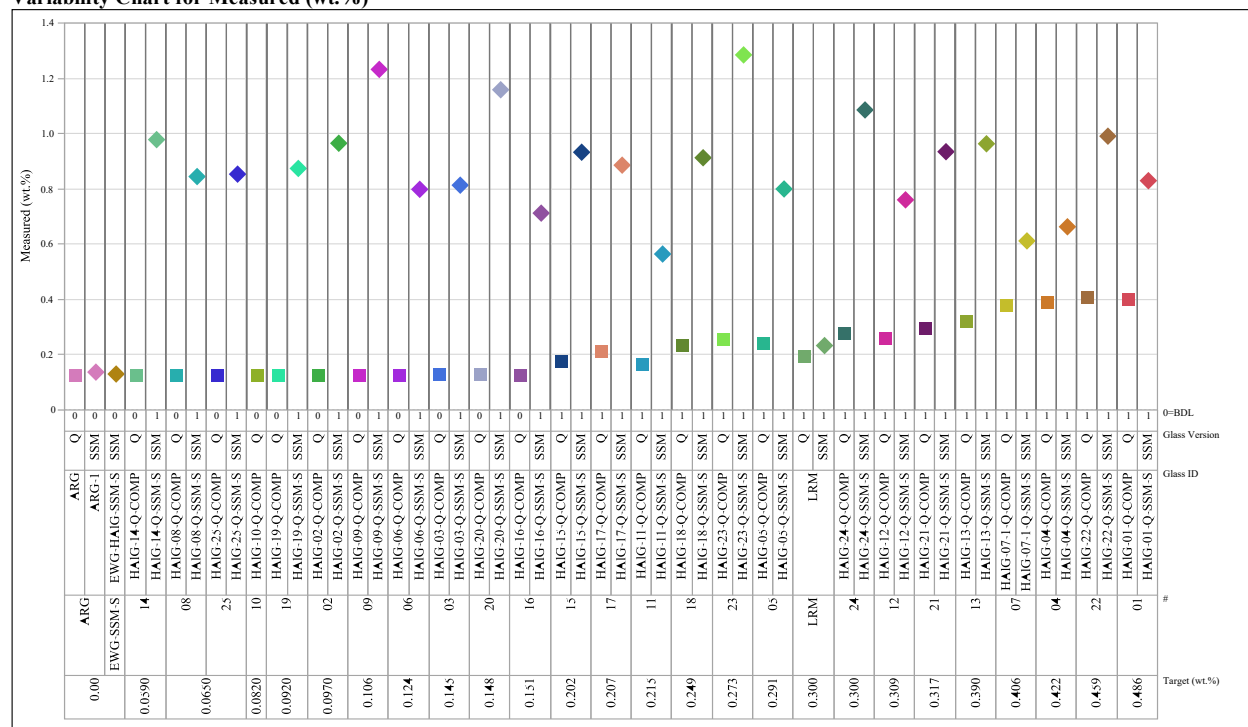


Exhibit A-4. Comparisons of the Measured Compositions of the Quenched and SSM Versions of the Study Glasses (continued)

Oxide=SO₃

Variability Chart for Measured (wt.%)



Oxide=SrO

Variability Chart for Measured (wt.%)

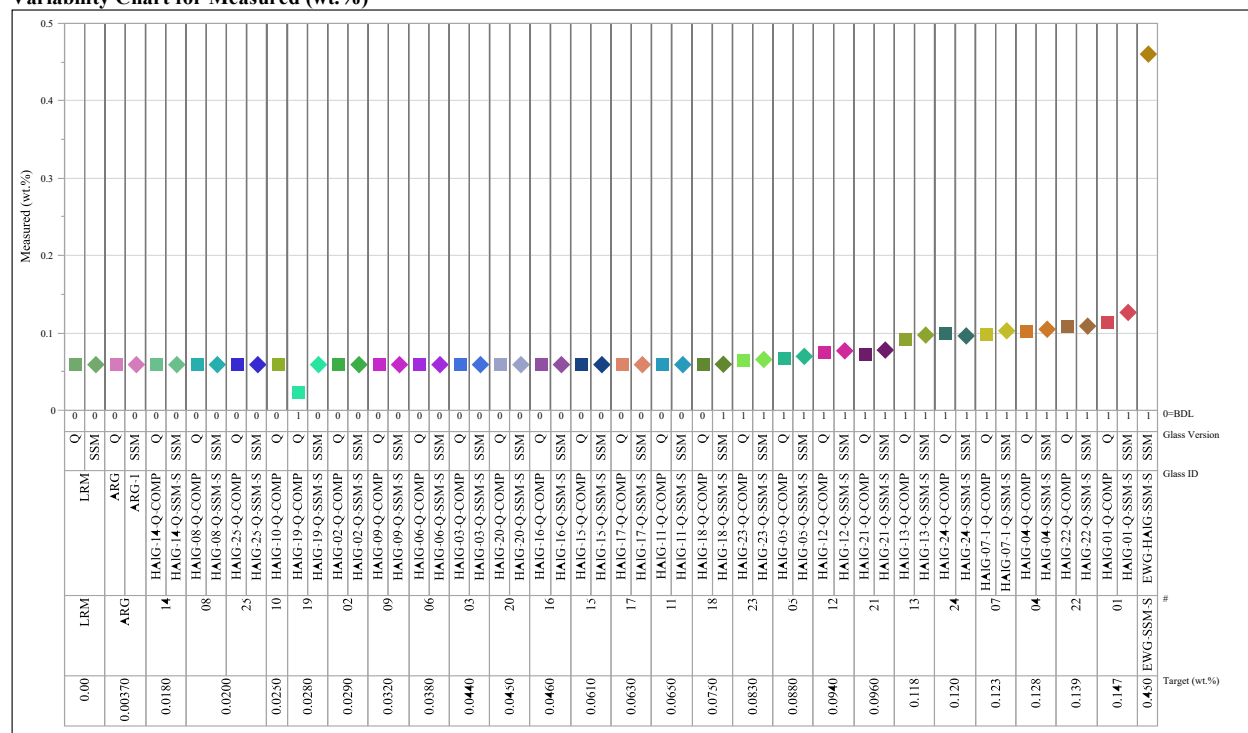
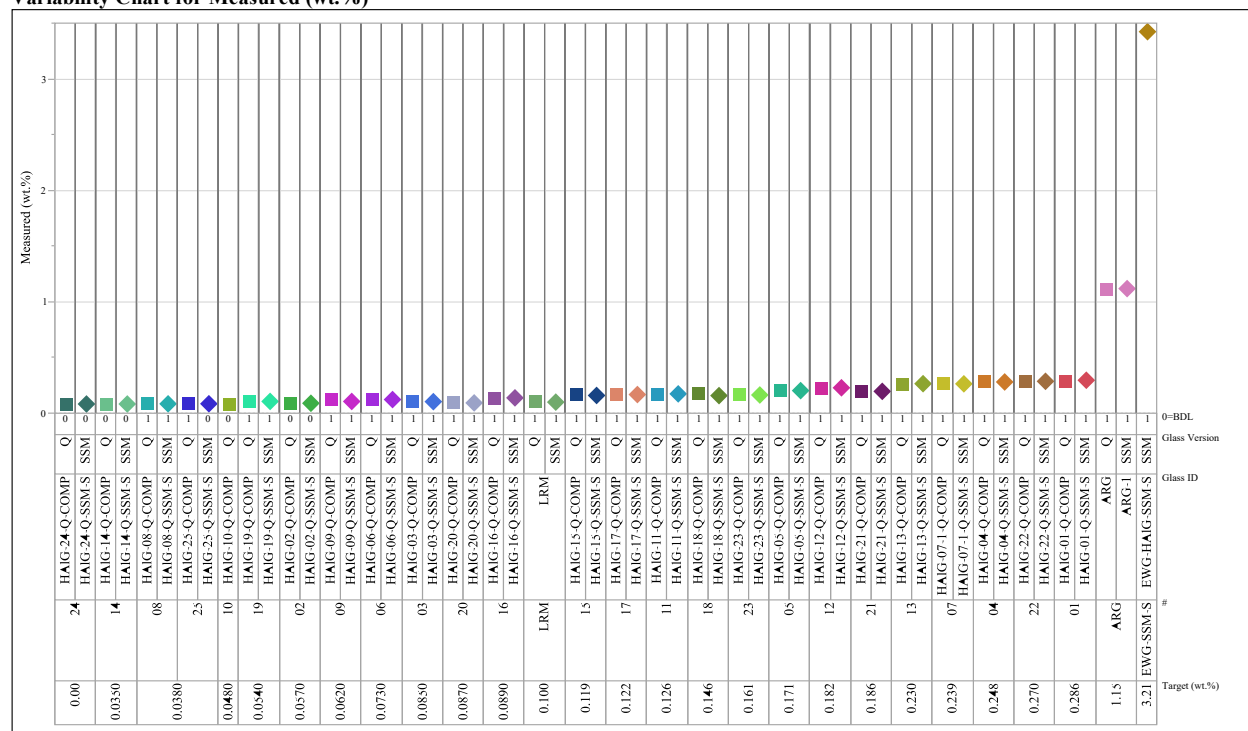


Exhibit A-4. Comparisons of the Measured Compositions of the Quenched and SSM Versions of the Study Glasses (continued)

Oxide=TiO₂

Variability Chart for Measured (wt.%)



Oxide=ZnO

Variability Chart for Measured (wt.%)

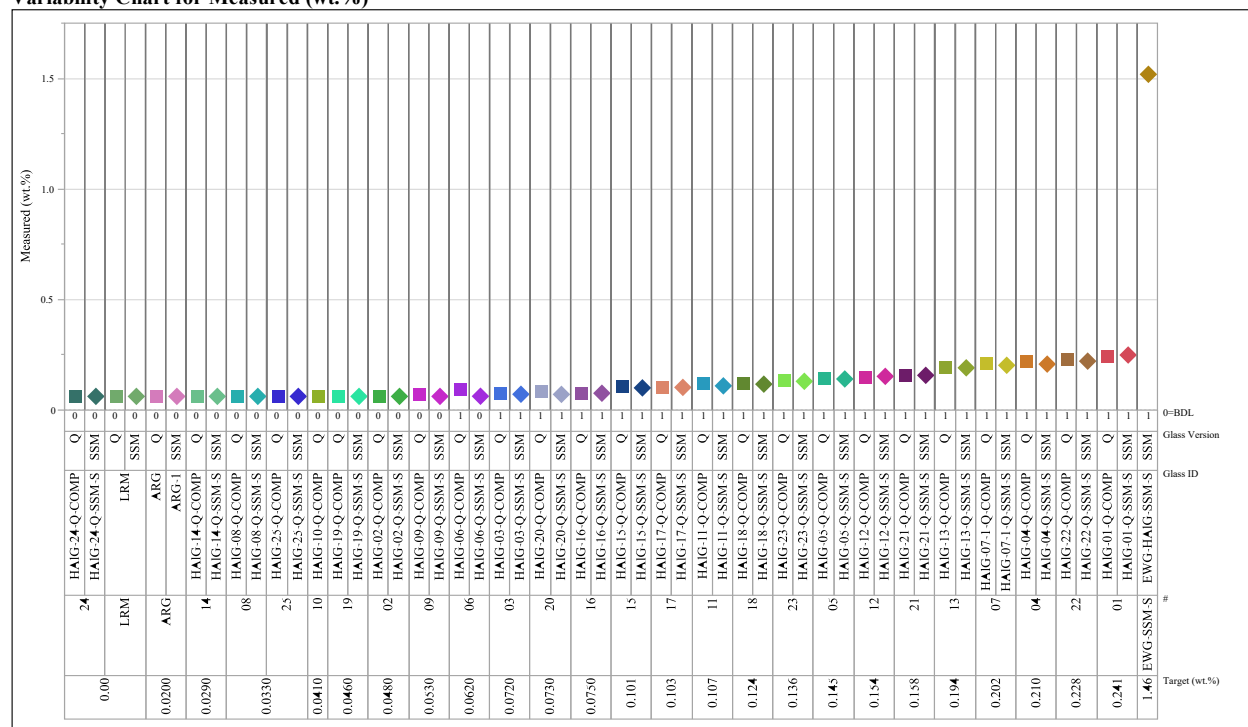
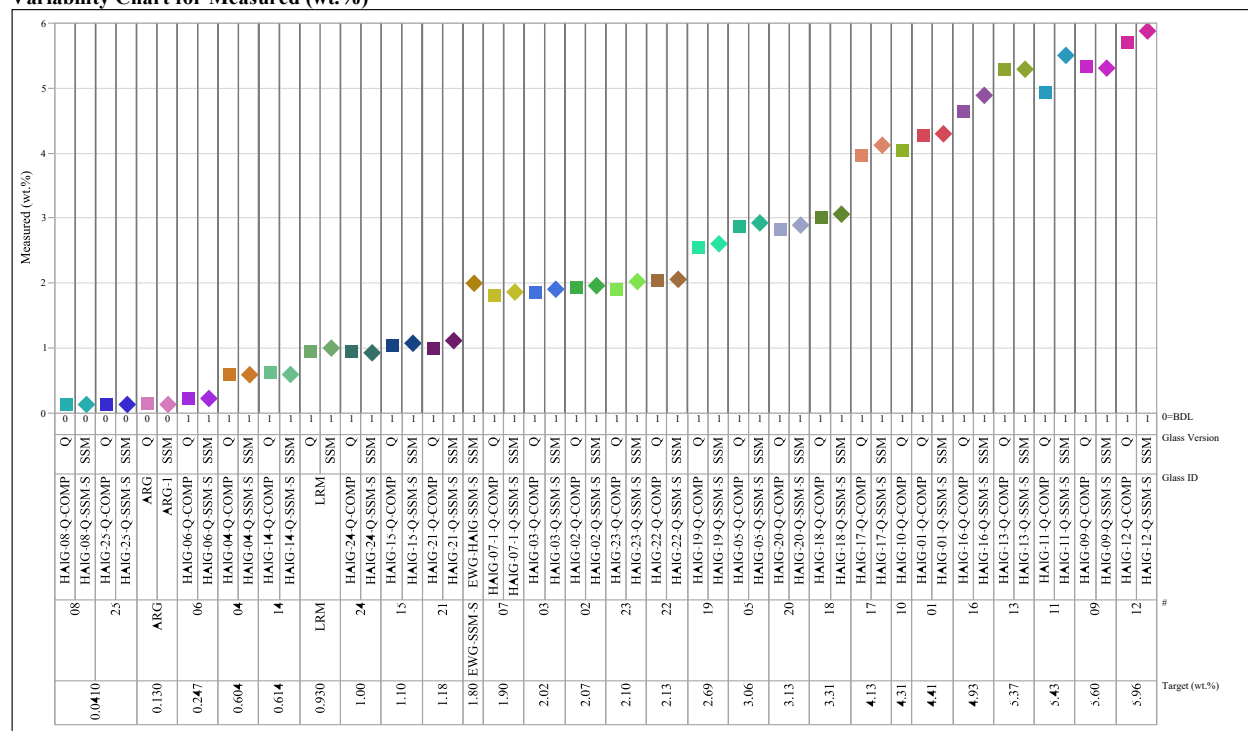


Exhibit A-4. Comparisons of the Measured Compositions of the Quenched and SSM Versions of the Study Glasses (continued)

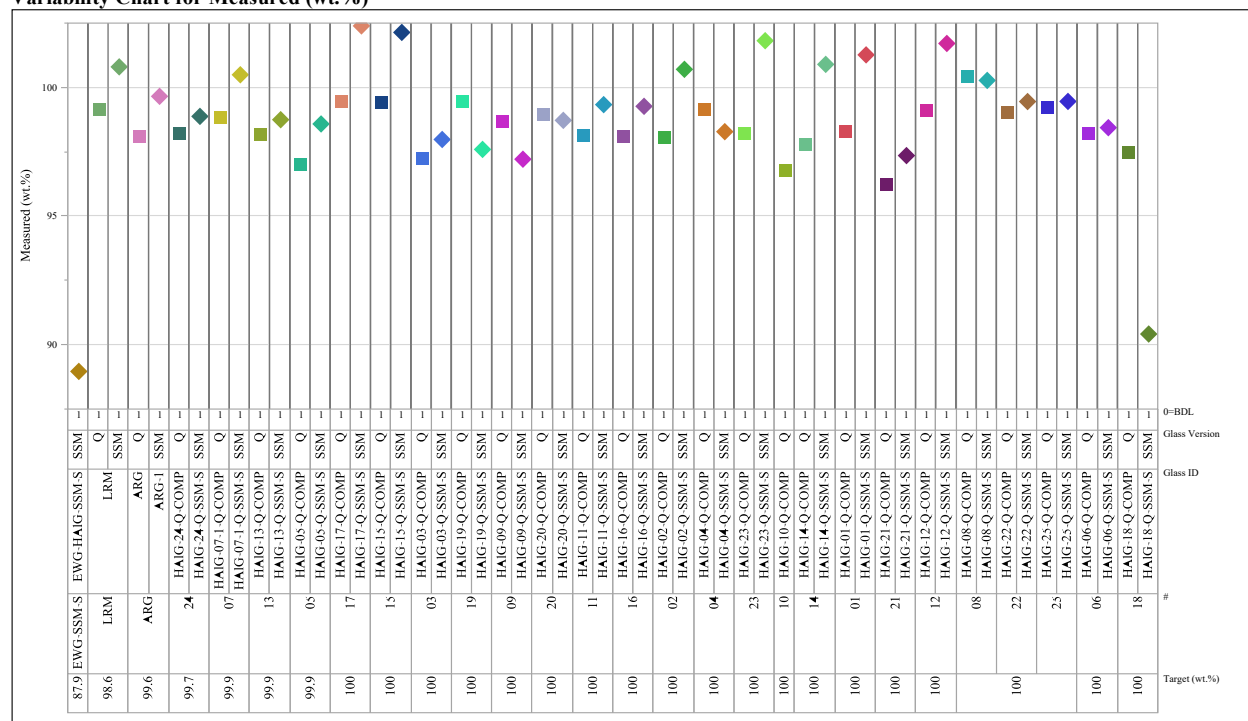
Oxide=ZrO₂

Variability Chart for Measured (wt.%)



Oxide=Sum of Oxides

Variability Chart for Measured (wt.%)



**Appendix B. Tables and Exhibits Supporting the HLW HAIG Wash Solution Composition
Measurements**

Table B-1. Measurements (mg/L) of the SSM Wash Solutions Measured by ICP-OES

PNNL ID	Block	Seq.	Lab ID	Al	B	Bi	Ca	Cd	Cr	Fe	K	Li	Mg	Mn	Na	Ni	P	S	Si	Sr	Ti	Zn	Zr
std	1	1	std-11	3.82	19.2	<1.00	<1.00	<1.00	<1.00	3.98	9.25	9.54	<1.00	<1.00	80.3	<1.00	<1.00	<1.00	47.0	<1.00	<1.00	<1.00	<1.00
hpstd	1	2	hpstd-11	51.0	<1.00	<1.00	<1.00	<1.00	<1.00	51.1	<1.00	<1.00	<1.00	20.6	147	10.3	<1.00	9.12	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-20-Q-SSM-W	1	3	S-14301-1	4.38	13.9	<1.00	3.62	<1.00	26.8	<1.00	16.2	38.8	<1.00	<1.00	551	<1.00	20.4	442	2.22	<1.00	<1.00	<1.00	<1.00
HAIG-23-Q-SSM-W	1	4	S-14304-1	2.83	11.6	<1.00	3.85	<1.00	30.7	<1.00	29.8	56.5	<1.00	<1.00	374	<1.00	15.3	356	2.42	<1.00	<1.00	<1.00	<1.00
HAIG-13-Q-SSM-W	1	5	S-14294-1	3.91	7.81	<1.00	1.74	<1.00	53.6	<1.00	110	36.8	<1.00	<1.00	858	<1.00	12.7	596	2.50	<1.00	<1.00	<1.00	<1.00
HAIG-17-Q-SSM-W	1	6	S-14298-1	2.63	18.0	<1.00	2.64	<1.00	12.9	<1.00	37.0	28.5	<1.00	<1.00	742	<1.00	13.1	513	2.42	<1.00	<1.00	<1.00	<1.00
HAIG-19-Q-SSM-W	1	7	S-14300-1	11.8	10.3	<1.00	<1.00	<1.00	164	<1.00	28.4	35.7	<1.00	<1.00	1050	<1.00	31.0	610	4.62	<1.00	<1.00	<1.00	<1.00
HAIG-21-Q-SSM-W	1	8	S-14302-1	13.8	72.6	<1.00	6.34	<1.00	51.4	<1.00	73.4	40.4	1.61	<1.00	989	<1.00	4.75	616	2.11	<1.00	<1.00	<1.00	<1.00
HAIG-18-Q-SSM-W	1	9	S-14299-1	13.0	202	<1.00	<1.00	<1.00	122	<1.00	95.8	71.0	<1.00	<1.00	1320	<1.00	5.92	548	1.60	<1.00	<1.00	<1.00	<1.00
HAIG-24-Q-SSM-W	1	10	S-14305-1	1.12	6.89	<1.00	30.7	<1.00	18.9	<1.00	25.5	39.0	<1.00	<1.00	491	<1.00	1.39	442	1.18	1.96	<1.00	<1.00	<1.00
HAIG-15-Q-SSM-W	1	11	S-14296-1	2.36	13.3	<1.00	2.27	<1.00	141	<1.00	51.7	68.8	<1.00	<1.00	778	<1.00	4.80	597	3.25	<1.00	<1.00	<1.00	<1.00
HAIG-02-Q-SSM-W	1	12	S-14284-1	9.01	25.3	<1.00	<1.00	<1.00	54.4	<1.00	14.9	10.9	<1.00	<1.00	768	<1.00	14.2	488	1.84	<1.00	<1.00	<1.00	<1.00
HAIG-07-1-Q-SSM-W	1	13	S-14289-1	5.18	14.0	<1.00	2.79	<1.00	11.4	<1.00	102	2.20	<1.00	<1.00	1000	<1.00	15.7	716	1.93	<1.00	<1.00	<1.00	<1.00
HAIG-16-Q-SSM-W	1	14	S-14297-1	4.27	10.2	<1.00	2.15	<1.00	163	<1.00	31.7	16.8	<1.00	<1.00	957	<1.00	21.3	570	3.02	<1.00	<1.00	<1.00	<1.00
std	1	15	std-12	3.83	18.8	<1.00	<1.00	<1.00	<1.00	4.01	9.20	9.31	<1.00	<1.00	80.4	<1.00	<1.00	<1.00	47.2	<1.00	<1.00	<1.00	<1.00
hpstd	1	16	hpstd-12	49.1	<1.00	<1.00	<1.00	<1.00	<1.00	49.3	<1.00	<1.00	<1.00	19.8	140	9.94	<1.00	9.72	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-12-Q-SSM-W	1	17	S-14293-1	2.95	17.2	<1.00	4.16	<1.00	112	<1.00	61.9	7.70	<1.00	<1.00	999	<1.00	10.4	580	1.33	<1.00	<1.00	<1.00	<1.00
HAIG-04-Q-SSM-W	1	18	S-14286-1	1.94	17.7	<1.00	7.73	<1.00	95.4	<1.00	112	6.01	<1.00	<1.00	1080	<1.00	5.29	679	1.60	1.47	<1.00	<1.00	<1.00
HAIG-09-Q-SSM-W	1	19	S-14291-1	9.65	25.7	<1.00	<1.00	<1.00	61.6	<1.00	16.9	60.3	<1.00	<1.00	552	<1.00	11.8	394	2.77	<1.00	<1.00	<1.00	<1.00
HAIG-14-Q-SSM-W	1	20	S-14295-1	14.6	38.7	<1.00	<1.00	<1.00	202	<1.00	17.4	59.3	<1.00	<1.00	813	<1.00	15.5	499	3.24	<1.00	<1.00	<1.00	<1.00
HAIG-25-Q-SSM-W	1	21	S-14306-1	6.17	10.6	<1.00	<1.00	<1.00	27.2	<1.00	9.09	16.4	<1.00	<1.00	592	<1.00	12.5	395	2.45	<1.00	<1.00	<1.00	<1.00
HAIG-06-Q-SSM-W	1	22	S-14288-1	10.7	25.0	<1.00	1.20	<1.00	38.0	<1.00	17.1	4.12	<1.00	<1.00	704	<1.00	9.33	454	2.31	<1.00	<1.00	<1.00	<1.00
HAIG-08-Q-SSM-W	1	23	S-14290-1	2.28	12.0	<1.00	<1.00	<1.00	26.7	<1.00	9.08	15.1	<1.00	<1.00	624	<1.00	11.7	444	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-03-Q-SSM-W	1	24	S-14285-1	2.59	8.35	<1.00	2.76	<1.00	10.3	<1.00	14.1	7.49	<1.00	<1.00	610	<1.00	10.8	433	1.72	<1.00	<1.00	<1.00	<1.00
HAIG-11-Q-SSM-W	1	25	S-14292-1	32.4	166	<1.00	<1.00	<1.00	431	<1.00	87.6	69.6	<1.00	<1.00	1630	<1.00	28.0	727	4.47	<1.00	<1.00	<1.00	<1.00
HAIG-01-Q-SSM-W	1	26	S-14283-1	2.83	14.0	<1.00	1.09	<1.00	3.99	<1.00	108	4.30	<1.00	<1.00	1200	<1.00	66.7	726	2.76	<1.00	<1.00	<1.00	<1.00
HAIG-22-Q-SSM-W	1	27	S-14303-1	1.38	6.98	<1.00	13.8	<1.00	92.3	<1.00	89.6	50.0	1.08	<1.00	732	<1.00	5.73	551	1.77	2.58	<1.00	<1.00	<1.00
EWG-HAIG-SSM-W	1	28	S-14307-1	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	595	<1.00	<1.00	407	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-05-Q-SSM-W	1	29	S-14287-1	1.48	19.7	<1.00	5.63	<1.00	13.0	<1.00	40.1	5.24	<1.00	<1.00	558	<1.00	<1.00	379	<1.00	<1.00	<1.00	<1.00	<1.00
std	1	30	std-13	3.92	18.5	<1.00	<1.00	<1.00	<1.00	4.00	9.50	9.51	<1.00	<1.00	77.8	<1.00	<1.00	<1.00	48.5	<1.00	<1.00	<1.00	<1.00
hpstd	1	31	hpstd-13	47.0	<1.00	<1.00	<1.00	<1.00	<1.00	47.3	<1.00	<1.00	<1.00	18.9	140	9.57	<1.00	9.90	<1.00	<1.00	<1.00	<1.00	<1.00
std	2	1	std-21	3.90	19.2	<1.00	<1.00	<1.00	<1.00	4.01	10.0	10.1	<1.00	<1.00	81.1	<1.00	<1.00	<1.00	48.2	<1.00	<1.00	<1.00	<1.00
hpstd	2	2	hpstd-21	48.6	<1.00	<1.00	<1.00	<1.00	<1.00	49.1	<1.00	<1.00	<1.00	19.7	149	9.90	<1.00	10.6	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-21-Q-SSM-W	2	3	S-14302-2	14.5	79.3	<1.00	7.28	<1.00	52.7	<1.00	75.2	42.2	1.72	<1.00	945	<1.00	5.09	667	2.25	<1.00	<1.00	<1.00	<1.00
HAIG-07-1-Q-SSM-W	2	4	S-14289-2	5.45	16.0	<1.00	3.10	<1.00	11.5	<1.00	101	2.20	<1.00	<1.00	1090	<1.00	16.7	759	2.07	<1.00	<1.00	<1.00	<1.00
HAIG-23-Q-SSM-W	2	5	S-14304-2	2.92	13.0	<1.00	4.27	<1.00	31.2	<1.00	29.8	57.5	<1.00	<1.00	380	<1.00	16.3	375	2.50	<1.00	<1.00	<1.00	<1.00
HAIG-09-Q-SSM-W	2	6	S-14291-2	9.97	28.9	<1.00	<1.00	<1.00	63.8	<1.00	17.5	64.6	<1.00	<1.00	566	<1.00	12.7	464	2.90	<1.00	<1.00	<1.00	<1.00
HAIG-05-Q-SSM-W	2	7	S-14287-2	1.48	21.1	<1.00	5.89	<1.00	13.1	<1.00	39.3	5.23	<1.00	<1.00	558	<1.00	<1.00	404	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-03-Q-SSM-W	2	8	S-14285-2	2.76	10.1	<1.00	3.13	<1.00	10.9	<1.00	14.6	7.85	<1.00	<1.00	647	<1.00	11.9	449	1.82	<1.00	<1.00	<1.00	<1.00
HAIG-12-Q-SSM-W	2	9	S-14293-2	3.04	19.9	<1.00	4.67	<1.00	137	<1.00	60.6	7.65	<1.00	<1.00	1110	<1.00	11.2	702	1.37	<1.00	<1.00	<1.00	<1.00
HAIG-20-Q-SSM-W	2	10	S-14301-2	4.30	13.6	<1.00	3.83	<1.00	26.3	<1.00	16.3	39.7	<1.00	<1.00	561	<1.00	21.0	462	2.52	<1.00	<1.00	<1.00	<1.00
HAIG-22-Q-SSM-W	2	11	S-14303-2	1.41	8.90	<1.00	15.0	<1.00	95.3	<1.00	88.1	48.0	1.13	<1.00	843	<1.00	5.92	676	1.70	2.87	<1.00	<1.00	<1.00
HAIG-08-Q-SSM-W	2	12	S-14290-2	2.41	14.1	<1.00	<1.00	<1.00	27.8	<1.00	9.77	16.1	<1.00	<1.00	661	<1.00	12.7	465	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-13-Q-SSM-W	2	13	S-14294-2	4.00	8.80	<1.00	1.90	<1.00	54.1	<1.00	109	37.4	<1.00	<1.00	935	<1.00	13.2	708	2.54	<1.00	<1.00	<1.00	<1.00
HAIG-16-Q-SSM-W	2	14	S-14297-2	4.59	12.3	<1.00	2.57	<1.00	203	<1.00	32.6	18.3	<1.00	<1.00	1180	<1.00	23.7	730	3.31	<1.00	<1.00	<1.00	<1.00
std	2	15	std-22	3.88	18.6	<1.00	<1.00	<1.00	<1.00	4.00	9.62	9.92	<1.00	<1.00	82.8	<1.00	<1.00	<1.00	48.4	<1.00	<1.00	<1.00	<1.00
hpstd	2	16	hpstd-22	48.1	<1.00	<1.00	<1.00	<1.00	<1.00	48.4	<1.00	<1.00	<1.00	19.6	148	9.77	<1.00	10.7	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-14-Q-SSM-W	2	17	S-14295-2	14.9	39.2	<1.00	<1.00	<1.00	258	<1.00	17.5	61.0	<1.00	<1.00	1010	<1.00	16.3	637	3.32	<1.00	<1.00	<1.00	<1.00

Table B-1. Measurements (mg/L) of the SSM Wash Solutions Measured by ICP-OES (continued)

PNNL ID	Block	Seq.	Lab ID	Al	B	Bi	Ca	Cd	Cr	Fe	K	Li	Mg	Mn	Na	Ni	P	S	Si	Sr	Ti	Zn	Zr
HAIG-15-Q-SSM-W	2	18	S-14296-2	2.39	14.9	<1.00	2.46	<1.00	146	<1.00	51.1	69.3	<1.00	<1.00	817	<1.00	5.16	636	3.39	<1.00	<1.00	<1.00	<1.00
HAIG-06-Q-SSM-W	2	19	S-14288-2	11.5	27.9	<1.00	1.34	<1.00	40.7	<1.00	17.8	4.30	<1.00	<1.00	758	<1.00	10.4	479	2.48	<1.00	<1.00	<1.00	<1.00
HAIG-04-Q-SSM-W	2	20	S-14286-2	2.01	20.2	<1.00	8.84	<1.00	97.1	<1.00	110	5.93	<1.00	<1.00	1150	<1.00	5.64	778	3.43	1.59	<1.00	<1.00	<1.00
HAIG-19-Q-SSM-W	2	21	S-14300-2	12.3	11.8	<1.00	<1.00	<1.00	170	<1.00	28.7	36.5	<1.00	<1.00	1070	<1.00	32.1	659	4.80	<1.00	<1.00	<1.00	<1.00
HAIG-11-Q-SSM-W	2	22	S-14292-2	32.4	166	<1.00	<1.00	<1.00	424	<1.00	84.9	69.1	<1.00	<1.00	1610	<1.00	29.1	713	4.27	<1.00	<1.00	<1.00	<1.00
HAIG-02-Q-SSM-W	2	23	S-14284-2	9.20	26.2	<1.00	<1.00	<1.00	55.4	<1.00	15.3	11.2	<1.00	<1.00	840	<1.00	15.0	539	1.86	<1.00	<1.00	<1.00	<1.00
HAIG-17-Q-SSM-W	2	24	S-14298-2	2.68	19.6	<1.00	2.90	<1.00	13.0	<1.00	37.1	28.8	<1.00	<1.00	795	<1.00	13.5	579	2.49	<1.00	<1.00	<1.00	<1.00
EWG-HAIG-SSM-W	2	25	S-14307-2	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	596	<1.00	<1.00	430	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-24-Q-SSM-W	2	26	S-14305-2	1.14	7.70	<1.00	34.4	<1.00	19.2	<1.00	25.4	39.5	<1.00	<1.00	474	<1.00	1.51	462	1.18	2.10	<1.00	<1.00	<1.00
HAIG-01-Q-SSM-W	2	27	S-14283-2	2.80	15.3	<1.00	1.06	<1.00	4.17	<1.00	104	4.23	<1.00	<1.00	1140	<1.00	66.6	714	2.70	<1.00	<1.00	<1.00	<1.00
HAIG-25-Q-SSM-W	2	28	S-14306-2	6.67	12.8	<1.00	<1.00	<1.00	28.5	1.03	9.84	16.6	<1.00	<1.00	696	<1.00	13.5	483	2.65	<1.00	<1.00	<1.00	<1.00
HAIG-18-Q-SSM-W	2	29	S-14299-2	12.9	231	<1.00	<1.00	<1.00	135	<1.00	93.9	72.0	<1.00	<1.00	1340	<1.00	6.20	613	1.59	<1.00	<1.00	<1.00	<1.00
std	2	30	std-23	3.88	19.1	<1.00	<1.00	<1.00	<1.00	4.02	9.43	9.81	<1.00	<1.00	80.2	<1.00	<1.00	<1.00	48.5	<1.00	<1.00	<1.00	<1.00
hpstd	2	31	hpstd-23	49.5	<1.00	<1.00	<1.00	<1.00	<1.00	49.7	<1.00	<1.00	<1.00	20.1	145	9.97	<1.00	10.5	<1.00	<1.00	<1.00	<1.00	<1.00
std	3	1	std-31	4.02	19.9	<1.00	<1.00	<1.00	<1.00	4.05	9.81	10.3	<1.00	<1.00	79.5	<1.00	<1.00	<1.00	49.0	<1.00	<1.00	<1.00	<1.00
hpstd	3	2	hpstd-31	50.4	<1.00	<1.00	<1.00	<1.00	<1.00	49.8	<1.00	<1.00	<1.00	20.2	150	10.1	<1.00	10.2	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-15-Q-SSM-W	3	3	S-14296-3	3.44	15.5	<1.00	2.57	<1.00	133	<1.00	51.4	71.7	<1.00	<1.00	834	<1.00	5.22	557	4.98	<1.00	<1.00	<1.00	<1.00
HAIG-07-1-Q-SSM-W	3	4	S-14289-3	5.02	15.2	<1.00	2.98	<1.00	10.7	<1.00	102	2.33	<1.00	<1.00	1050	<1.00	15.7	654	1.84	<1.00	<1.00	<1.00	<1.00
HAIG-18-Q-SSM-W	3	5	S-14299-3	11.7	218	<1.00	<1.00	<1.00	130	<1.00	97.8	75.1	<1.00	<1.00	1390	<1.00	6.39	573	1.63	<1.00	<1.00	<1.00	<1.00
EWG-HAIG-SSM-W	3	6	S-14307-3	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	611	<1.00	<1.00	386	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-03-Q-SSM-W	3	7	S-14285-3	2.96	10.6	<1.00	3.22	<1.00	10.4	<1.00	14.5	7.97	<1.00	<1.00	625	<1.00	11.6	399	2.22	<1.00	<1.00	<1.00	<1.00
HAIG-13-Q-SSM-W	3	8	S-14294-3	4.09	9.09	<1.00	1.98	<1.00	52.4	<1.00	107	38.4	<1.00	<1.00	939	<1.00	13.2	620	2.70	<1.00	<1.00	<1.00	<1.00
HAIG-24-Q-SSM-W	3	9	S-14305-3	<1.00	8.09	<1.00	33.4	<1.00	17.9	<1.00	24.9	41.6	<1.00	<1.00	478	<1.00	1.36	427	1.13	1.97	<1.00	<1.00	<1.00
HAIG-25-Q-SSM-W	3	10	S-14306-3	2.15	12.7	<1.00	<1.00	<1.00	27.3	<1.00	9.35	17.3	<1.00	<1.00	692	<1.00	13.0	429	1.09	<1.00	<1.00	<1.00	<1.00
HAIG-19-Q-SSM-W	3	11	S-14300-3	13.0	11.9	<1.00	<1.00	<1.00	160	2.05	28.5	36.8	<1.00	<1.00	1030	<1.00	32.5	584	5.99	<1.00	<1.00	<1.00	<1.00
HAIG-09-Q-SSM-W	3	12	S-14291-3	9.49	27.1	<1.00	<1.00	<1.00	58.7	<1.00	16.4	59.8	<1.00	<1.00	542	<1.00	12.1	376	2.63	<1.00	<1.00	<1.00	<1.00
HAIG-11-Q-SSM-W	3	13	S-14292-3	32.3	152	<1.00	<1.00	<1.00	394	<1.00	84.1	68.5	<1.00	<1.00	1580	<1.00	29.6	634	4.25	<1.00	<1.00	<1.00	<1.00
HAIG-16-Q-SSM-W	3	14	S-14297-3	4.35	11.9	<1.00	2.42	<1.00	168	<1.00	31.1	17.8	<1.00	<1.00	1050	<1.00	22.6	577	3.05	<1.00	<1.00	<1.00	<1.00
std	3	15	std-32	3.93	19.0	<1.00	<1.00	<1.00	<1.00	3.91	9.41	9.84	<1.00	<1.00	80.8	<1.00	<1.00	<1.00	46.9	<1.00	<1.00	<1.00	<1.00
hpstd	3	16	hpstd-32	48.8	<1.00	<1.00	<1.00	<1.00	<1.00	47.6	<1.00	<1.00	<1.00	19.3	145	9.69	<1.00	9.40	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-20-Q-SSM-W	3	17	S-14301-3	5.41	14.1	<1.00	4.27	<1.00	25.4	<1.00	15.7	40.7	<1.00	<1.00	551	<1.00	22.1	429	3.38	<1.00	<1.00	<1.00	<1.00
HAIG-23-Q-SSM-W	3	18	S-14304-3	3.31	12.6	<1.00	4.15	<1.00	28.8	<1.00	28.0	54.4	<1.00	<1.00	392	<1.00	15.5	336	3.07	<1.00	<1.00	<1.00	<1.00
HAIG-06-Q-SSM-W	3	19	S-14288-3	10.7	25.5	<1.00	1.33	<1.00	37.9	<1.00	16.8	4.16	<1.00	<1.00	721	<1.00	9.91	437	2.15	<1.00	<1.00	<1.00	<1.00
HAIG-05-Q-SSM-W	3	20	S-14287-3	1.66	20.4	<1.00	5.75	<1.00	12.4	<1.00	38.1	5.13	<1.00	<1.00	522	<1.00	<1.00	332	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-08-Q-SSM-W	3	21	S-14290-3	2.52	13.8	<1.00	<1.00	<1.00	25.9	<1.00	8.85	15.3	<1.00	<1.00	624	<1.00	12.2	402	<1.00	<1.00	<1.00	<1.00	<1.00
HAIG-01-Q-SSM-W	3	22	S-14283-3	2.65	14.6	<1.00	1.05	<1.00	3.75	<1.00	99.1	4.06	<1.00	<1.00	1040	<1.00	64.5	583	2.48	<1.00	<1.00	<1.00	<1.00
HAIG-21-Q-SSM-W	3	23	S-14302-3	14.2	76.1	<1.00	7.14	<1.00	50.9	<1.00	74.5	43.9	1.66	<1.00	907	<1.00	5.05	584	2.19	<1.00	<1.00	<1.00	<1.00
HAIG-12-Q-SSM-W	3	24	S-14293-3	3.07	19.1	<1.00	4.67	<1.00	121	<1.00	59.7	7.68	<1.00	<1.00	1020	<1.00	11.0	597	1.39	<1.00	<1.00	<1.00	<1.00
HAIG-04-Q-SSM-W	3	25	S-14286-3	1.99	19.5	<1.00	8.62	<1.00	92.2	<1.00	110	5.55	<1.00	<1.00	1020	<1.00	5.65	596	1.61	1.50	<1.00	<1.00	<1.00
HAIG-22-Q-SSM-W	3	26	S-14303-3	1.34	8.71	<1.00	14.2	<1.00	88.6	<1.00	85.9	50.1	1.05	<1.00	686	<1.00	5.69	472	1.59	2.59	<1.00	<1.00	<1.00
HAIG-14-Q-SSM-W	3	27	S-14295-3	15.1	38.4	<1.00	<1.00	<1.00	212	<1.00	17.8	62.4	<1.00	<1.00	929	<1.00	16.3	497	3.33	<1.00	<1.00	<1.00	<1.00
HAIG-17-Q-SSM-W	3	28	S-14298-3	4.01	19.0	<1.00	2.94	<1.00	11.9	<1.00	36.0	28.7	<1.00	<1.00	715	<1.00	13.0	470	4.55	<1.00	<1.00	<1.00	<1.00
HAIG-02-Q-SSM-W	3	29	S-14284-3	9.58	24.7	<1.00	1.11	<1.00	51.9	<1.00	15.1	11.3	<1.00	<1.00	854	<1.00	15.0	478	2.24	<1.00	<1.00	<1.00	<1.00
std	3	30	std-33	3.95	19.0	<1.00	<1.00	<1.00	<1.00	3.91	9.54	9.88	<1.00	<1.00	80.2	<1.00	<1.00	<1.00	46.8	<1.00	<1.00	<1.00	<1.00
hpstd	3	31	hpstd-33	48.4	<1.00	<1.00	<1.00	<1.00	<1.00	47.1	<1.00	<1.00	<1.00	19.0	146	9.59	<1.00	9.27	<1.00	<1.00	<1.00	<1.00	<1.00

Table B-2. Measurements (mg/L) of the SSM Wash Solutions Measured by IC

PNNL ID	Block	Seq.	Lab ID	F⁻	PO₄³⁻	SO₄²⁻
IC Blank	1	1	IC BLANK 1-1	<5.00	<10.0	<10.0
5 ppm std	1	2	5 ppm std	4.97	4.98	5.06
HAIG-04-Q-SSM-W	1	3	S-14286-1	25.7	17.1	2120
HAIG-08-Q-SSM-W	1	4	S-14290-1	<5.00	32.5	1290
HAIG-16-Q-SSM-W	1	5	S-14297-1	7.75	64.9	1880
HAIG-15-Q-SSM-W	1	6	S-14296-1	13.7	12.4	1770
HAIG-07-1-Q-SSM-W	1	7	S-14289-1	17.3	41.5	2090
HAIG-06-Q-SSM-W	1	8	S-14288-1	<5.00	25.3	1410
HAIG-24-Q-SSM-W	1	9	S-14305-1	<5.00	<10.0	1310
HAIG-13-Q-SSM-W	1	10	S-14294-1	28.2	32.4	1910
IC Blank	1	11	IC BLANK 1-2	<5.00	<10.0	<10.0
5 ppm std	1	12	5 ppm std	4.98	4.91	5.00
HAIG-12-Q-SSM-W	1	13	S-14293-1	11.3	28.2	1870
HAIG-19-Q-SSM-W	1	14	S-14300-1	7.33	94.6	1850
HAIG-14-Q-SSM-W	1	15	S-14295-1	<5.00	41.0	1670
HAIG-01-Q-SSM-W	1	16	S-14283-1	26.8	<10.0	2070
HAIG-11-Q-SSM-W	1	17	S-14292-1	33.8	85.5	2040
HAIG-18-Q-SSM-W	1	18	S-14299-1	35.4	14.6	1810
HAIG-05-Q-SSM-W	1	19	S-14287-1	<5.00	<10.0	1160
HAIG-03-Q-SSM-W	1	20	S-14285-1	<5.00	28.5	1250
IC Blank	1	21	IC BLANK 1-3	<5.00	<10.0	<10.0
5 ppm std	1	22	5 ppm std	4.96	5.18	4.99
HAIG-02-Q-SSM-W	1	23	S-14284-1	<5.00	42.1	1510
HAIG-20-Q-SSM-W	1	24	S-14301-1	<5.00	59.4	1280
HAIG-17-Q-SSM-W	1	25	S-14298-1	9.06	36.3	1670
HAIG-09-Q-SSM-W	1	26	S-14291-1	<5.00	32.3	1260
HAIG-21-Q-SSM-W	1	27	S-14302-1	23.9	13.0	1850
HAIG-22-Q-SSM-W	1	28	S-14303-1	31.0	15.8	1790
EWG-HAIG-SSM-W	1	29	S-14307-1	<5.00	<10.0	1260
HAIG-25-Q-SSM-W	1	30	S-14306-1	<5.00	32.8	1340
HAIG-23-Q-SSM-W	1	31	S-14304-1	8.51	44.3	1030
IC Blank	1	32	IC BLANK 1-4	<5.00	<10.0	<10.0
5 ppm std	1	33	5 ppm std	4.95	5.10	4.99
IC Blank	2	1	IC BLANK 2-1	<5.00	<10.0	<10.0
5 ppm std	2	2	5 ppm std	4.97	4.85	5.07
HAIG-11-Q-SSM-W	2	3	S-14292-2	33.9	91.5	2040
HAIG-24-Q-SSM-W	2	4	S-14305-2	<5.00	<10.0	1320
HAIG-15-Q-SSM-W	2	5	S-14296-2	13.8	12.0	1770
HAIG-20-Q-SSM-W	2	6	S-14301-2	<5.00	60.3	1280
HAIG-21-Q-SSM-W	2	7	S-14302-2	23.9	12.3	1850
HAIG-22-Q-SSM-W	2	8	S-14303-2	31.1	14.5	1790
HAIG-14-Q-SSM-W	2	9	S-14295-2	<5.00	41.6	1670
HAIG-07-1-Q-SSM-W	2	10	S-14289-2	17.3	42.0	2100
IC Blank	2	11	IC BLANK 2-2	<5.00	<10.0	<10.0
5 ppm std	2	12	5 ppm std	4.97	4.87	5.02
HAIG-08-Q-SSM-W	2	13	S-14290-2	<5.00	32.0	1290
HAIG-13-Q-SSM-W	2	14	S-14294-2	28.5	31.1	1910
EWG-HAIG-SSM-W	2	15	S-14307-2	<5.00	<10.0	1270

Table B-2. Measurements (mg/L) of the SSM Wash Solutions Measured by IC (continued)

PNNL ID	Block	Seq.	Lab ID	F ⁻	PO ₄ ³⁻	SO ₄ ²⁻
HAIG-17-Q-SSM-W	2	16	S-14298-2	9.05	34.9	1670
HAIG-12-Q-SSM-W	2	17	S-14293-2	11.3	29.6	1890
HAIG-18-Q-SSM-W	2	18	S-14299-2	35.5	15.2	1810
HAIG-05-Q-SSM-W	2	19	S-14287-2	<5.00	<10.0	1170
HAIG-23-Q-SSM-W	2	20	S-14304-2	8.54	43.7	1030
IC Blank	2	21	IC BLANK 2-3	<5.00	<10.0	<10.0
5 ppm std	2	22	5 ppm std	4.95	5.11	5.00
HAIG-19-Q-SSM-W	2	23	S-14300-2	7.45	108	1860
HAIG-06-Q-SSM-W	2	24	S-14288-2	<5.00	25.2	1410
HAIG-16-Q-SSM-W	2	25	S-14297-2	7.82	64.1	1880
HAIG-25-Q-SSM-W	2	26	S-14306-2	<5.00	33.5	1340
HAIG-03-Q-SSM-W	2	27	S-14285-2	<5.00	29.8	1250
HAIG-04-Q-SSM-W	2	28	S-14286-2	25.8	13.8	2130
HAIG-02-Q-SSM-W	2	29	S-14284-2	<5.00	40.4	1530
HAIG-09-Q-SSM-W	2	30	S-14291-2	<5.00	32.1	1270
HAIG-01-Q-SSM-W	2	31	S-14283-2	26.9	<10.0	2080
IC Blank	2	32	IC BLANK 2-4	<5.00	<10.0	<10.0
5 ppm std	2	33	5 ppm std	4.98	5.09	5.06
IC Blank	3	1	IC BLANK 3-1	<5.00	<10.0	<10.0
5 ppm std	3	2	5 ppm std	5.01	4.93	5.14
HAIG-19-Q-SSM-W	3	3	S-14300-3	7.42	107	1870
HAIG-05-Q-SSM-W	3	4	S-14287-3	<5.00	<10.0	1180
HAIG-01-Q-SSM-W	3	5	S-14283-3	27.0	<10.0	2090
HAIG-03-Q-SSM-W	3	6	S-14285-3	<5.00	31.5	1260
HAIG-04-Q-SSM-W	3	7	S-14286-3	25.9	15.0	2140
HAIG-14-Q-SSM-W	3	8	S-14295-3	<5.00	43.8	1690
HAIG-20-Q-SSM-W	3	9	S-14301-3	<5.00	60.8	1290
HAIG-21-Q-SSM-W	3	10	S-14302-3	24.0	13.3	1860
IC Blank	3	11	IC BLANK 3-2	<5.00	<10.0	<10.0
5 ppm std	3	12	5 ppm std	5.03	4.96	5.09
HAIG-08-Q-SSM-W	3	13	S-14290-3	<5.00	32.6	1300
HAIG-15-Q-SSM-W	3	14	S-14296-3	14.0	11.7	1790
HAIG-12-Q-SSM-W	3	15	S-14293-3	11.4	27.5	1910
HAIG-11-Q-SSM-W	3	16	S-14292-3	34.3	91.7	2060
HAIG-16-Q-SSM-W	3	17	S-14297-3	7.87	65.5	1900
EWG-HAIG-SSM-W	3	18	S-14307-3	<5.00	<10.0	1280
HAIG-18-Q-SSM-W	3	19	S-14299-3	35.9	14.3	1830
HAIG-07-1-Q-SSM-W	3	20	S-14289-3	17.5	44.5	2110
IC Blank	3	21	IC BLANK 3-3	<5.00	<10.0	<10.0
5 ppm std	3	22	5 ppm std	5.01	5.05	5.05
HAIG-24-Q-SSM-W	3	23	S-14305-3	<5.00	<10.0	1330
HAIG-06-Q-SSM-W	3	24	S-14288-3	<5.00	26.6	1420
HAIG-22-Q-SSM-W	3	25	S-14303-3	31.4	15.5	1810
HAIG-09-Q-SSM-W	3	26	S-14291-3	<5.00	32.9	1270
HAIG-17-Q-SSM-W	3	27	S-14298-3	9.11	35.6	1680
HAIG-13-Q-SSM-W	3	28	S-14294-3	28.6	34.0	1930
HAIG-23-Q-SSM-W	3	29	S-14304-3	8.68	43.2	1050
HAIG-25-Q-SSM-W	3	30	S-14306-3	<5.00	34.2	1350

Table B-2. Measurements (mg/L) of the SSM Wash Solutions Measured by IC (continued)

PNNL ID	Block	Seq.	Lab ID	F⁻	PO₄³⁻	SO₄²⁻
HAIG-02-Q-SSM-W	3	31	S-14284-3	<5.00	39.7	1530
IC Blank	3	32	IC BLANK 3-4	<5.00	<10.0	<10.0
5 ppm std	3	33	5 ppm std	5.07	5.11	5.11

Table B-3. Results for Standards Utilized During the Measurement of the Wash Solutions

Solution ID	Instrument	Analyte	Reference Value (mg/L)	Mean Measurement (mg/L)
5 ppm std	IC	F-	5	4.99
5 ppm std	IC	PO ₄	5	5.01
5 ppm std	IC	SO ₄	5	5.05
hpstd	ICP	Al	50	49.0
hpstd	ICP	B	0	<1.00
hpstd	ICP	Bi	0	<1.00
hpstd	ICP	Ca	0	<1.00
hpstd	ICP	Cd	0	<1.00
hpstd	ICP	Cr	0	<1.00
hpstd	ICP	Fe	50	48.8
hpstd	ICP	K	0	<1.00
hpstd	ICP	Li	0	<1.00
hpstd	ICP	Mg	0	<1.00
hpstd	ICP	Mn	20	19.7
hpstd	ICP	Na	150	146
hpstd	ICP	Ni	10	9.87
hpstd	ICP	P	0	<1.00
hpstd	ICP	S	10	9.93
hpstd	ICP	Si	0	<1.00
hpstd	ICP	Sr	0	<1.00
hpstd	ICP	Ti	0	<1.00
hpstd	ICP	Zn	0	<1.00
hpstd	ICP	Zr	0	<1.00
soln std	ICP	Al	4	3.90
soln std	ICP	B	20	19.0
soln std	ICP	Bi	0	<1.00
soln std	ICP	Ca	0	<1.00
soln std	ICP	Cd	0	<1.00
soln std	ICP	Cr	0	<1.00
soln std	ICP	Fe	4	3.99
soln std	ICP	K	10	9.53
soln std	ICP	Li	10	9.80
soln std	ICP	Mg	0	<1.00
soln std	ICP	Mn	0	<1.00
soln std	ICP	Na	81	80.3
soln std	ICP	Ni	0	<1.00
soln std	ICP	P	0	<1.00
soln std	ICP	S	0	<1.00
soln std	ICP	Si	50	47.8
soln std	ICP	Sr	0	<1.00
soln std	ICP	Ti	0	<1.00
soln std	ICP	Zn	0	<1.00
soln std	ICP	Zr	0	<1.00

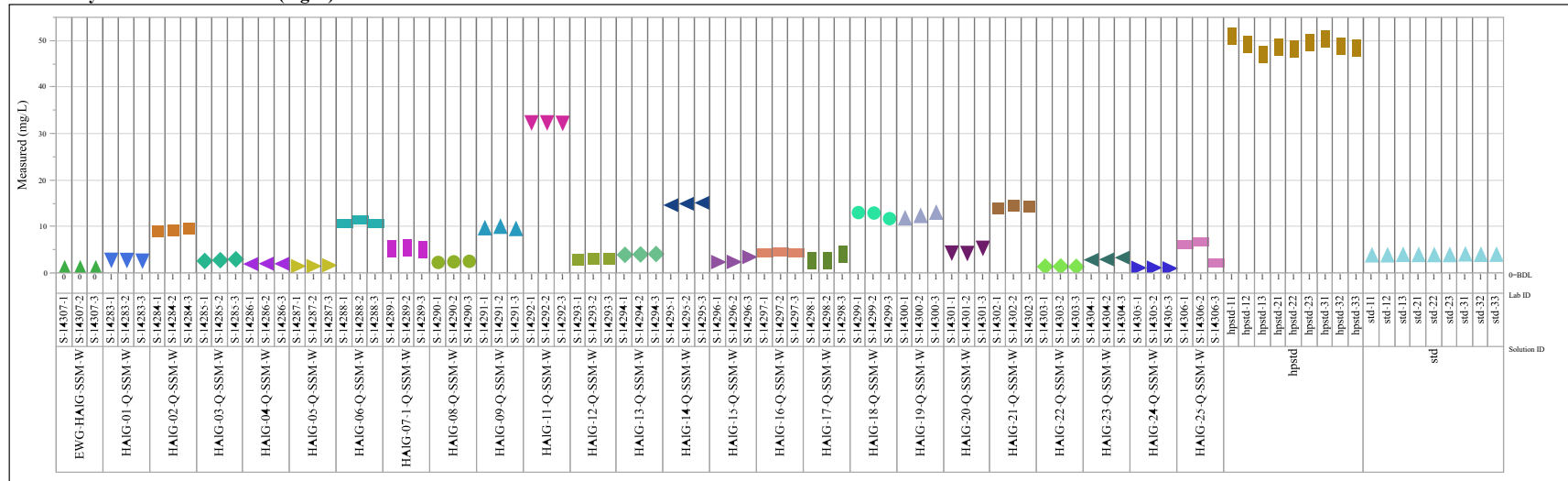
Table B-4. Average Measurements (mg/L) of the SSM Wash Solutions

		IC			ICP-OES																					
Lab ID	PNNL ID	F ⁻	PO ₄ ³⁻	SO ₄ ²⁻	Al	B	Bi	Ca	Cd	Cr	Fe	K	Li	Mg	Mn	Na	Ni	P	PO ₄	S	Si	SO ₄	Sr	Ti	Zn	Zr
S-14283	HAIG-01-Q-SSM-W	26.9	<10.0	2080	2.76	14.6	<1.00	1.07	<1.00	3.97	<1.00	104	4.20	<1.00	<1.00	1130	<1.00	65.9	202	674	2.65	2020	<1.00	<1.00	<1.00	<1.00
S-14284	HAIG-02-Q-SSM-W	<5.00	40.7	1520	9.26	25.4	<1.00	<1.04	<1.00	53.9	<1.00	15.1	11.1	<1.00	<1.00	821	<1.00	14.7	45.2	502	1.98	1500	<1.00	<1.00	<1.00	<1.00
S-14285	HAIG-03-Q-SSM-W	<5.00	29.9	1250	2.77	9.68	<1.00	3.04	<1.00	10.5	<1.00	14.4	7.77	<1.00	<1.00	627	<1.00	11.4	35.1	427	1.92	1280	<1.00	<1.00	<1.00	<1.00
S-14286	HAIG-04-Q-SSM-W	25.8	15.3	2130	1.98	19.1	<1.00	8.40	<1.00	94.9	<1.00	111	5.83	<1.00	<1.00	1080	<1.00	5.53	16.9	684	2.21	2050	1.52	<1.00	<1.00	<1.00
S-14287	HAIG-05-Q-SSM-W	<5.00	<10.0	1170	1.54	20.4	<1.00	5.76	<1.00	12.8	<1.00	39.2	5.20	<1.00	<1.00	546	<1.00	<1.00	<3.07	372	<1.00	1110	<1.00	<1.00	<1.00	<1.00
S-14288	HAIG-06-Q-SSM-W	<5.00	25.7	1410	11.0	26.1	<1.00	1.29	<1.00	38.9	<1.00	17.2	4.19	<1.00	<1.00	728	<1.00	9.88	30.3	457	2.31	1370	<1.00	<1.00	<1.00	<1.00
S-14289	HAIG-07-1-Q-SSM-W	17.4	42.7	2100	5.22	15.1	<1.00	2.96	<1.00	11.2	<1.00	102	2.24	<1.00	<1.00	1050	<1.00	16.0	49.2	710	1.95	2130	<1.00	<1.00	<1.00	<1.00
S-14290	HAIG-08-Q-SSM-W	<5.00	32.4	1290	2.40	13.3	<1.00	<1.00	<1.00	26.8	<1.00	9.23	15.5	<1.00	<1.00	636	<1.00	12.2	37.4	437	<1.00	1310	<1.00	<1.00	<1.00	<1.00
S-14291	HAIG-09-Q-SSM-W	<5.00	32.4	1270	9.70	27.2	<1.00	<1.00	<1.00	61.4	<1.00	16.9	61.6	<1.00	<1.00	553	<1.00	12.2	37.4	411	2.77	1230	<1.00	<1.00	<1.00	<1.00
S-14292	HAIG-11-Q-SSM-W	34.0	89.6	2050	32.4	161	<1.00	<1.00	<1.00	416	<1.00	85.5	69.1	<1.00	<1.00	1610	<1.00	28.9	88.6	691	4.33	2070	<1.00	<1.00	<1.00	<1.00
S-14293	HAIG-12-Q-SSM-W	11.3	28.4	1890	3.02	18.7	<1.00	4.50	<1.00	123	<1.00	60.7	7.68	<1.00	<1.00	1040	<1.00	10.9	33.3	626	1.36	1880	<1.00	<1.00	<1.00	<1.00
S-14294	HAIG-13-Q-SSM-W	28.4	32.5	1920	4.00	8.57	<1.00	1.87	<1.00	53.4	<1.00	109	37.5	<1.00	<1.00	911	<1.00	13.0	40.0	641	2.58	1920	<1.00	<1.00	<1.00	<1.00
S-14295	HAIG-14-Q-SSM-W	<5.00	42.1	1680	14.9	38.8	<1.00	<1.00	<1.00	224	<1.00	17.6	60.9	<1.00	<1.00	917	<1.00	16.0	49.2	544	3.30	1630	<1.00	<1.00	<1.00	<1.00
S-14296	HAIG-15-Q-SSM-W	13.8	12.0	1780	2.73	14.6	<1.00	2.43	<1.00	140	<1.00	51.4	69.9	<1.00	<1.00	810	<1.00	5.06	15.5	597	3.87	1790	<1.00	<1.00	<1.00	<1.00
S-14297	HAIG-16-Q-SSM-W	7.81	64.8	1890	4.40	11.5	<1.00	2.38	<1.00	178	<1.00	31.8	17.6	<1.00	<1.00	1060	<1.00	22.5	69.1	626	3.13	1870	<1.00	<1.00	<1.00	<1.00
S-14298	HAIG-17-Q-SSM-W	9.07	35.6	1670	3.11	18.9	<1.00	2.83	<1.00	12.6	<1.00	36.7	28.7	<1.00	<1.00	751	<1.00	13.2	40.5	521	3.15	1560	<1.00	<1.00	<1.00	<1.00
S-14299	HAIG-18-Q-SSM-W	35.6	14.7	1820	12.5	217	<1.00	<1.00	<1.00	129	<1.00	95.8	72.7	<1.00	<1.00	1350	<1.00	6.17	18.9	578	1.61	1730	<1.00	<1.00	<1.00	<1.00
S-14300	HAIG-19-Q-SSM-W	7.40	103	1860	12.4	11.3	<1.00	<1.00	<1.00	165	<1.35	28.5	36.3	<1.00	<1.00	1050	<1.00	31.9	97.7	618	5.14	1850	<1.00	<1.00	<1.00	<1.00
S-14301	HAIG-20-Q-SSM-W	<5.00	60.2	1280	4.70	13.9	<1.00	3.91	<1.00	26.2	<1.00	16.1	39.7	<1.00	<1.00	554	<1.00	21.2	64.9	444	2.71	1330	<1.00	<1.00	<1.00	<1.00
S-14302	HAIG-21-Q-SSM-W	23.9	12.9	1850	14.2	76.0	<1.00	6.92	<1.00	51.7	<1.00	74.4	42.2	1.66	<1.00	947	<1.00	4.96	15.2	622	2.18	1860	<1.00	<1.00	<1.00	<1.00
S-14303	HAIG-22-Q-SSM-W	31.2	15.3	1800	1.38	8.20	<1.00	14.3	<1.00	92.1	<1.00	87.9	49.4	1.09	<1.00	754	<1.00	5.78	17.7	566	1.69	1700	2.68	<1.00	<1.00	<1.00
S-14304	HAIG-23-Q-SSM-W	8.58	43.7	1040	3.02	12.4	<1.00	4.09	<1.00	30.2	<1.00	29.2	56.1	<1.00	<1.00	382	<1.00	15.7	48.1	356	2.66	1070	<1.00	<1.00	<1.00	<1.00
S-14305	HAIG-24-Q-SSM-W	<5.00	<10.0	1320	<1.09	7.56	<1.00	32.8	<1.00	18.7	<1.00	25.3	40.0	<1.00	<1.00	481	<1.00	1.42	4.35	444	1.16	1330	2.01	<1.00	<1.00	<1.00
S-14306	HAIG-25-Q-SSM-W	<5.00	33.5	1340	5.00	12.0	<1.00	<1.00	<1.00	27.7	<1.01	9.43	16.8	<1.00	<1.00	660	<1.00	13.0	39.9	436	2.06	1310	<1.00	<1.00	<1.00	<1.00
S-14307	EWG-HAIG-SSM-W	<5.00	<10.0	1270	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	<1.00	601	<1.00	<1.00	<3.07	408	<1.00	1220	<1.00	<1.00	<1.00	<1.00

Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte

Analyte=Al, Analysis=ICP

Variability Chart for Measured (mg/L)



Analyte=B, Analysis=ICP

Variability Chart for Measured (mg/L)

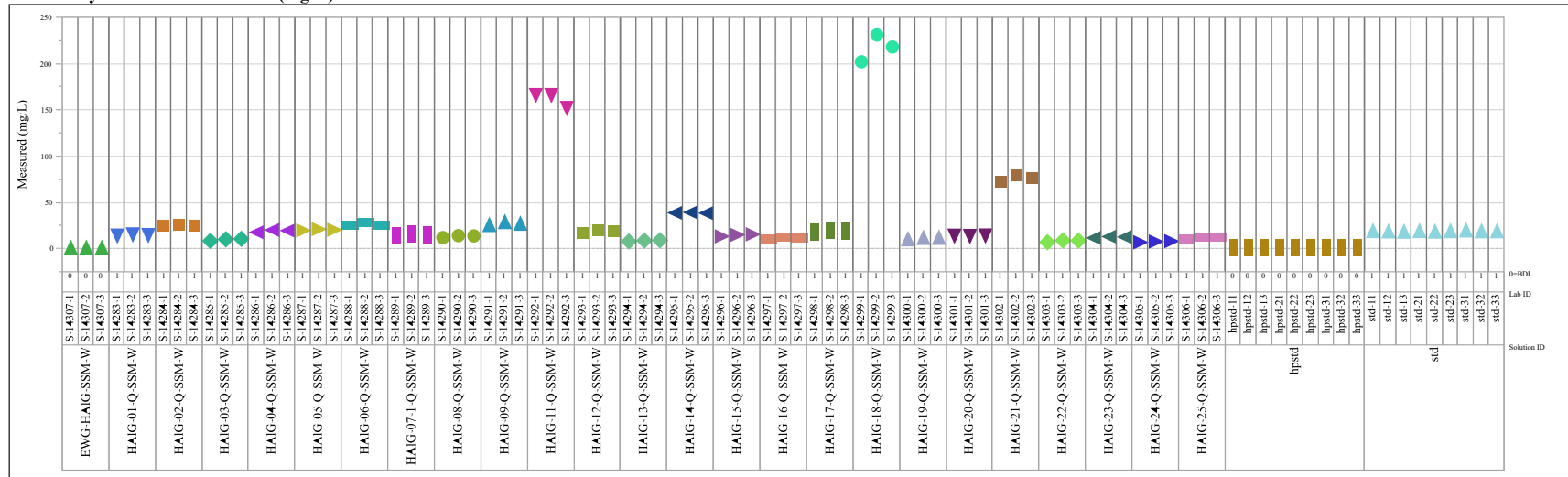
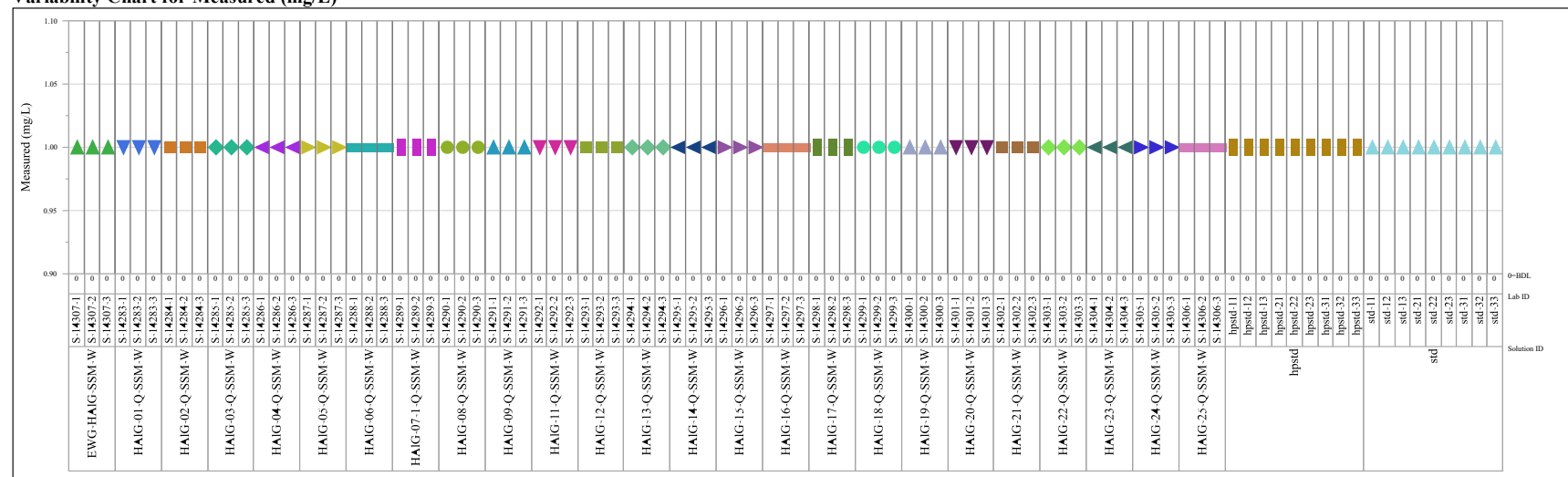


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

Analyte=Bi, Analysis=ICP

Variability Chart for Measured (mg/L)



Analyte=Ca, Analysis=ICP

Variability Chart for Measured (mg/L)

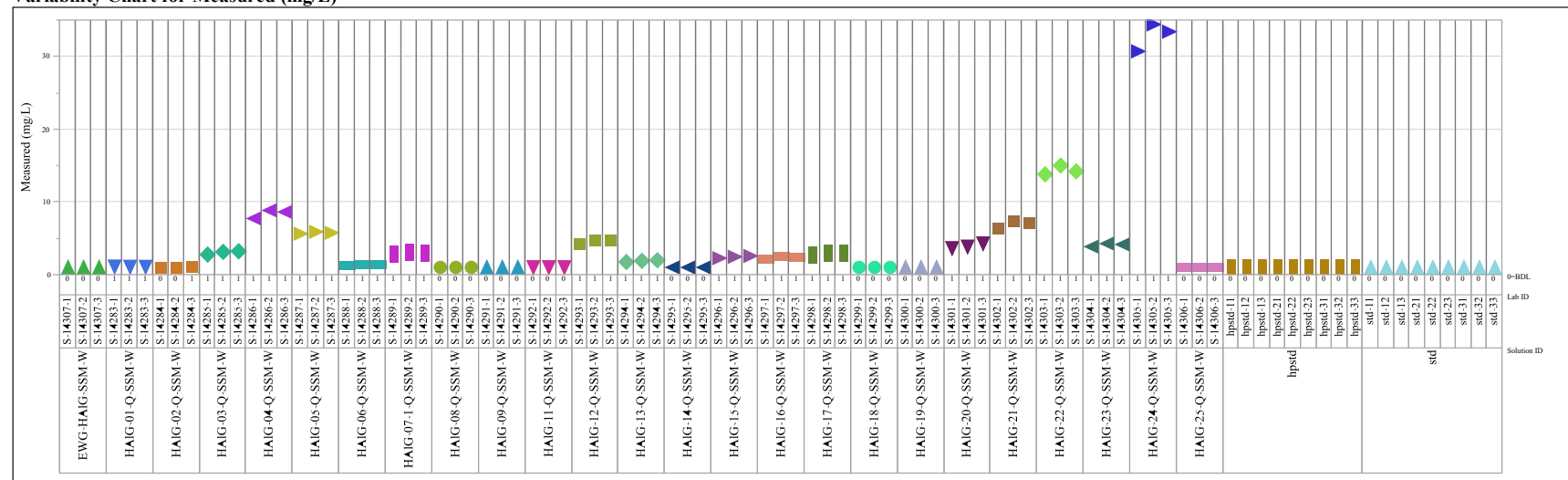


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

Analyte=Cd, Analysis=ICP

Variability Chart for Measured (mg/L)

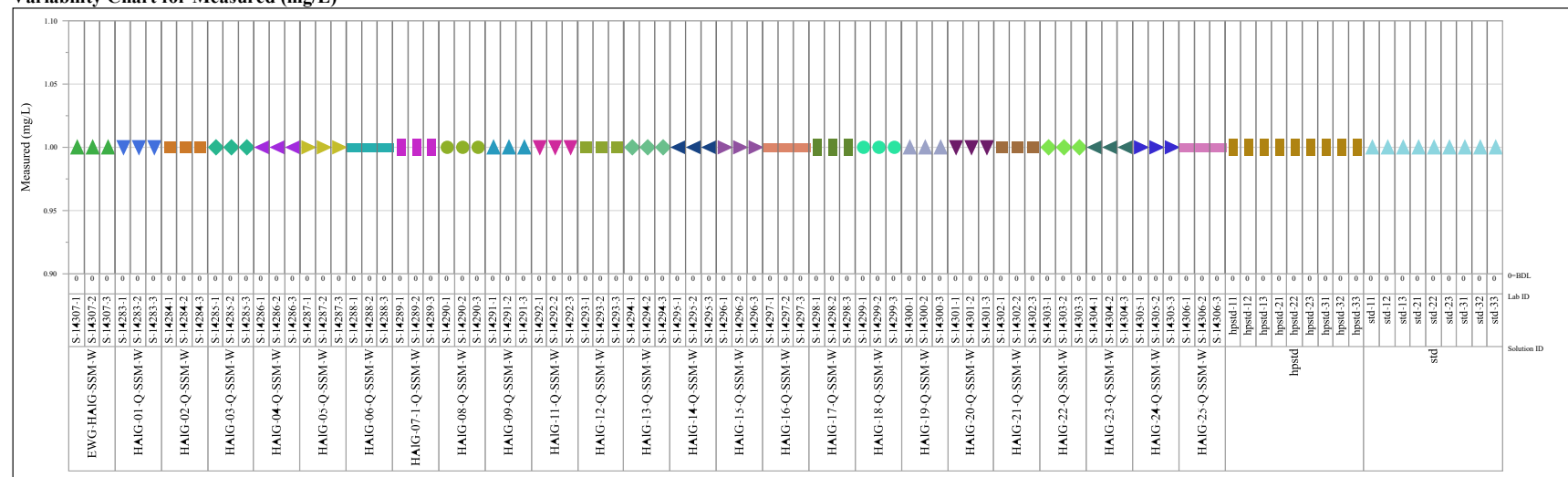
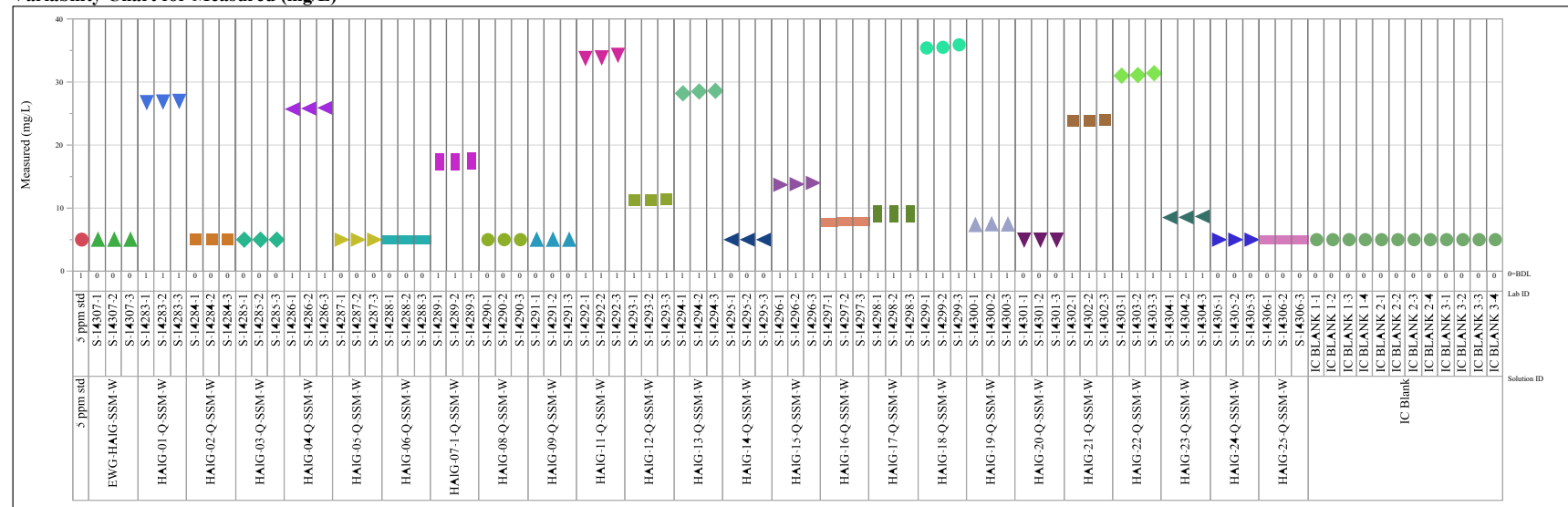


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

Analyte=F, Analysis=IC

Variability Chart for Measured (mg/L)



Analyte=Fe, Analysis=ICP

Variability Chart for Measured (mg/L)

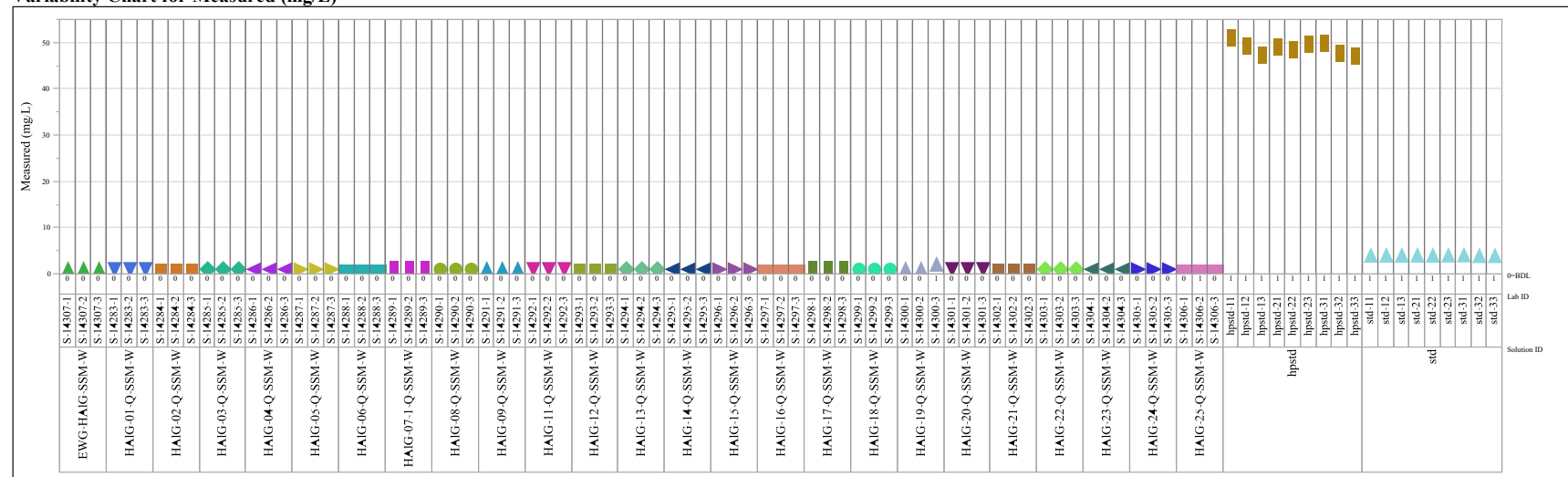
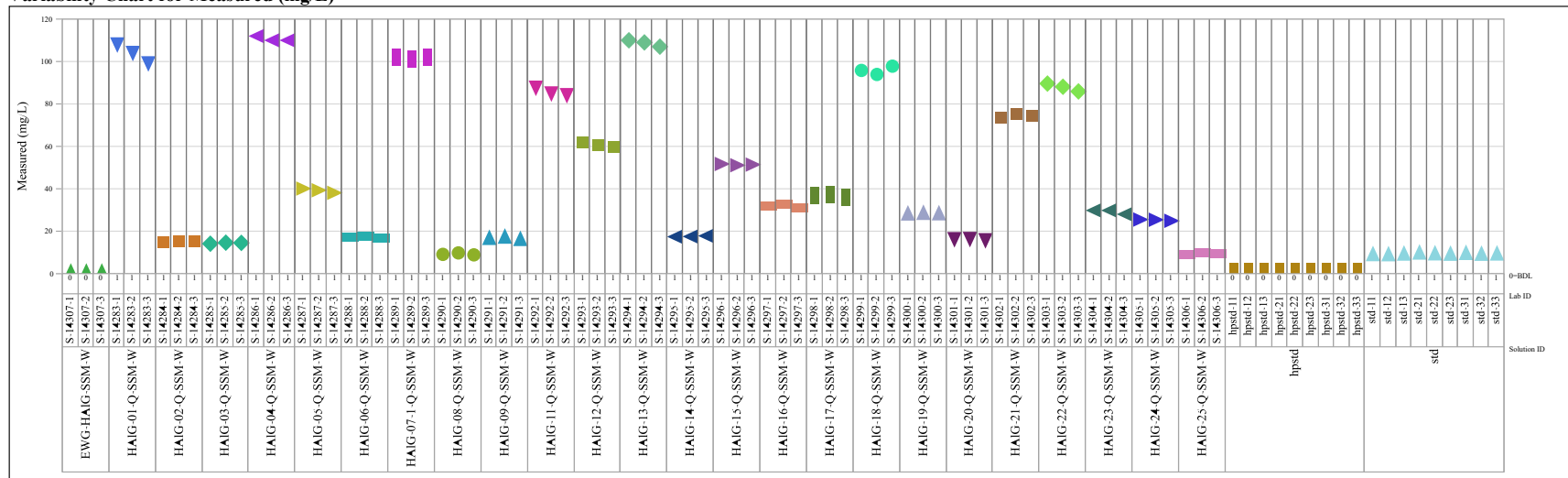


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

Analyte=K, Analysis=ICP

Variability Chart for Measured (mg/L)



Analyte=Li, Analysis=ICP

Variability Chart for Measured (mg/L)

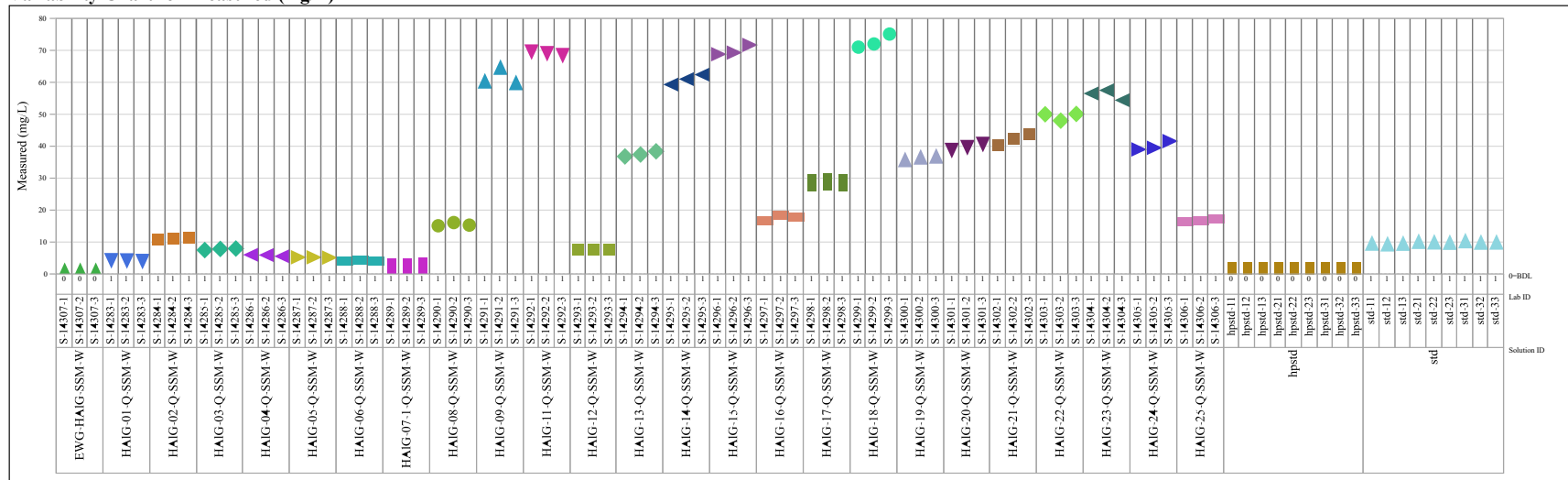
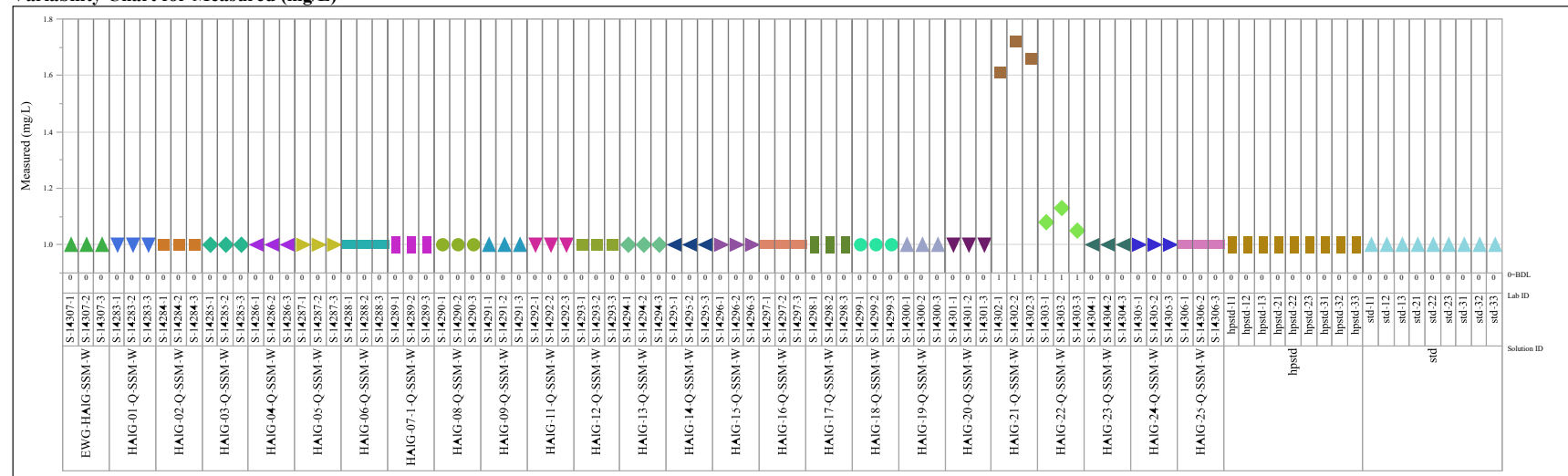


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

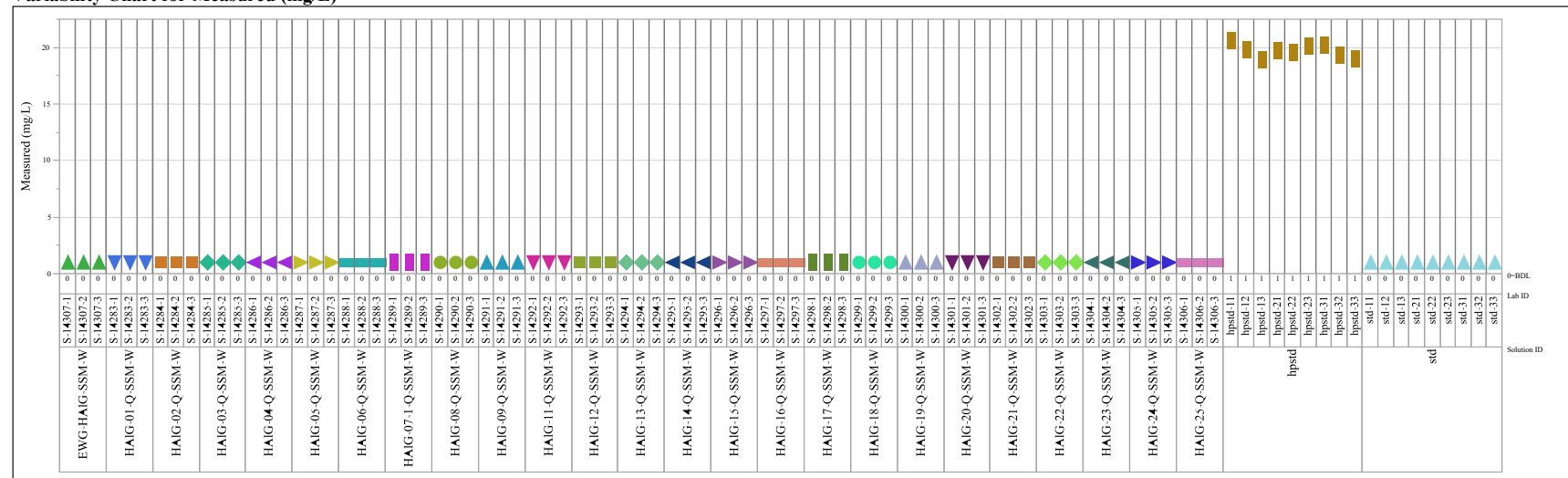
Analyte=Mg, Analysis=ICP

Variability Chart for Measured (mg/L)

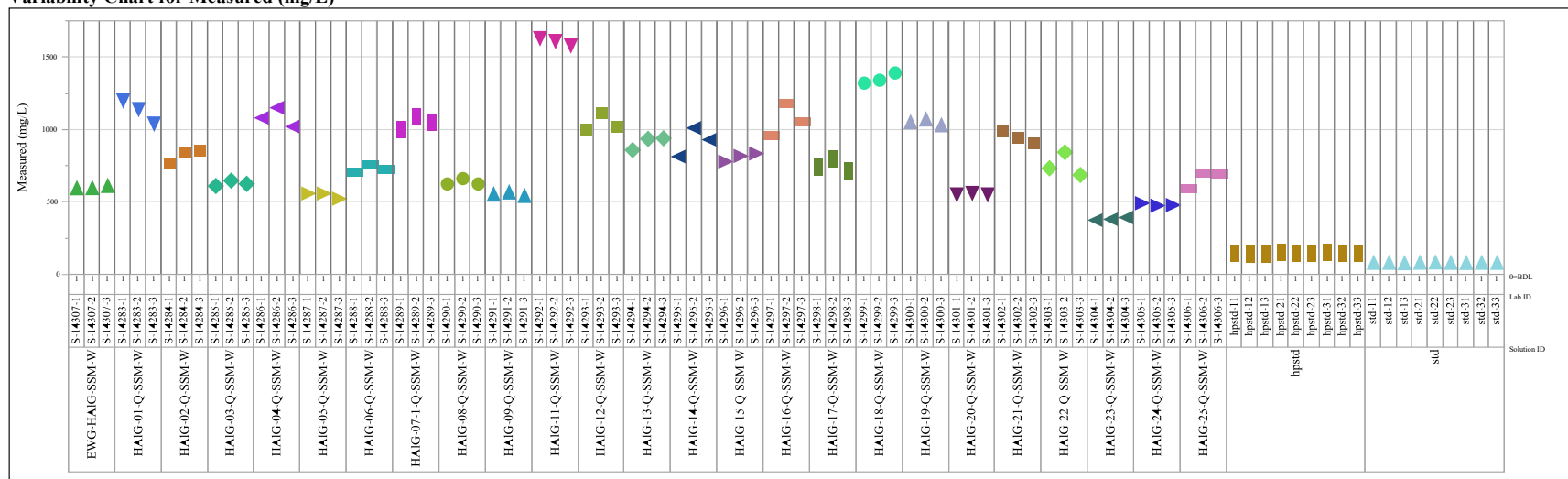


Analyte=Mn, Analysis=ICP

Variability Chart for Measured (mg/L)



Analyte=Na, Analysis=ICP
Variability Chart for Measured (mg/L)



Analyte=Ni, Analysis=ICP
 Variability Chart for Measured (mg/L)

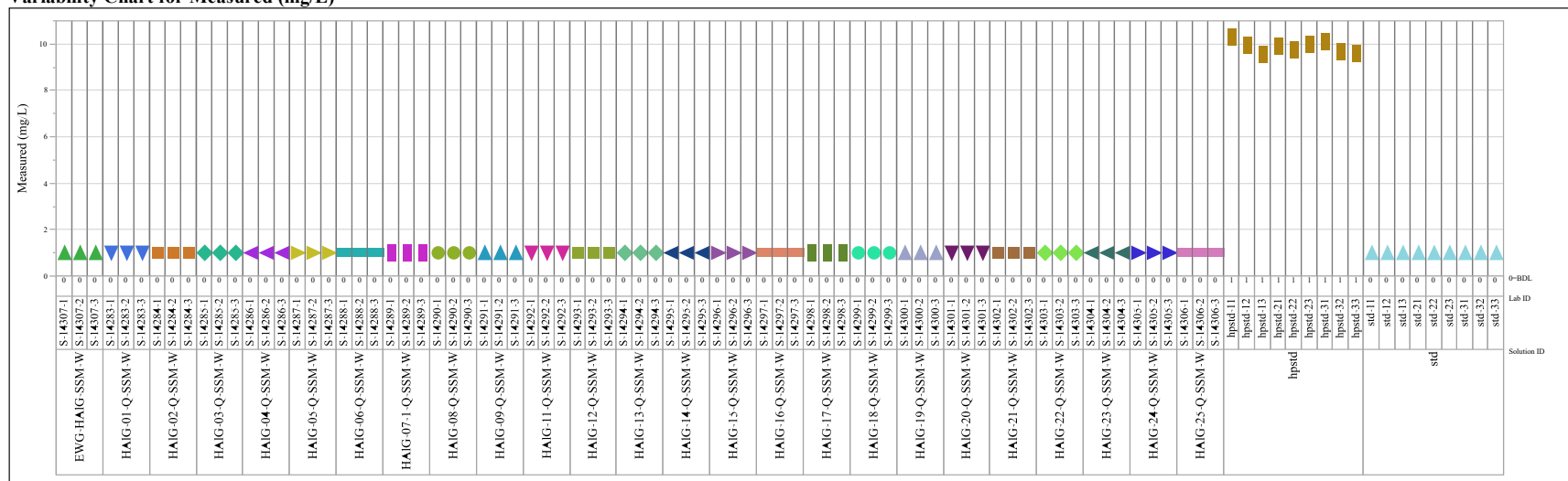
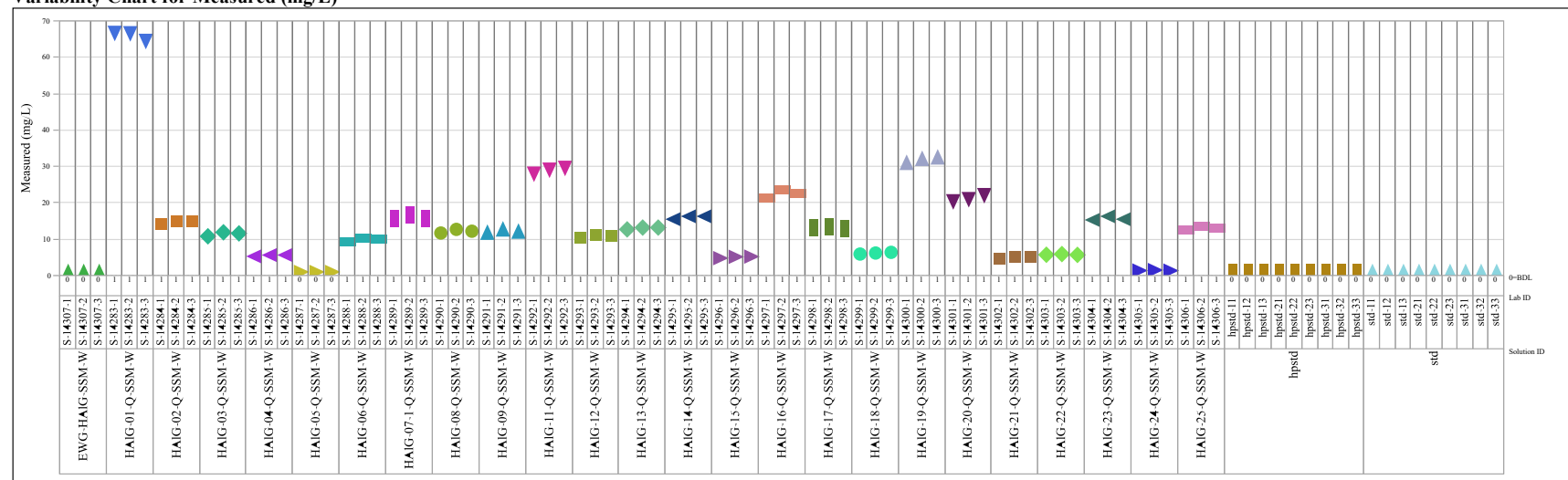


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

Analyte=P, Analysis=ICP

Variability Chart for Measured (mg/L)



Analyte=PO4, Analysis=IC

Variability Chart for Measured (mg/L)

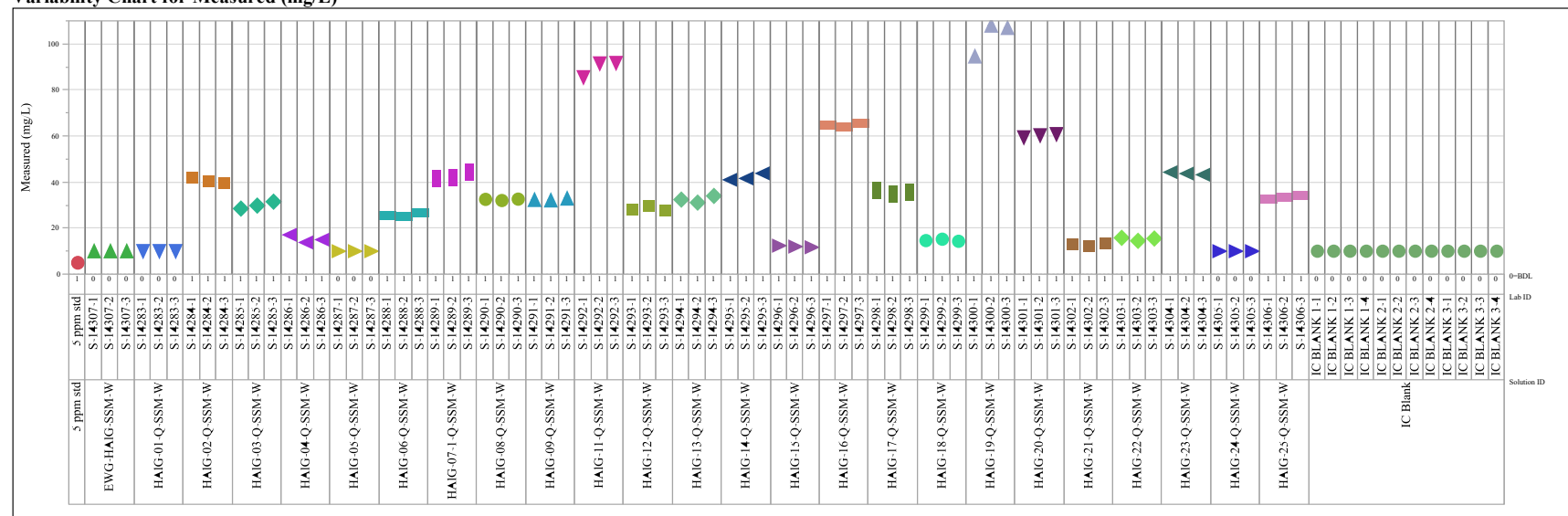
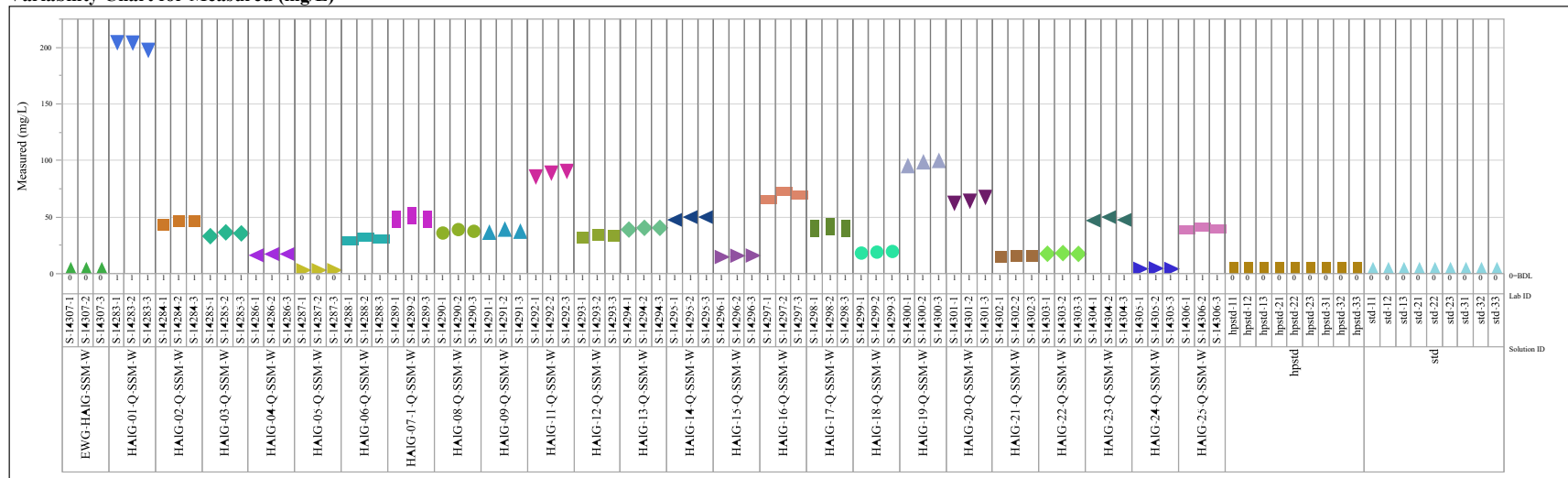


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

Analyte=PO4, Analysis=ICP

Variability Chart for Measured (mg/L)



Analyte=S, Analysis=ICP

Variability Chart for Measured (mg/L)

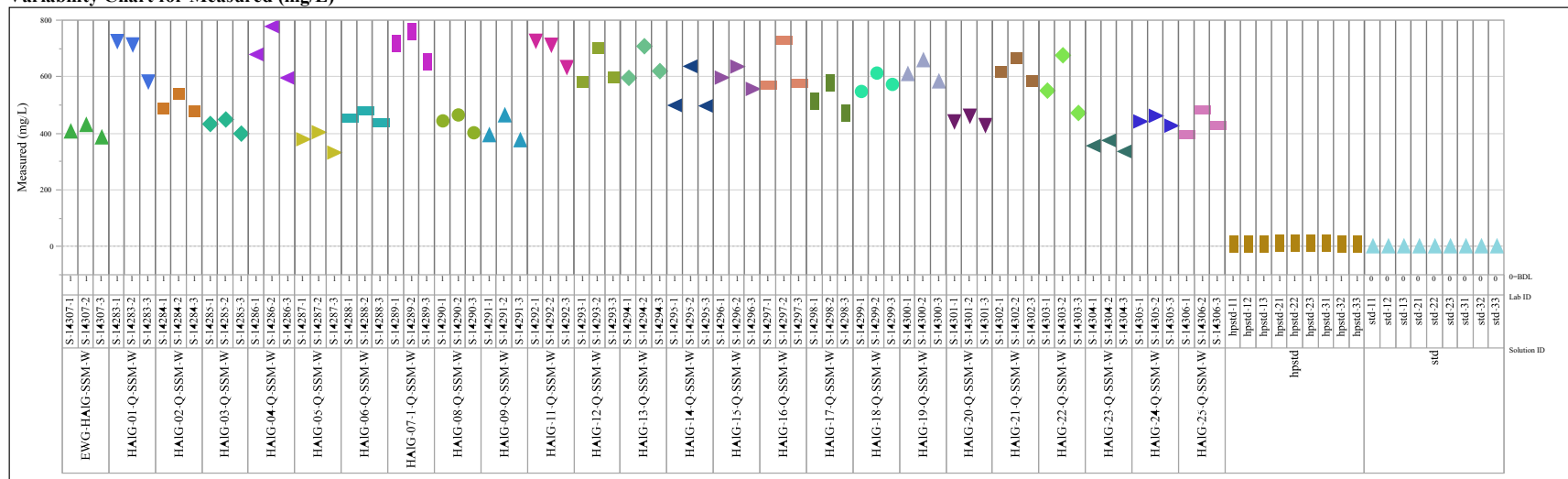
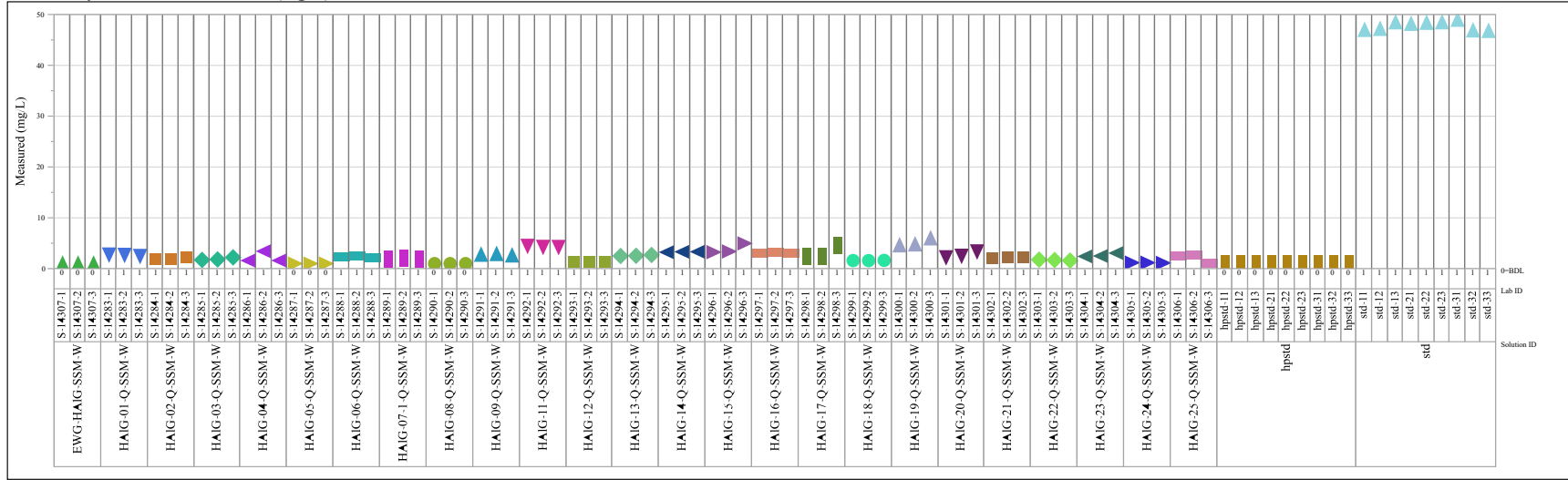


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

Analyte=Si, Analysis=ICP

Variability Chart for Measured (mg/L)



Analyte=SO4, Analysis=IC

Variability Chart for Measured (mg/L)

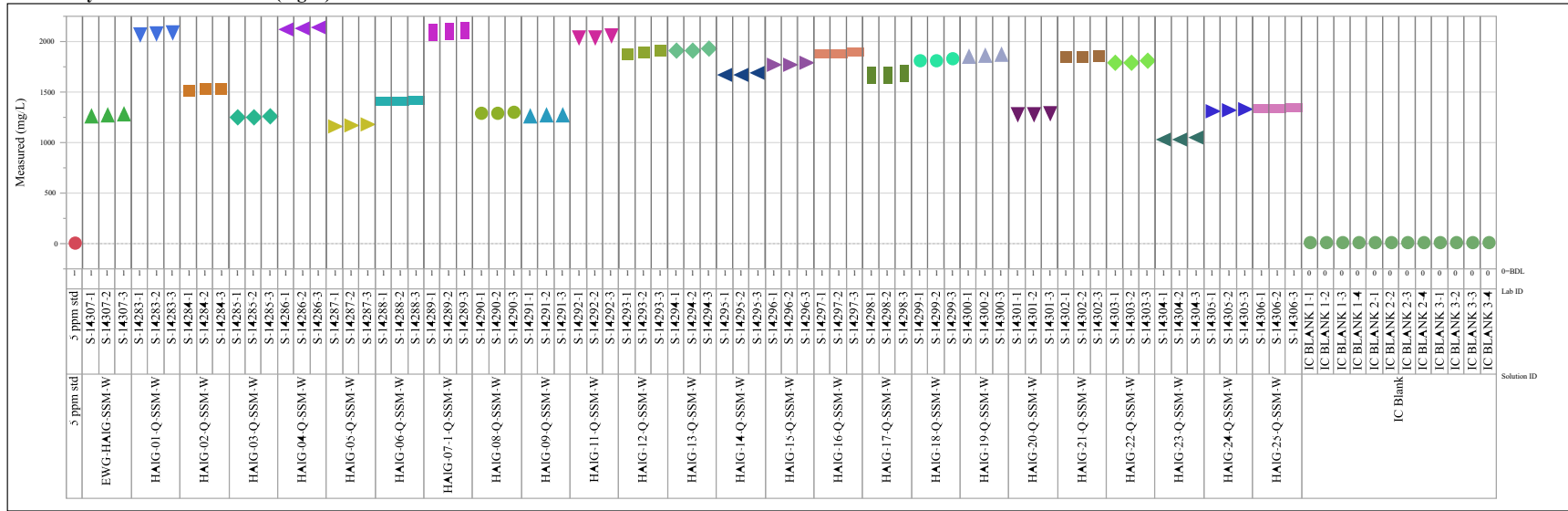
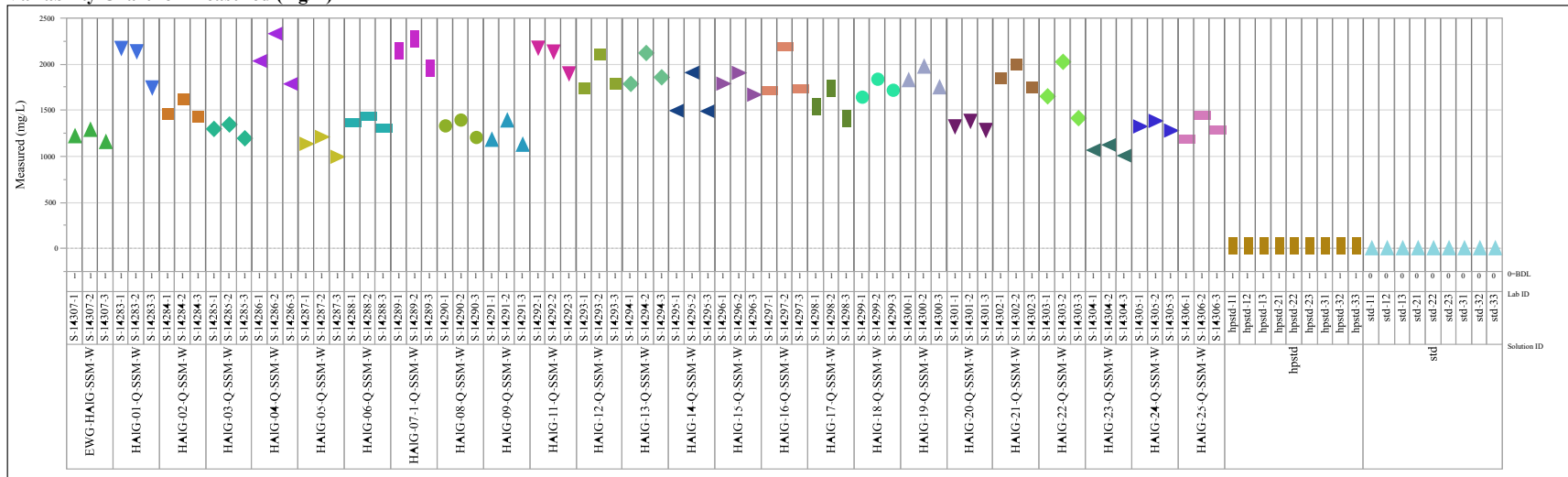


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

Analyte=SO4, Analysis=ICP

Variability Chart for Measured (mg/L)



Analyte=Sr, Analysis=ICP

Variability Chart for Measured (mg/L)

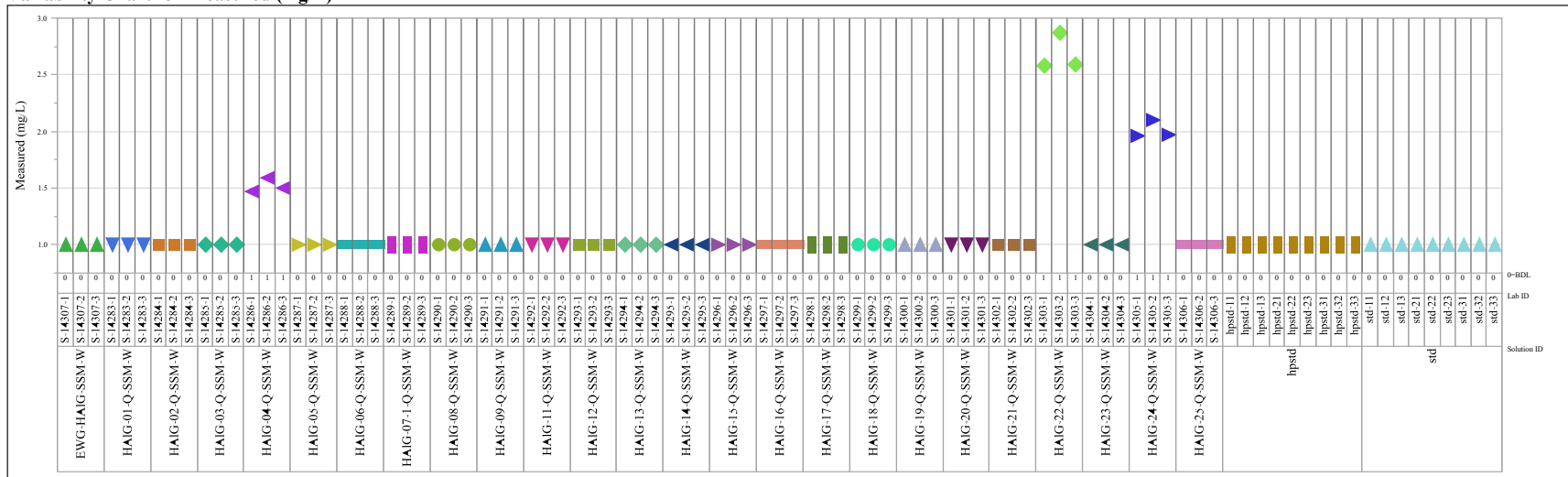
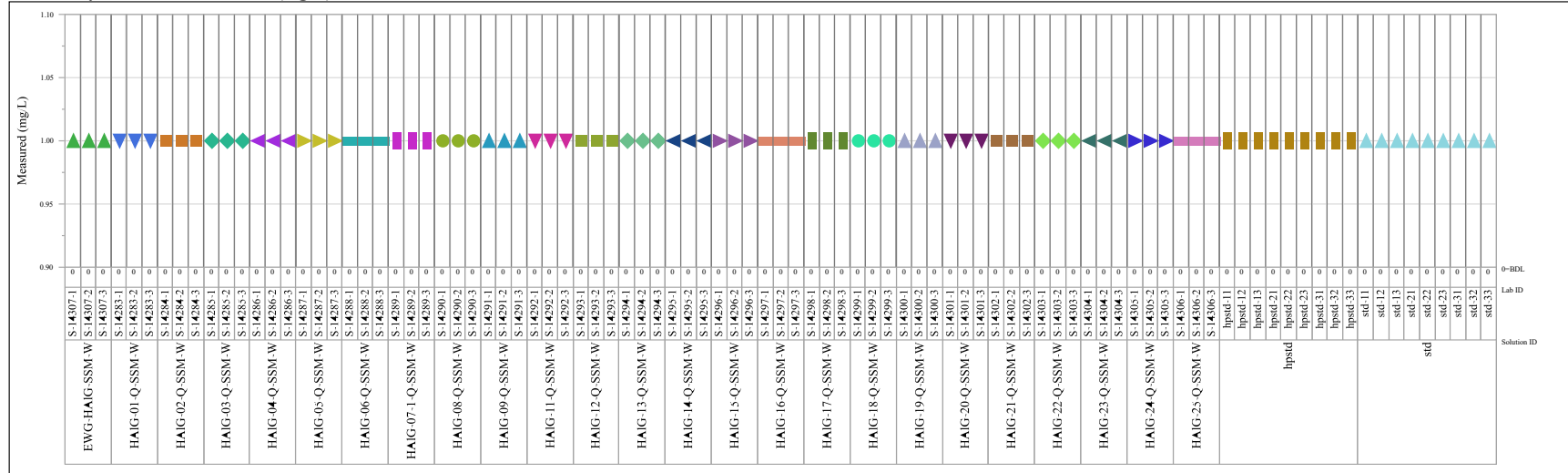


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

Analyte=Ti, Analysis=ICP

Variability Chart for Measured (mg/L)



Analyte=Zn, Analysis=ICP

Variability Chart for Measured (mg/L)

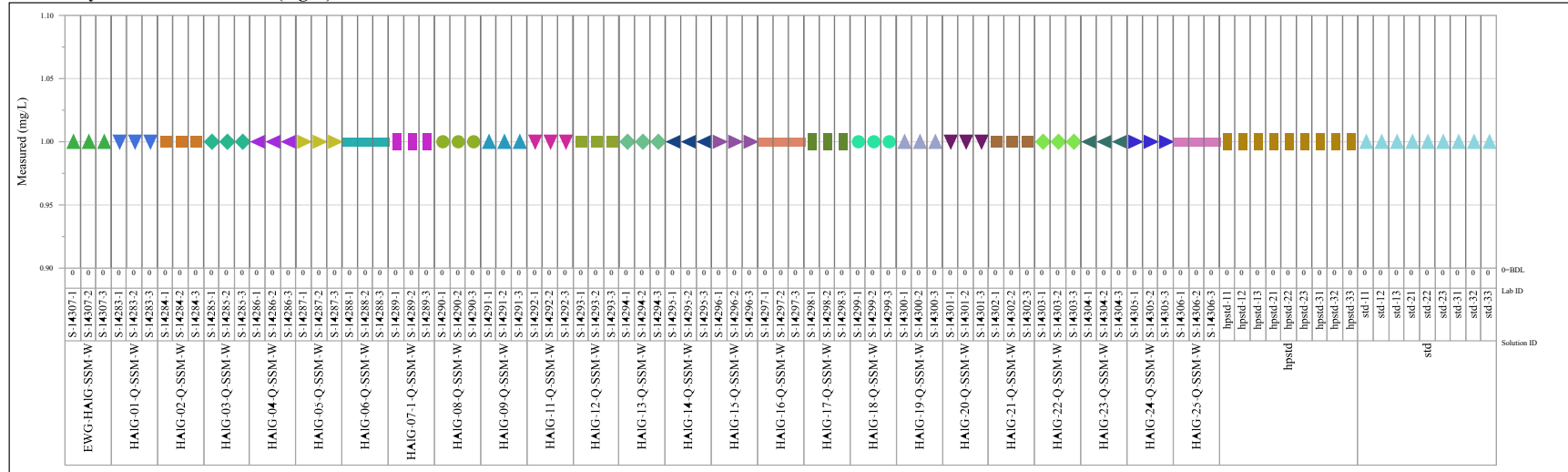
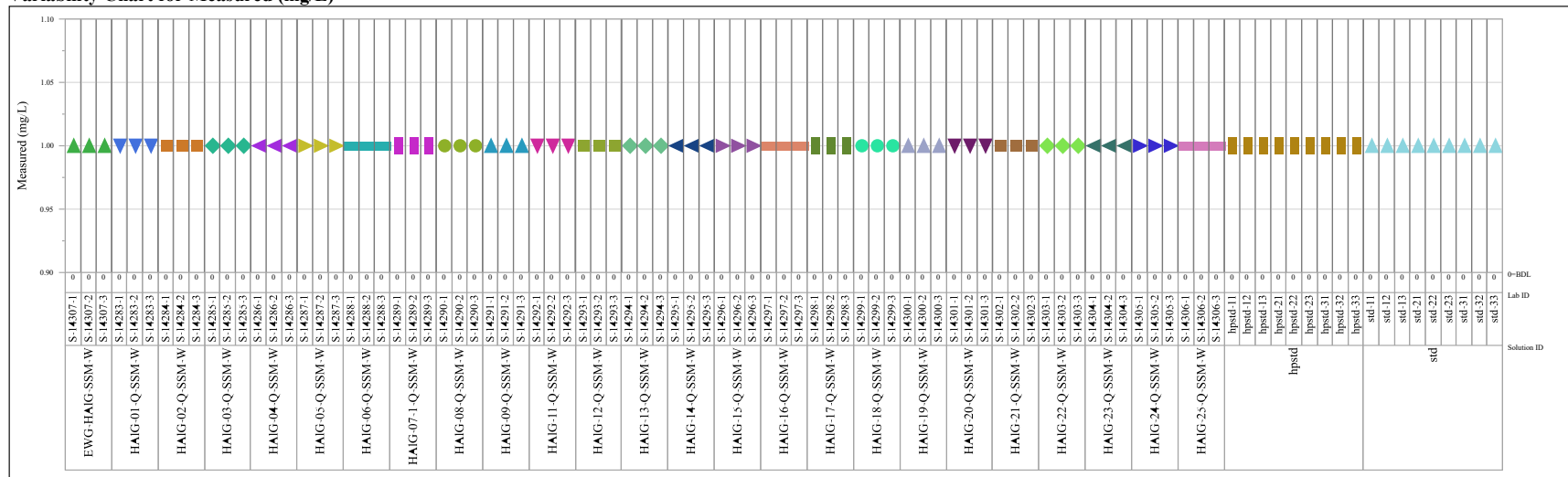


Exhibit B-1. Measurements of SSM Wash Solutions by Solution ID by Analyte (continued)

Analyte=Zr, Analysis=ICP

Variability Chart for Measured (mg/L)



Distribution:

Jake.Amoroso@sml.doe.gov
CJ.Bannochie@sml.doe.gov
Alex.Cozzi@srnl.doe.gov
Charles.Crawford@srnl.doe.gov
Elaine_N_Diaz@orp.doe.gov
William.C.Eaton@pnnl.gov
Holly.Hall@sml.doe.gov
Erich.Hansen@srnl.doe.gov
Connie.Herman@srnl.doe.gov
Anthony.Howe@sml.doe.gov
Madison.Hsieh@sml.doe.gov
Fabienne.Johnson@sml.doe.gov
Albert_A_Kruger@orp.doe.gov
Christine.Langton@srnl.doe.gov
Brady.Lee@srnl.doe.gov
Charmayne.Lonergan@pnnl.gov
Joseph.Manna@sml.doe.gov
Daniel.McCabe@sml.doe.gov
Gregg.Morgan@sml.doe.gov
Frank.Pennebaker@srnl.doe.gov
William.Ramsey@srnl.doe.gov
Whitney.Riley@srnl.doe.gov
Renee.Russell@pnnl.gov
Eric.Skidmore@srnl.doe.gov
Anna.Stanfield@srnl.doe.gov
Michael.Stone@srnl.doe.gov
John.Vienna@pnnl.gov
Boyd.Wiedenman@srnl.doe.gov
Richard.Wyrwas@srnl.doe.gov
Records Administration (EDWS)